

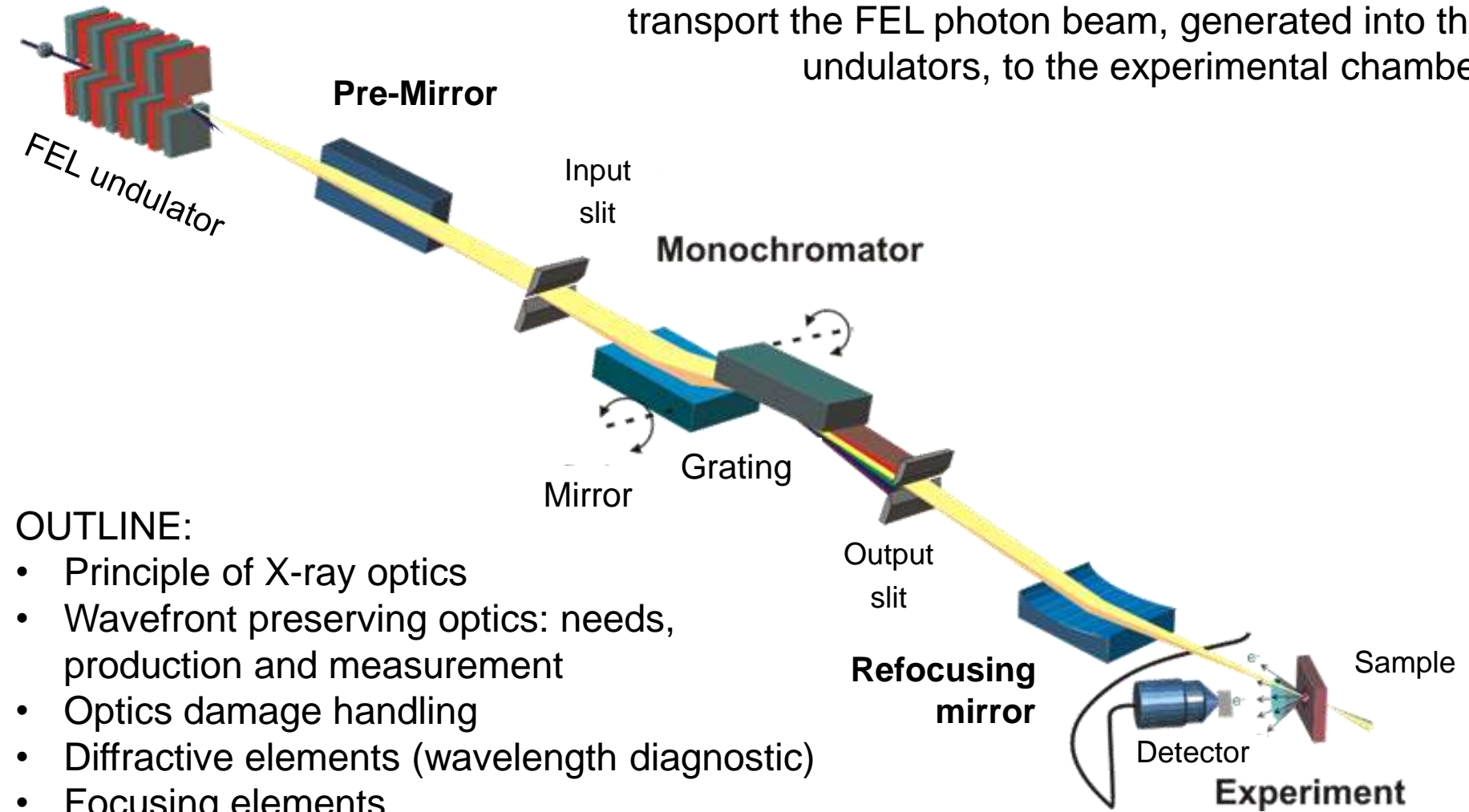
S³EPB

SLAC Summer Seminar
on Electron and Photon Beams

Photon Beamlines

Daniele Cocco
August 6th, 2015

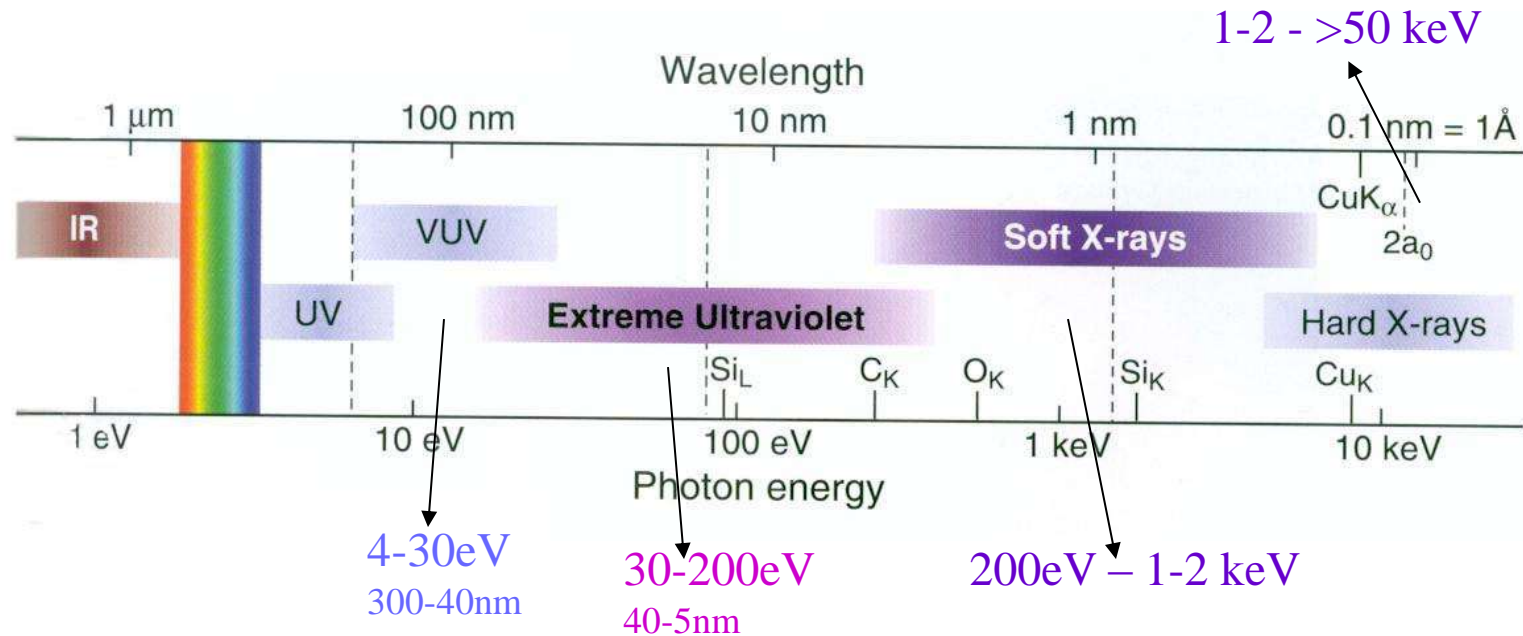
A *photon beamline* is everything necessary to transport the FEL photon beam, generated into the undulators, to the experimental chamber



OUTLINE:

- Principle of X-ray optics
- Wavefront preserving optics: needs, production and measurement
- Optics damage handling
- Diffractive elements (wavelength diagnostic)
- Focusing elements

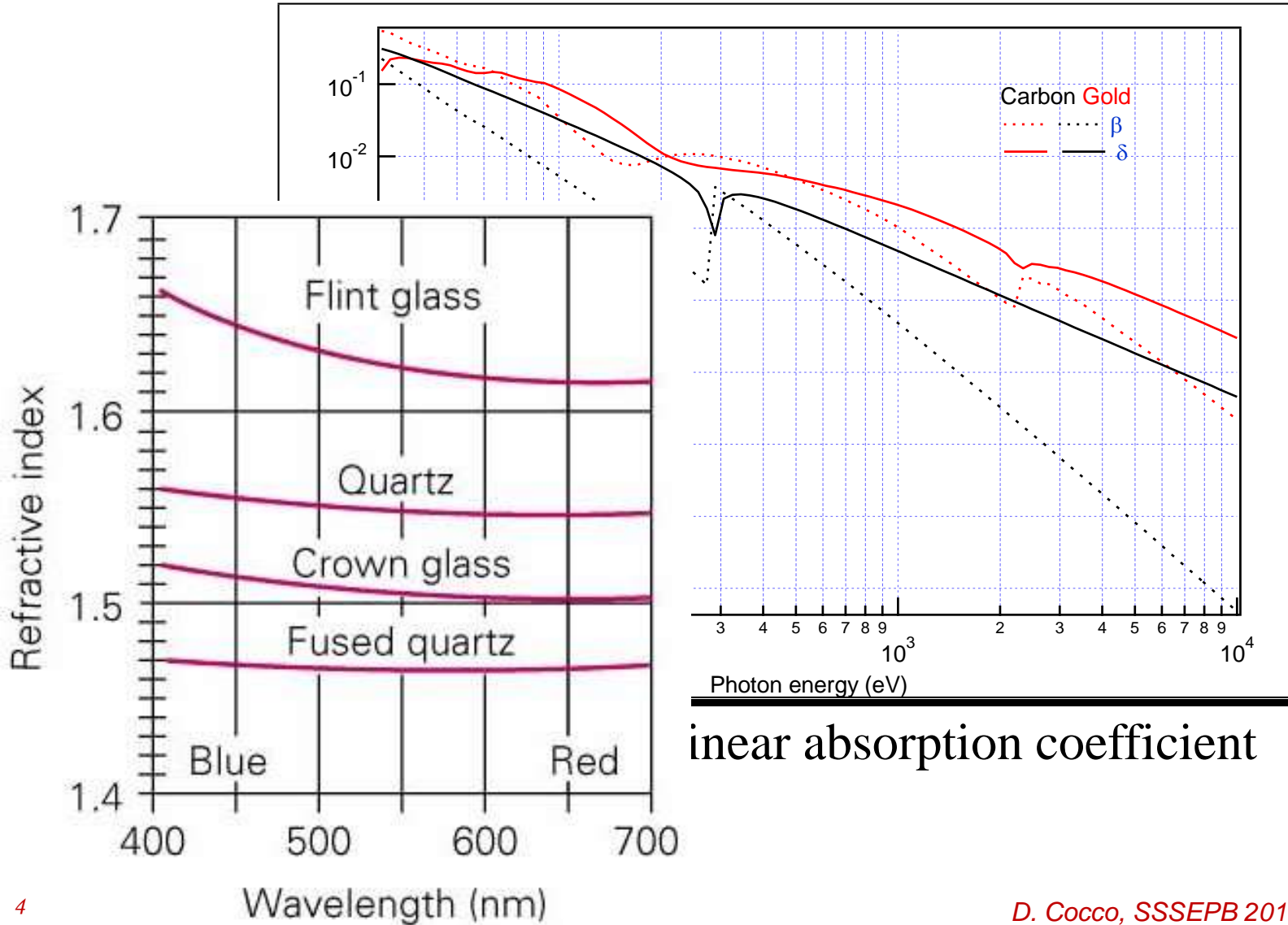
Photon energy regions



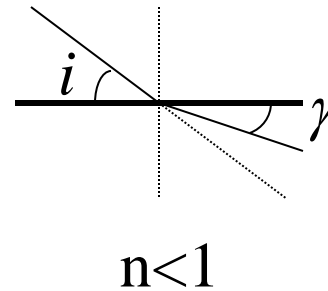
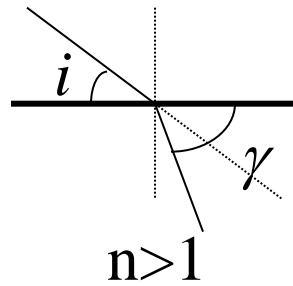
SXR: These regions are very interesting because are characterized by the presence of the absorption edges of most low and intermediate Z elements; photons with these energies are a **very sensitive tool** for elemental and chemical identification. **PROBLEM:** Absorption edges are bad things for photon transport

HXR: This region provide highly penetrating radiations, it is useful to study bulk rather than surface. The short wavelength make possible high spatial resolution microscopy or diffraction techniques. **PROBLEM:** penetration is not good for reflective optics.

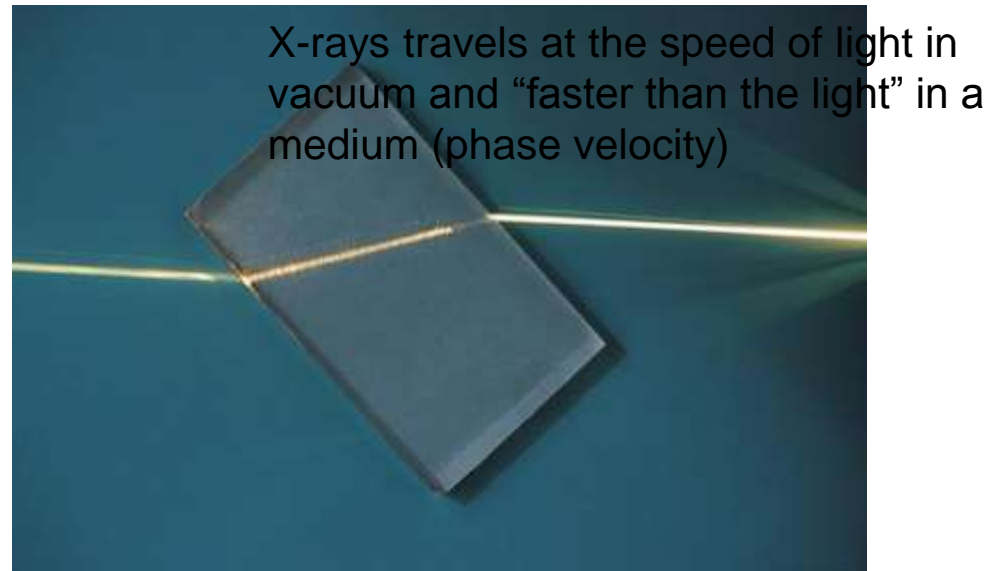
refractive index $\mu = 1 - \delta - i\beta$



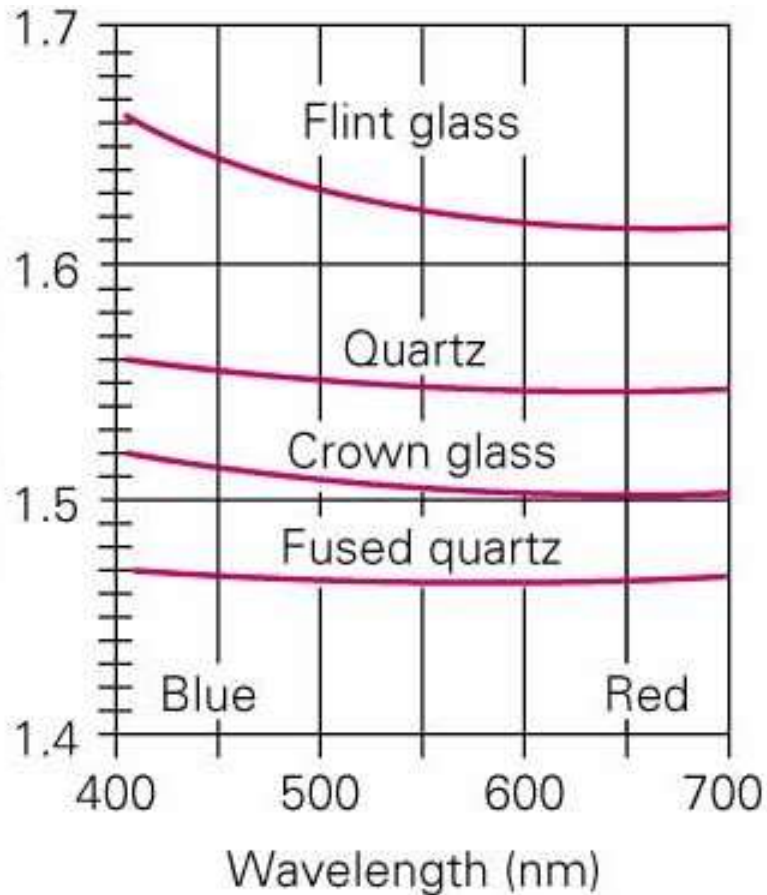
near absorption coefficient

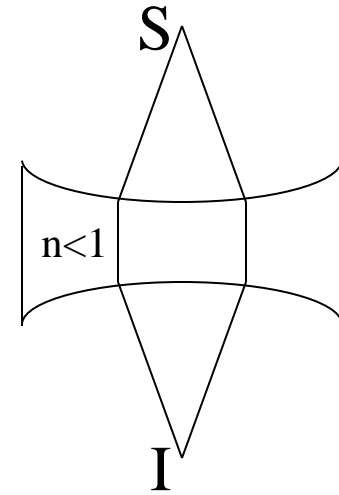
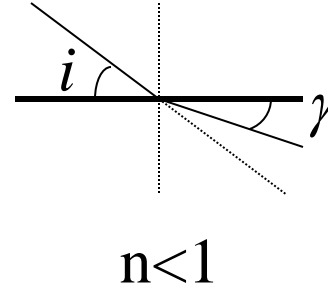
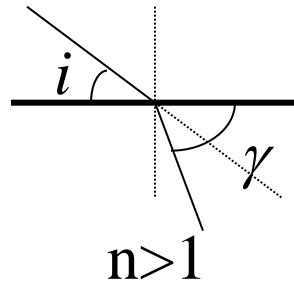
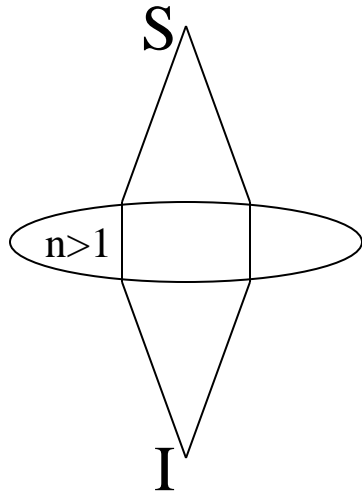


Snell's law: $n_1 \cos \gamma = n_2 \cos i$



Fermat's principle
The Light travels the path from A to B in the minimum possible time (valid for every wavelength)

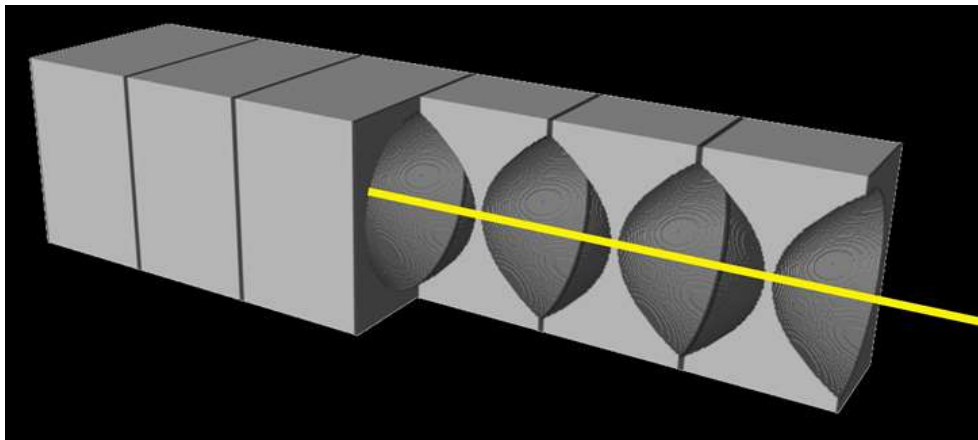
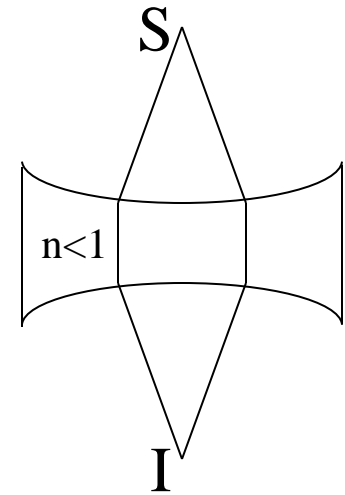
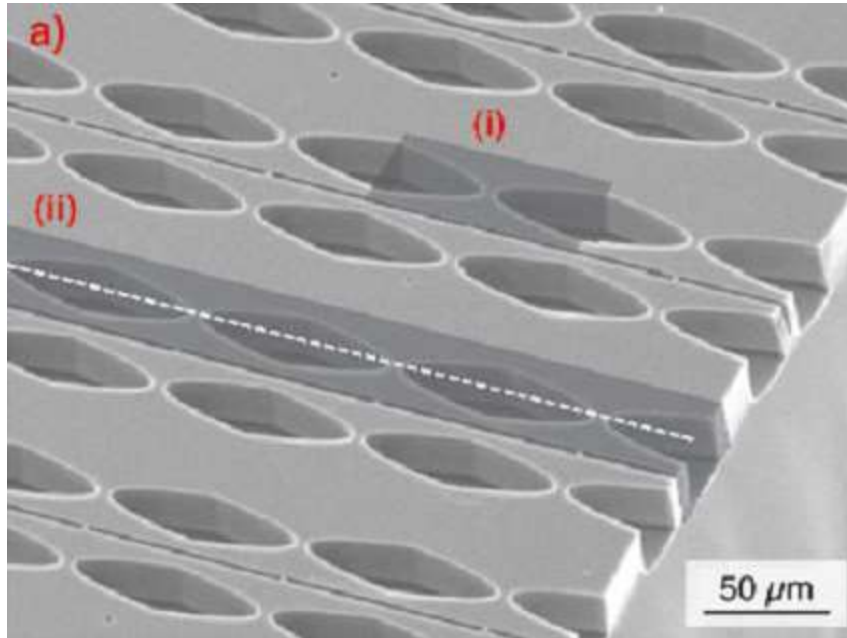




$$\frac{1}{f} = (n - 1) \left(\frac{1}{R_1} + \frac{1}{R_2} \right) \approx (1 - \delta - 1) \cdot \frac{2}{R} < 0$$

$$\delta = \frac{Ne^2 \lambda^2}{2\pi mc^2} \approx 10^{-2} - 10^{-4}$$

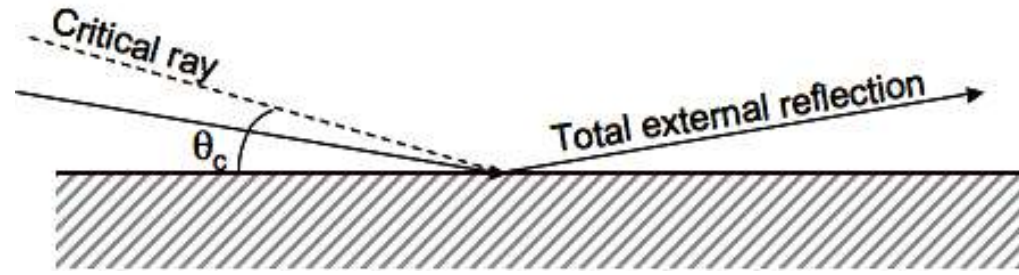
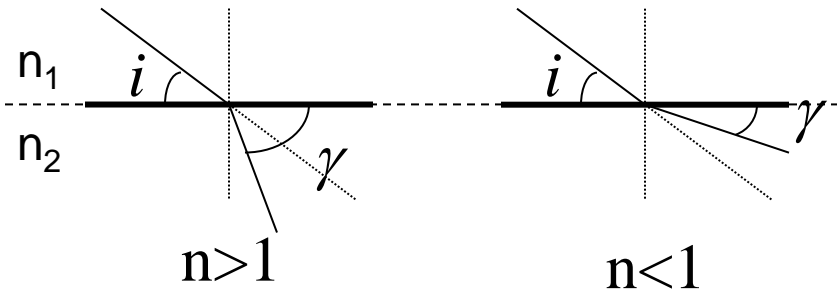
$$\delta \approx 10^{-4} \quad HXR \Rightarrow f \approx 1m \quad \text{if} \quad R \approx 1mm$$



if $R \approx 1mm$

This could be, in principle, all you need

Total external reflection



Snell's law: $n_1 \cos \gamma = n_2 \cos i$

Snell's law ($n_1=1$, vacuum):

$$\cos \gamma = \cos i / n$$

$$\gamma = 0 \quad n = \cos i_c$$

i_c critical angle: total external reflection

$$\sin i_c = \lambda (e^2 N / \pi m c^2)^{1/2}$$

$$\lambda_c(\text{min}) = 3.333 \cdot 10^{-13} N^{-1/2} \sin i_c$$

Material	Density (g/cm ³)	N (electron/cm ³)	λ_{min} nm
Pentadecane (oil)	0.77	7×10^{22}	$64.1 \sin i$
Glass	2.6	78×10^{22}	$37.9 \sin i$
Aluminum oxide	3.9	115×10^{22}	$31.2 \sin i$
Gold	19.3	466×10^{22}	$15.4 \sin i$

$i=5^\circ: \quad \lambda_{\text{min}} \text{glass} = 3.3 \text{nm} = 375 \text{ eV}$

$\lambda_{\text{min}} \text{gold} = 1.34 \text{nm} = 923 \text{ eV}$

gold

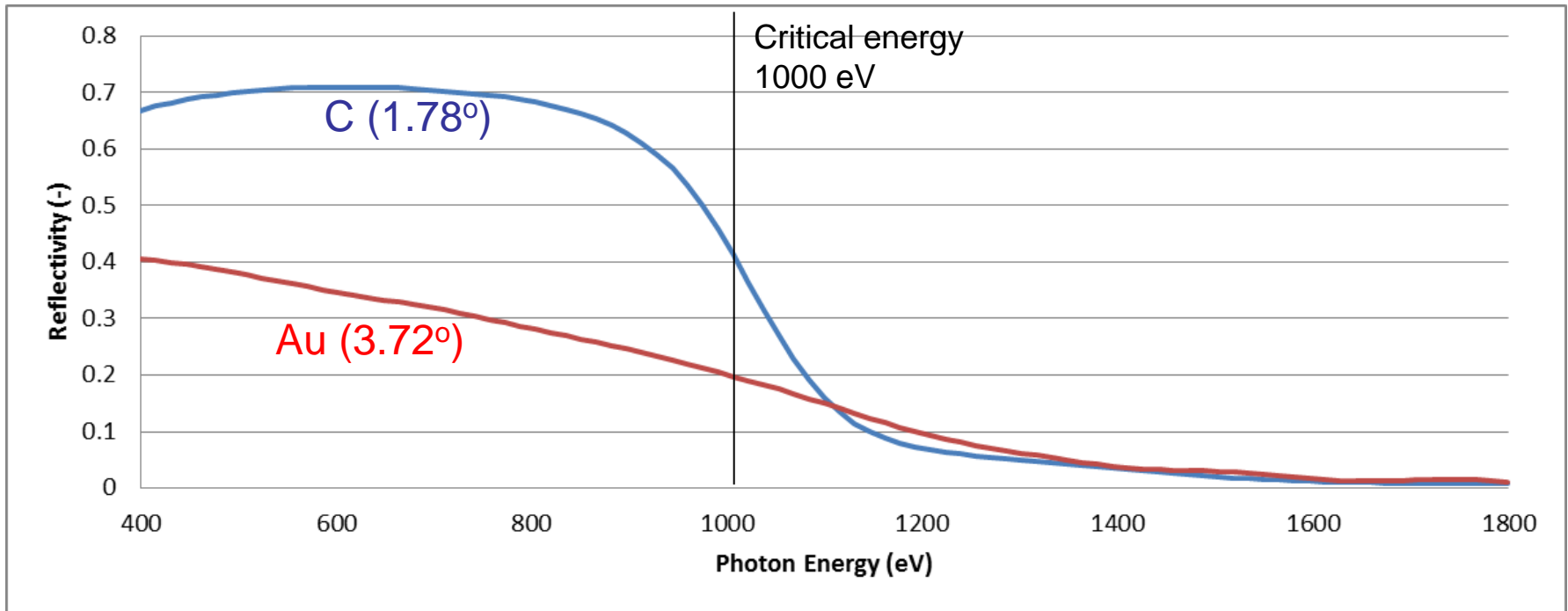
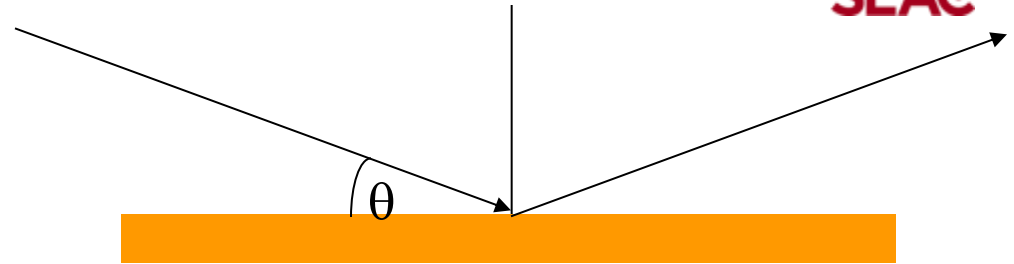
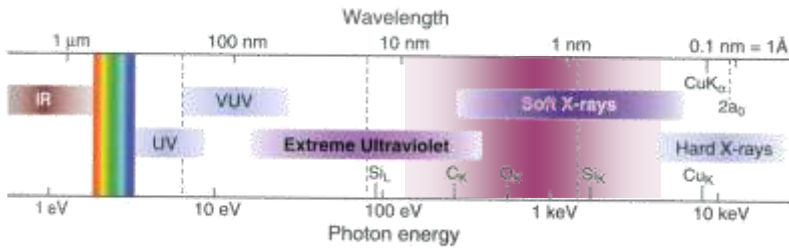
$600 \text{ eV} \Rightarrow i_c \approx 7.4^\circ$

$1200 \text{ eV} \Rightarrow i_c \approx 3.7^\circ$

$5 \text{ keV} \Rightarrow i_c \approx 0.9^\circ$

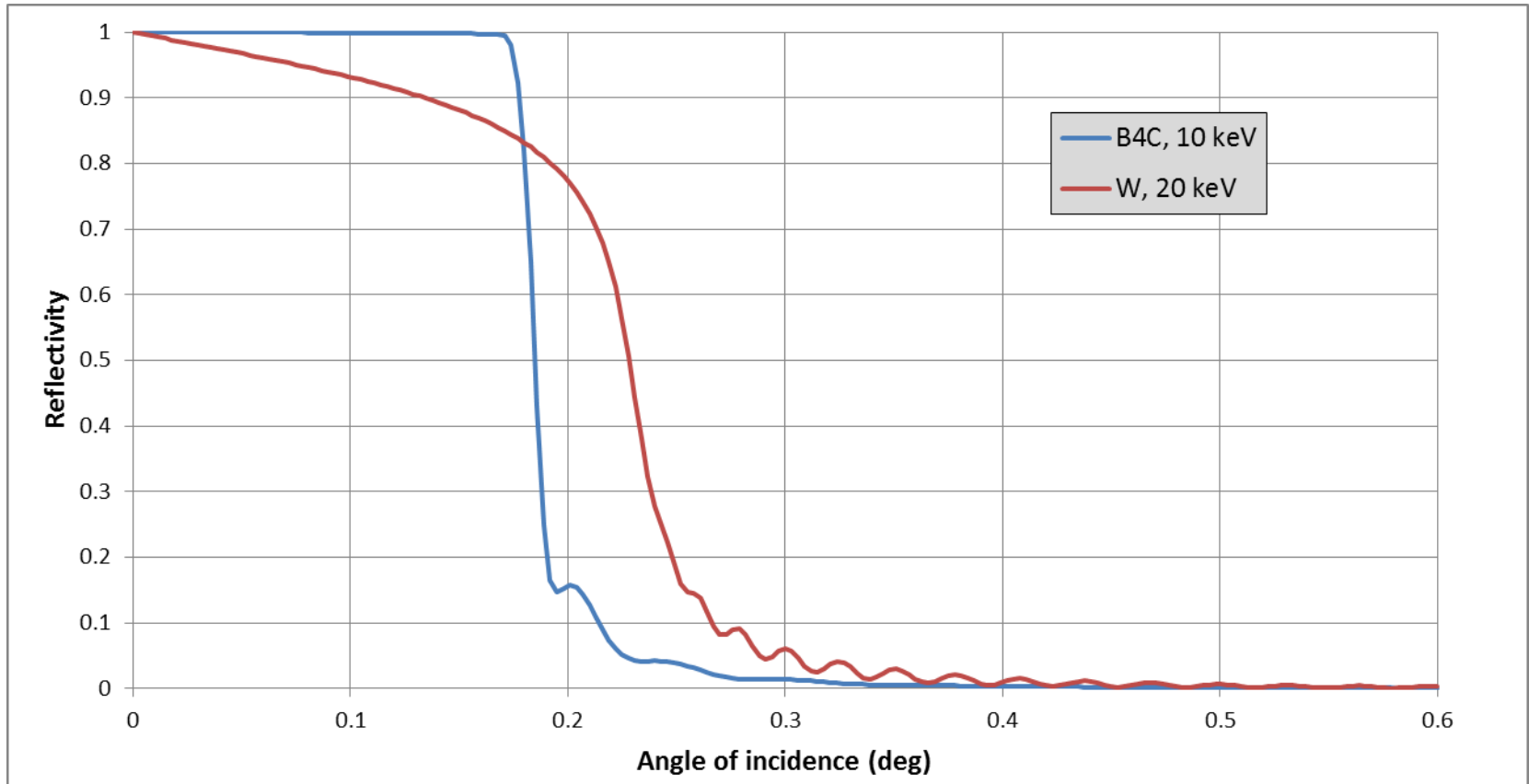
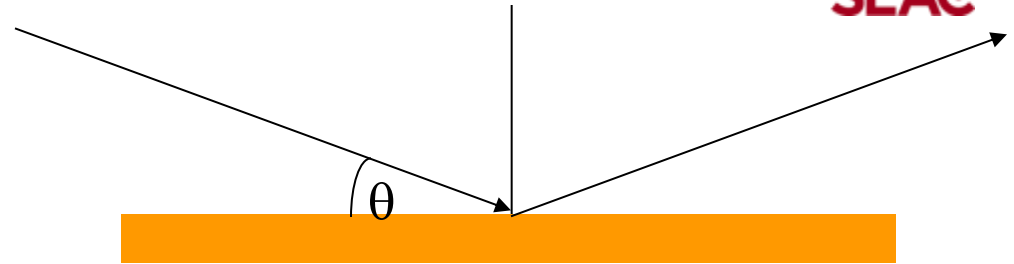
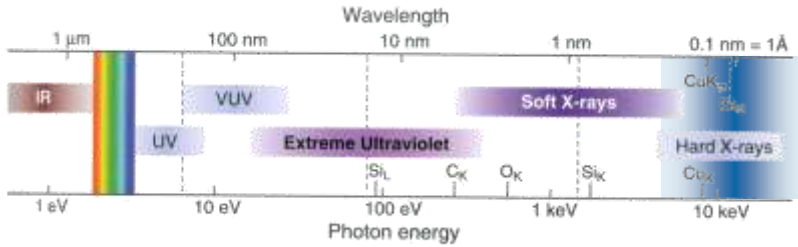
Mirror reflectivity and critical energy Soft X-ray

SLAC

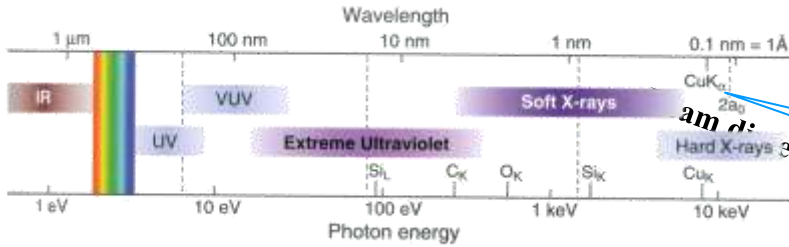


Mirror Reflectivity and critical angle (Hard X-ray)

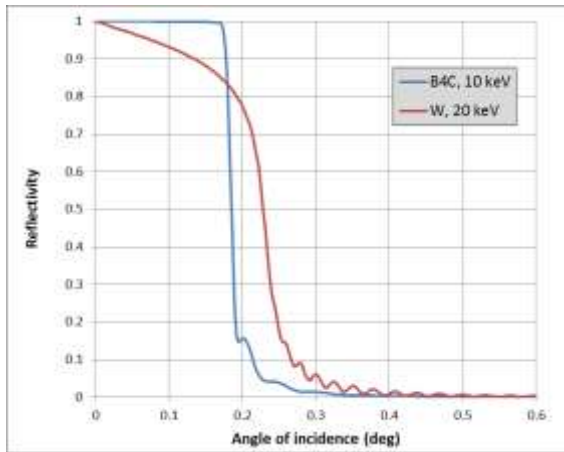
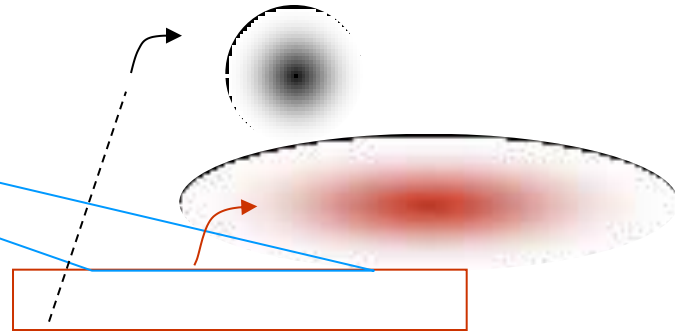
SLAC



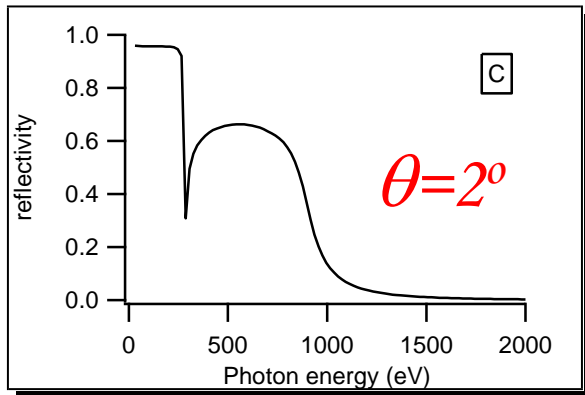
Mirror dimension



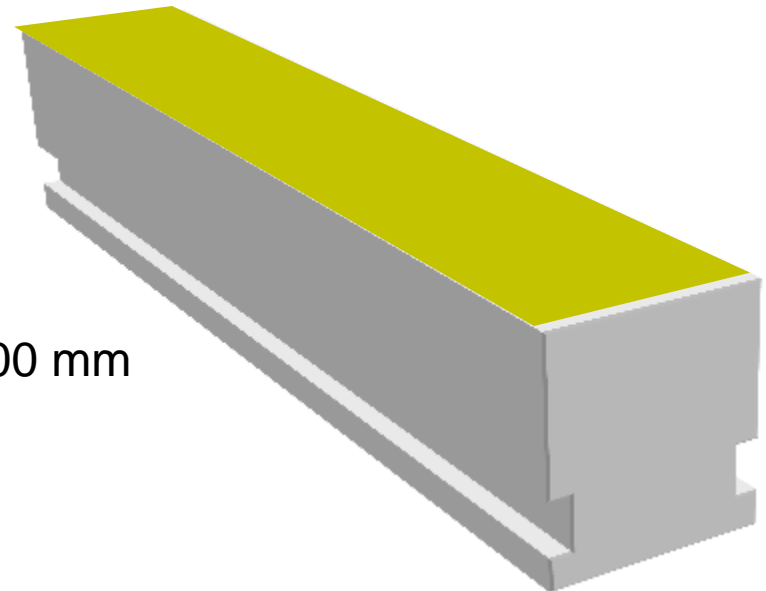
Dimensions from 0.1 to 20 mm

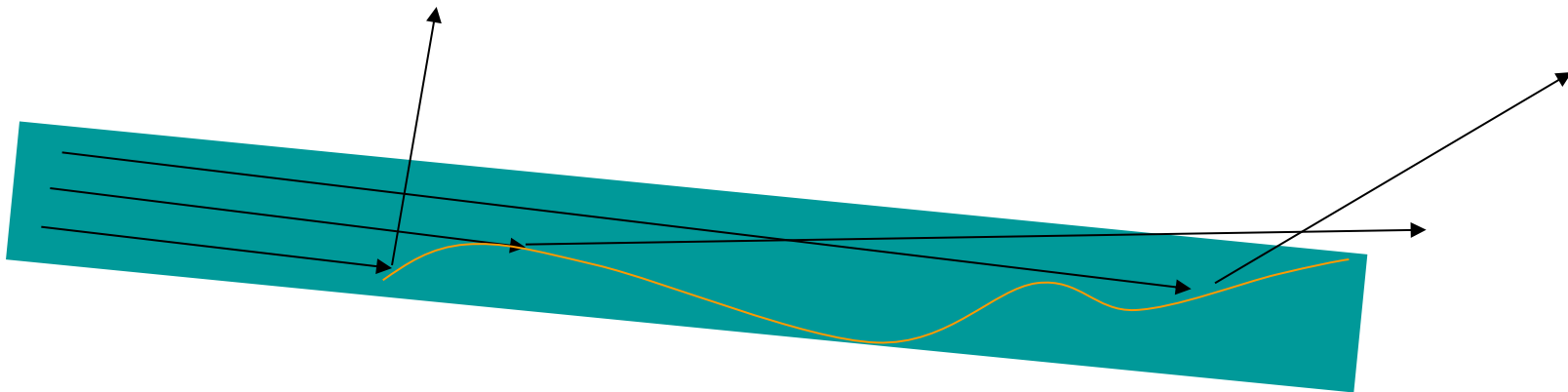
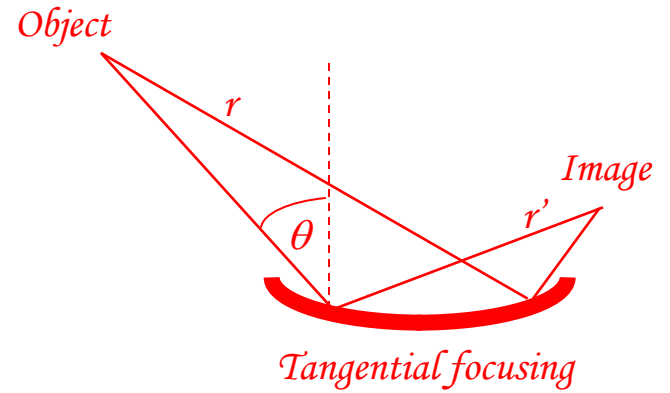
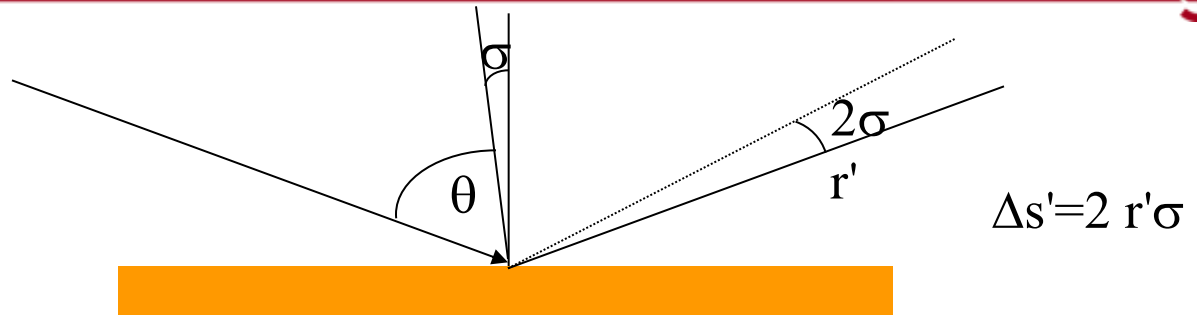


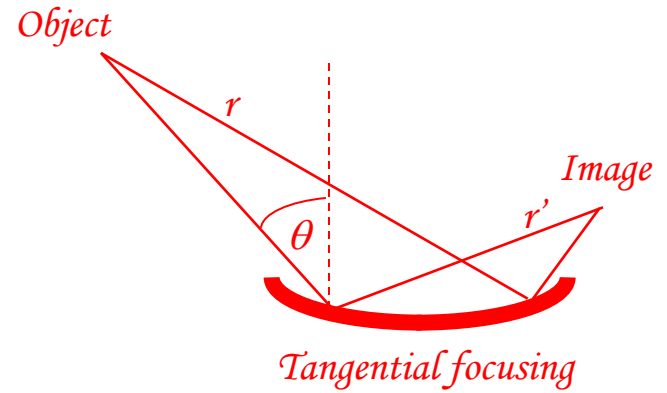
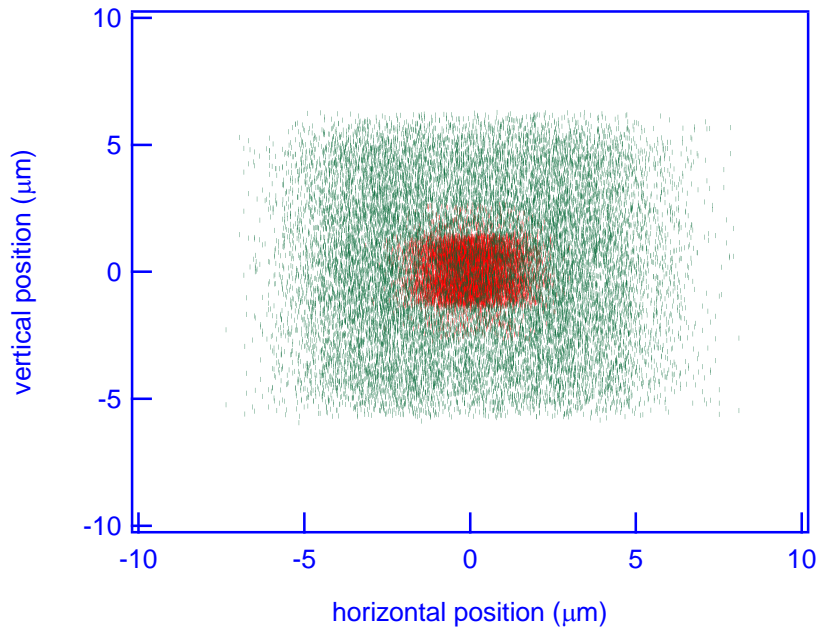
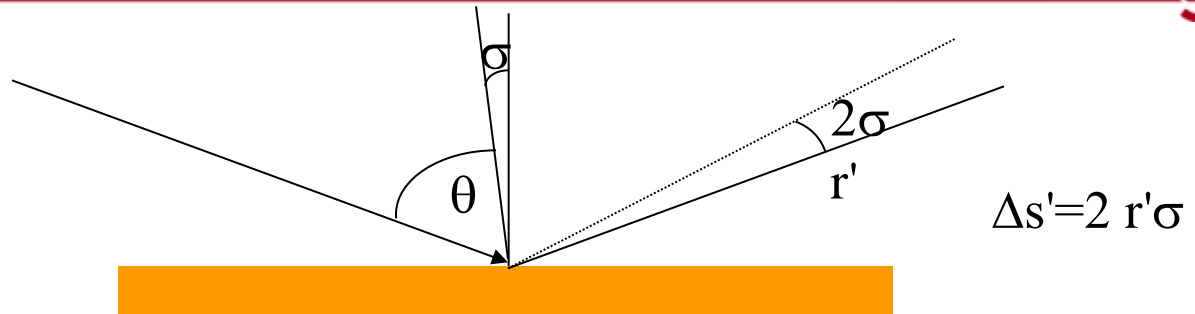
$$1 \text{ mm} / \sin(0.2^\circ) > 1.5 \text{ m}$$



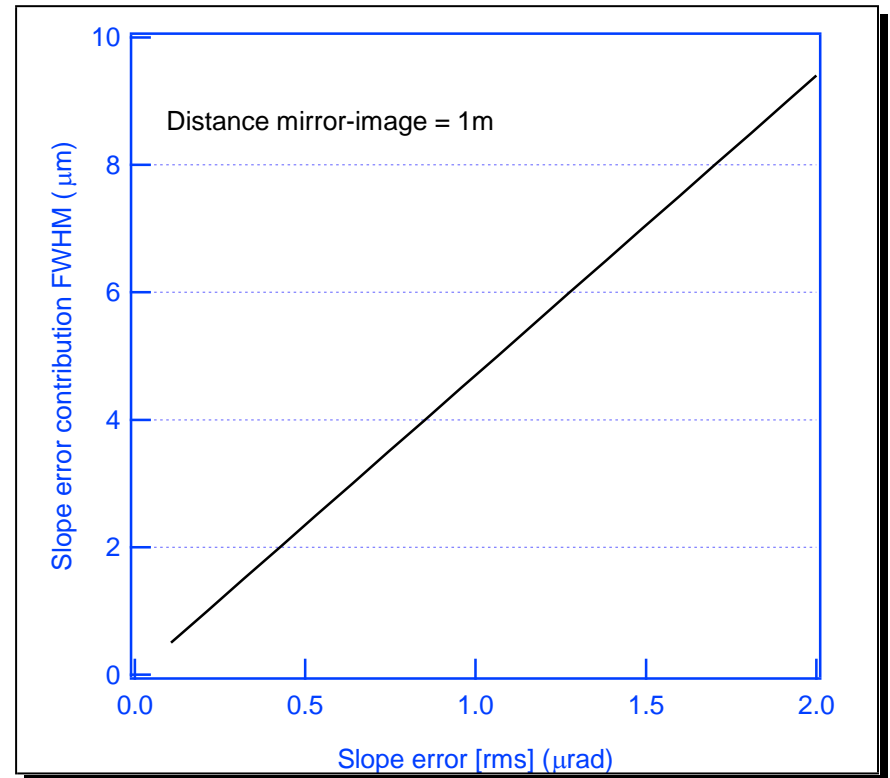
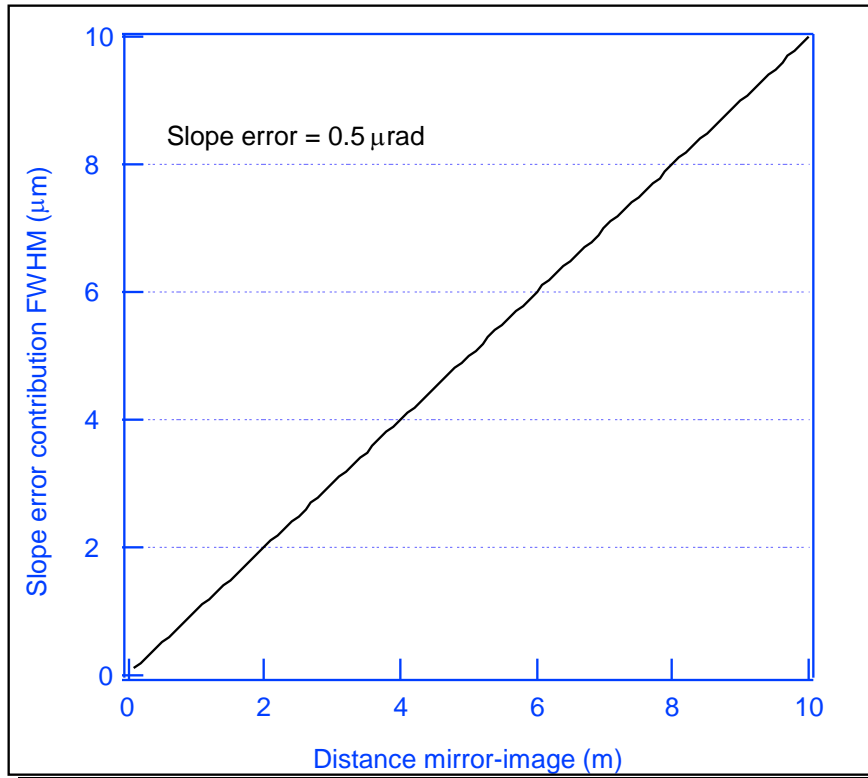
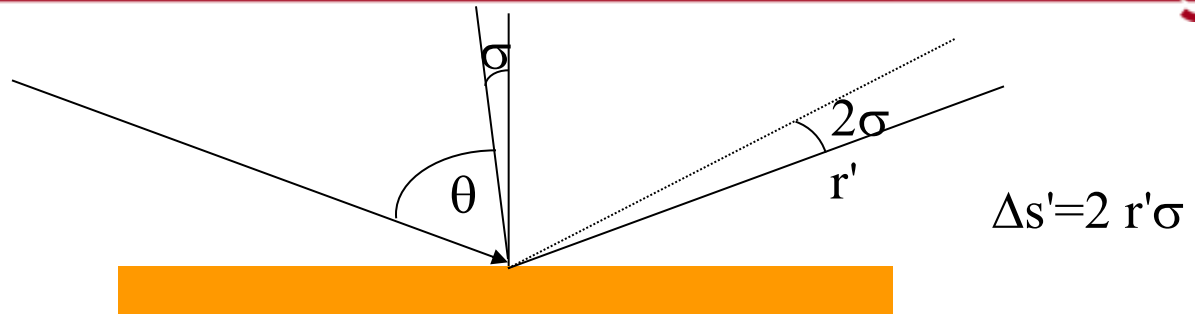
$$4\text{-}5 \text{ mm} / \sin(2^\circ) < 200 \text{ mm}$$





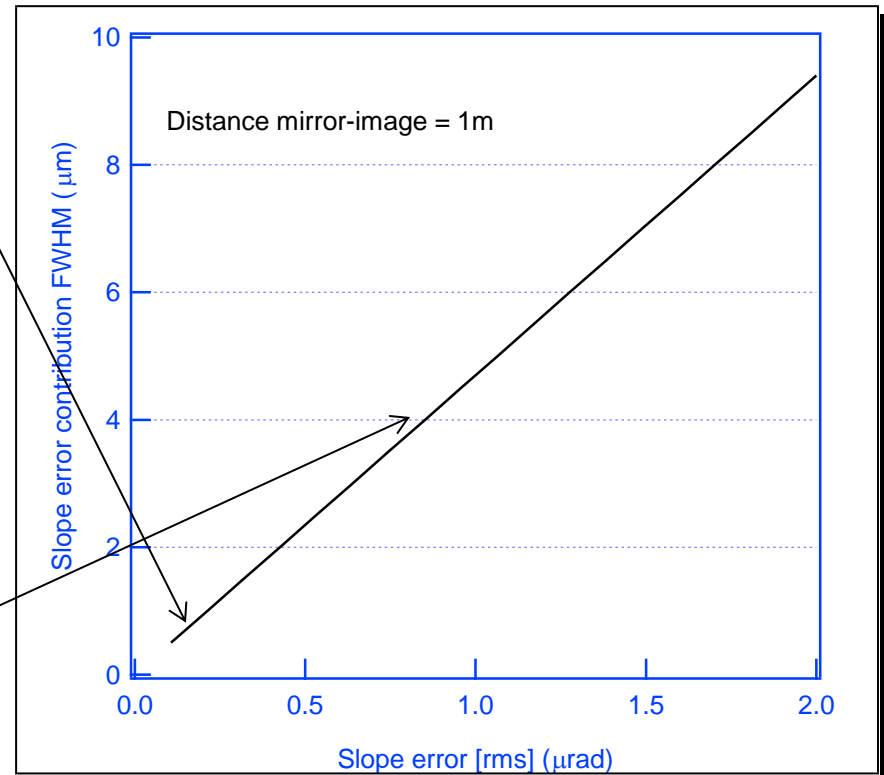


$$s' = Ms + \overline{(2 r' \sigma)^2}$$

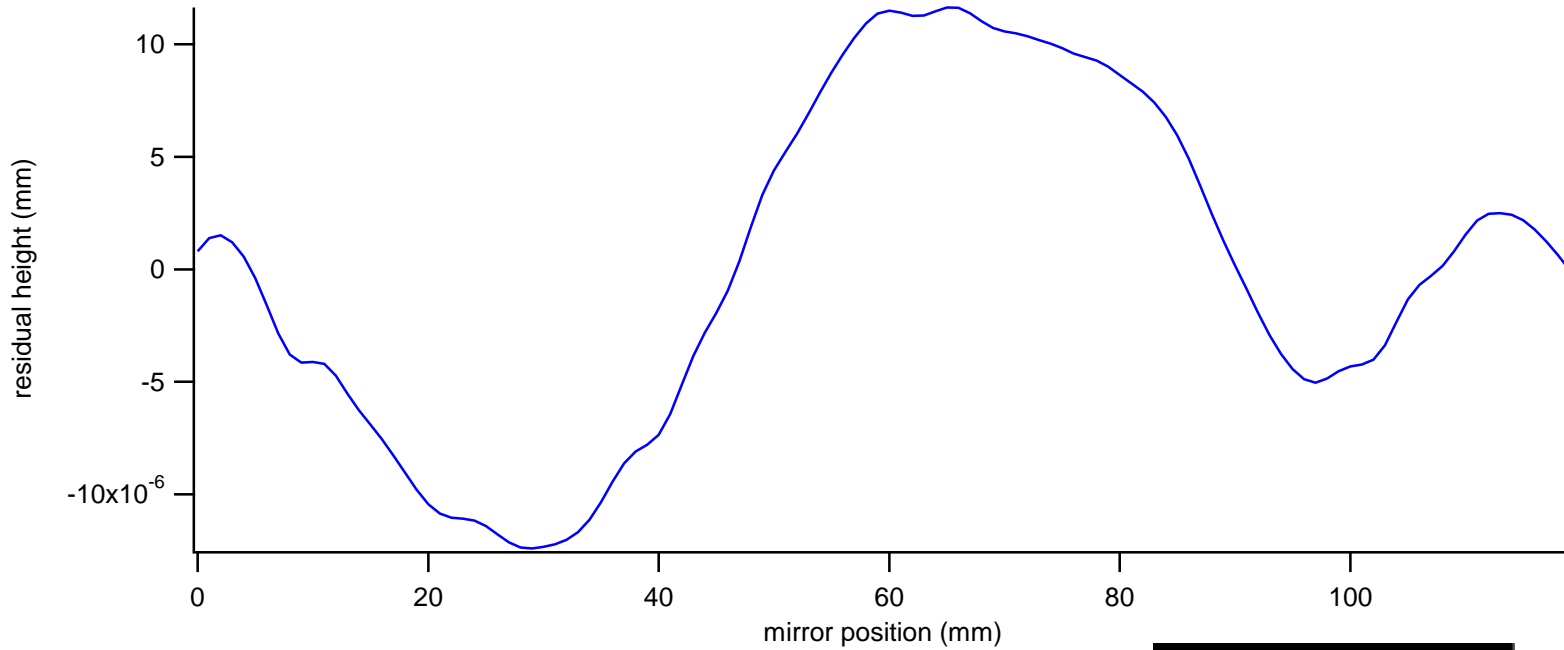


Typical manufacturer capabilities (*SESO, ZEISS, Winlight, Insync*)

Shape	Length	rms errors
Spherical/flat	Up to 500 mm	< 0.1 μrad
Spherical/flat	> 500 mm	< 0.5 μrad
Toroidal	Up to 500 mm	$\sim 1 \mu\text{rad}$
Toroidal	> 500 mm	$\sim 2 \mu\text{rad}$
Elliptical	Up to 500 mm	$\geq 1\text{-}2 \mu\text{rad}$
Elliptical	> 500 mm	> 2 μrad



State of the art SR manufacturer capabilities

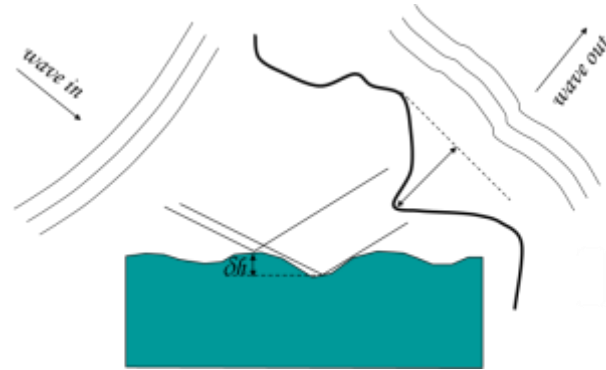


$$\text{Strehl Ratio} \approx e^{-(2\pi\phi)^2} \approx 1 - (2\pi\phi)^2$$

The Strehl Ratio (SR) is defined as a ratio of the maximum intensity in the focus, with and without wave front distortions which are introduced by the optics

$$\phi = \frac{2\delta h \sin \theta}{\lambda}$$

ϕ is the wave distortion (phase)



$$\delta h = \lambda \frac{\sqrt{1 - \text{Strehl Ratio}}}{4\pi \sin \theta}$$

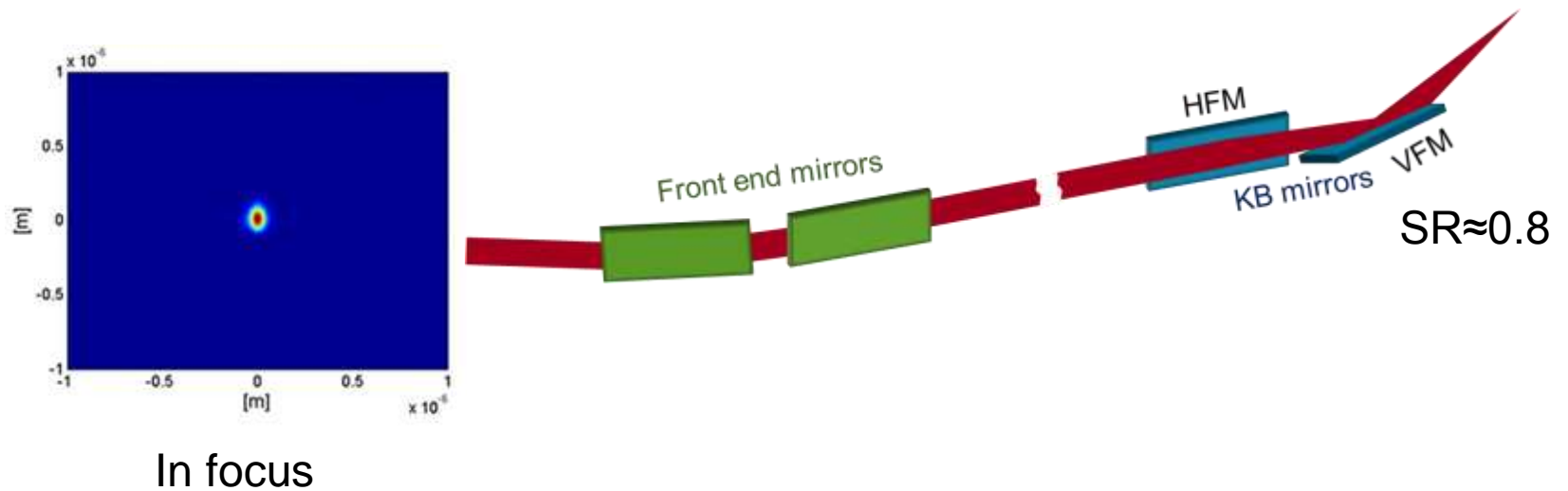
Maximum acceptable rms shape error for a given Strehl Ratio
 $SR \geq 0.8$ (according to the Marechal Criterion) is necessary to have
 "good" optical system

→ Angle of incidence dependent (larger angles need better shape errors)
 → Wavelength depended (shorter wavelengths needs better shape errors)
 → This is the value we must "specify" for the mirrors

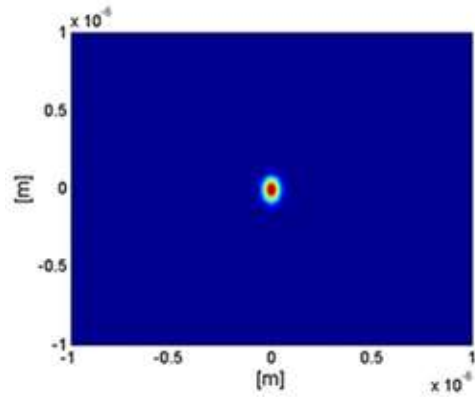
Angle of incidence (mrad/deg)	Photon Energy (KeV)	Shape error (nm)
3/0.17	5	2.1
	20	0.5
1.35/0.077	5	4.6
	20	1.1

The Marechal Criterion states that a good optical system has a $SR \geq 0.8$; e.g. In focus: the *Gaussian* spot intensity is ≥ 0.8 of the unperturbed *Gaussian* spot intensity

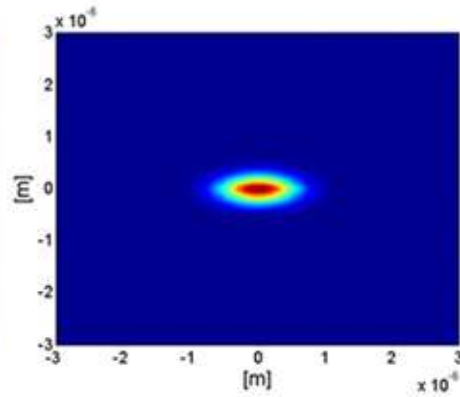
Simulations of 3 mirrors in one direction and 1 in the other for a global SR of 0.8



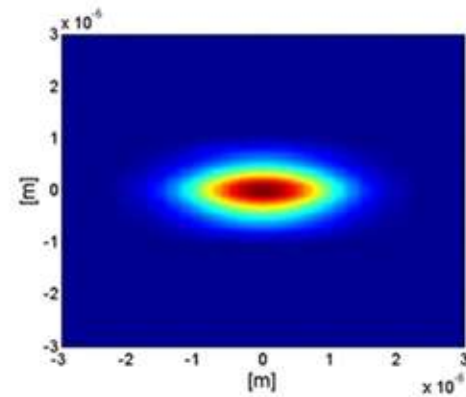
We need better.....



In focus



1 mm out of focus



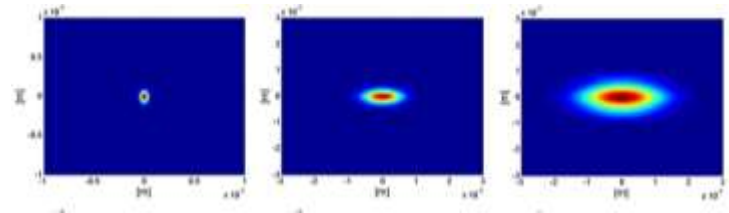
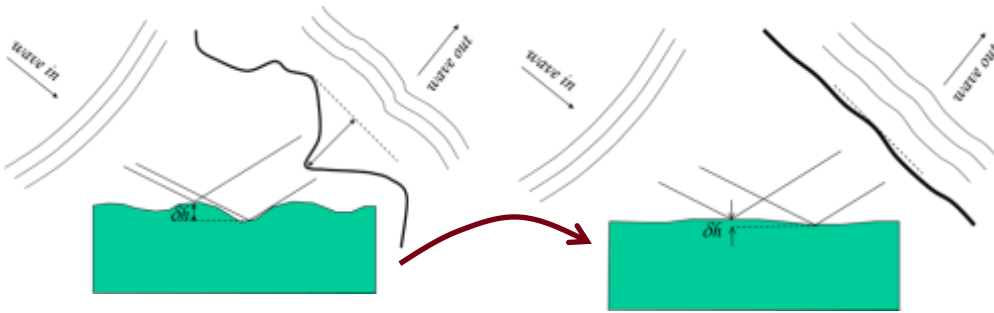
2 mm out of focus

SR \approx 0.97

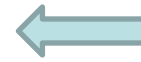
SR \approx 0.8

How to compensate wavefront distortions

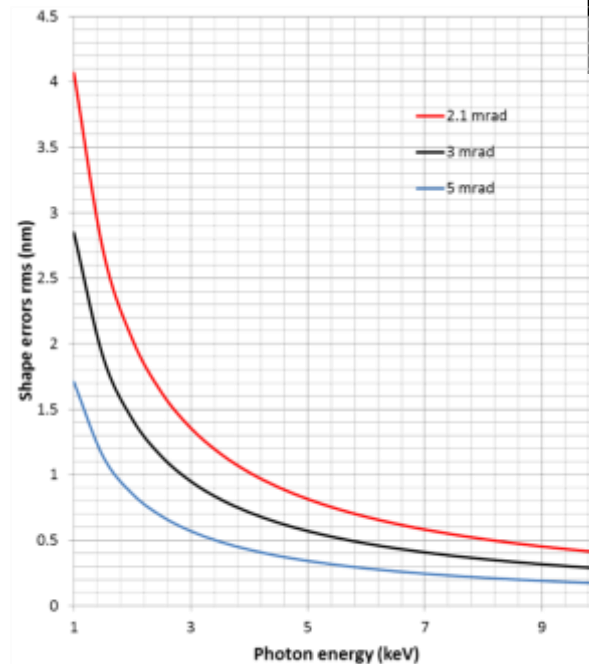
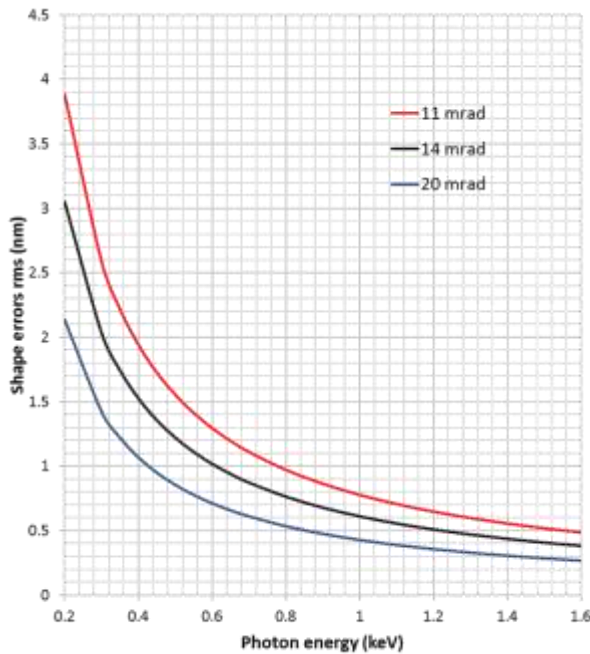
SLAC

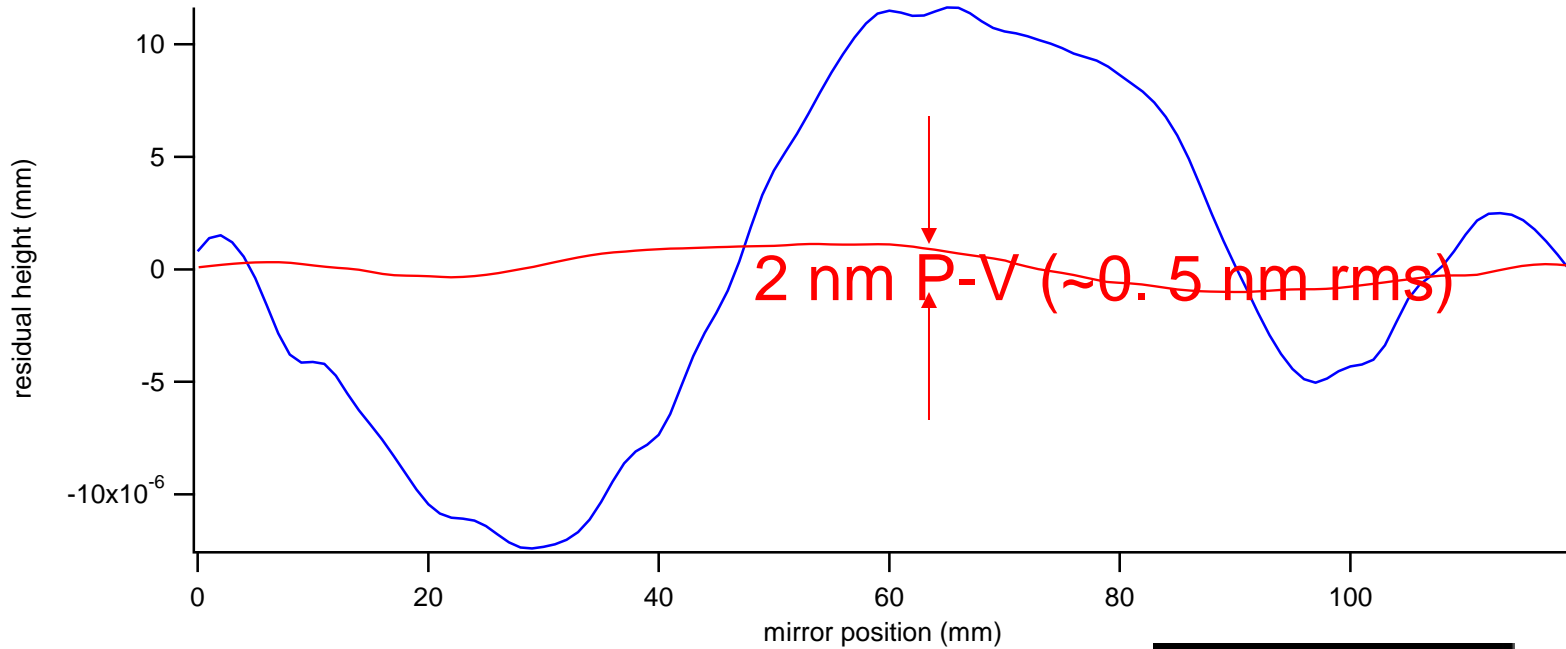


HXR; 1.35 mrad, 13 keV → **0.56 nm rms**
 SXR; 12.0 mrad, 1.3 keV → **0.6 nm rms**



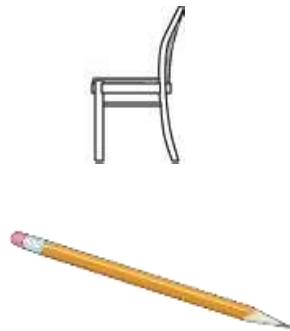
Angle of incidence (mrad/deg)	Photon Energy (KeV)	Shape error (nm)
1.35/0.077	5	4.6
	20	1.1
	13	1.78





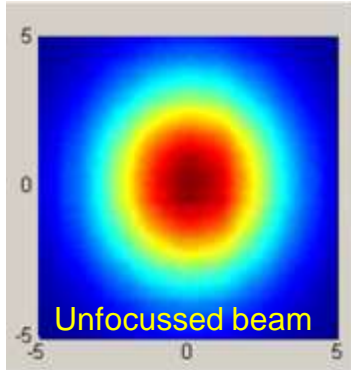
Typical SR mirrors

Required FEL mirrors

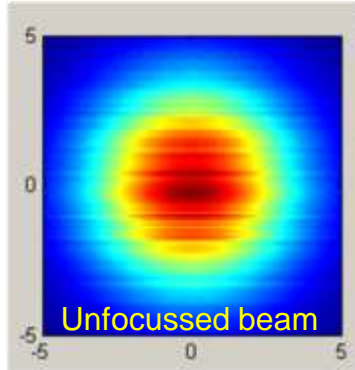


Affected by truncation (limited acceptance) and wavefront deformation (shape errors)

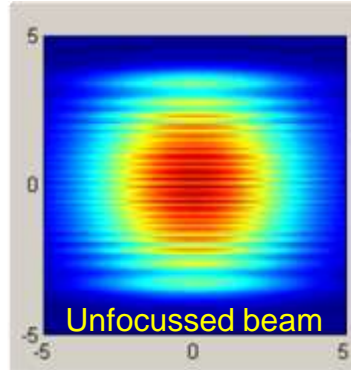
∞ acceptance



2 FWHM accept.

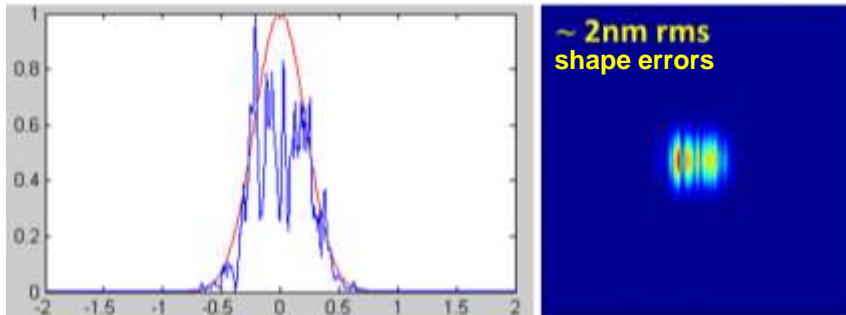


1 FWHM accept.

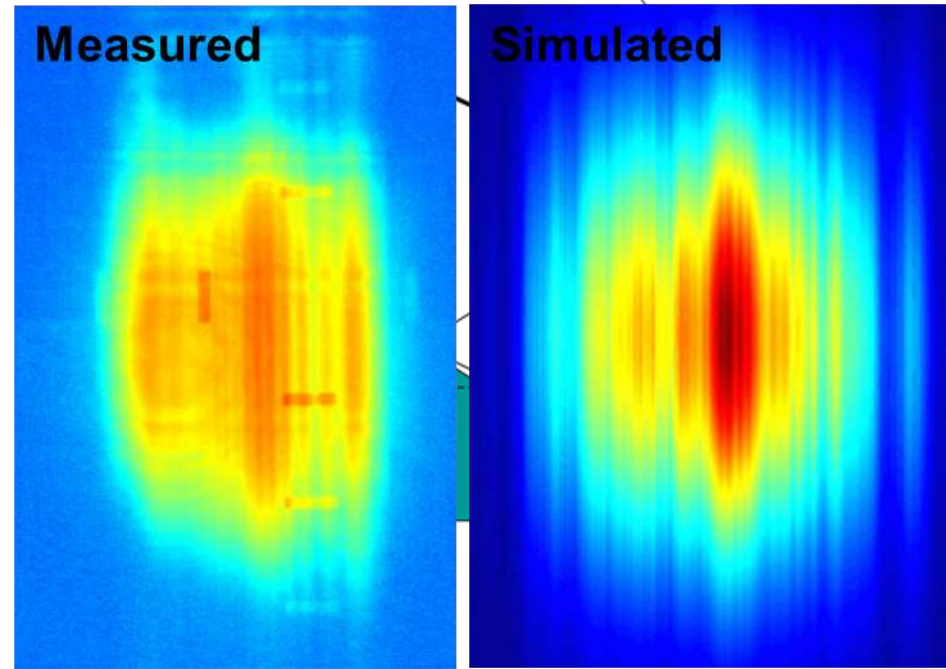


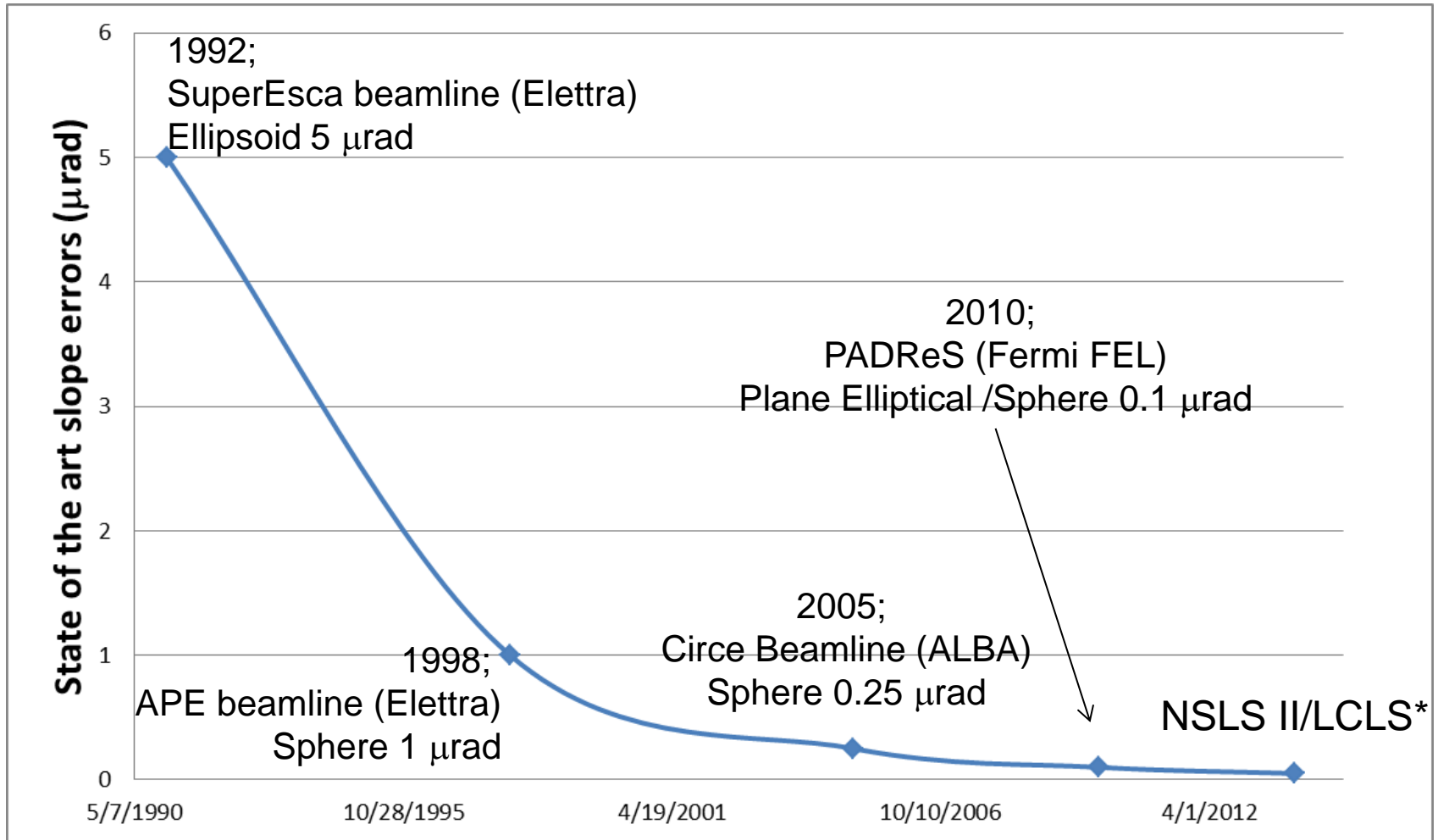
The LCLS mirrors were procured according to the state of the art availability e.g. 450 mm long mirrors with 2 nm rms shape error (compromise between shape and length)

Out of focus beam



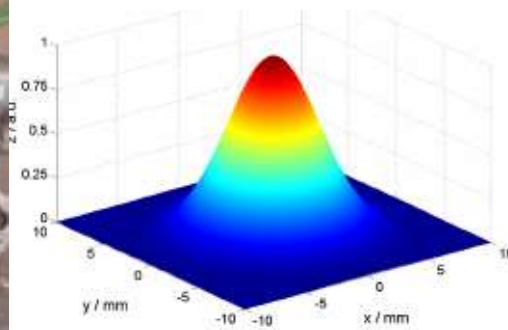
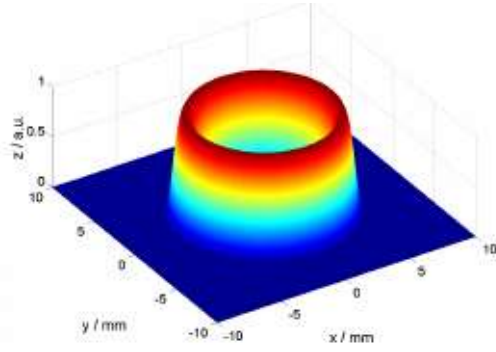
LCLS is upgrading the mirrors with better figure and larger acceptance



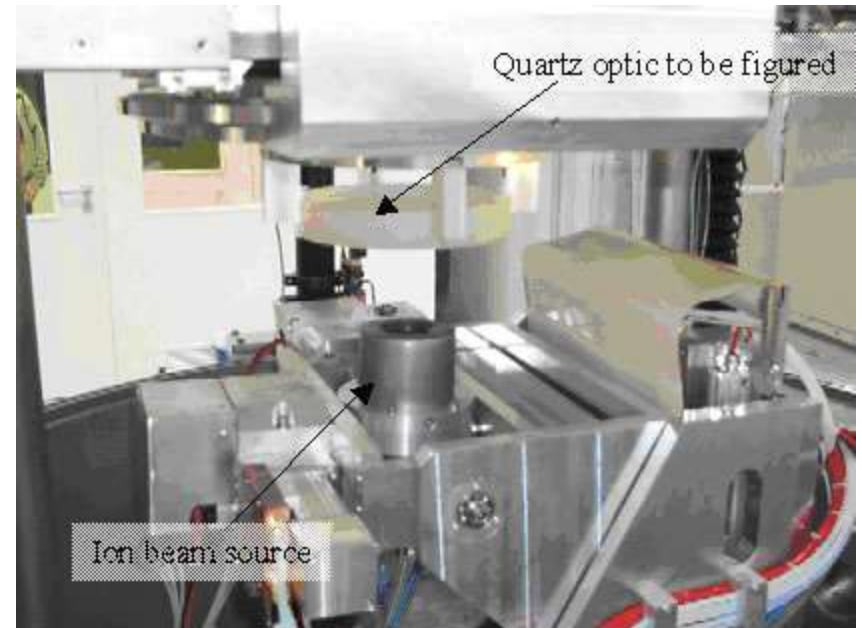
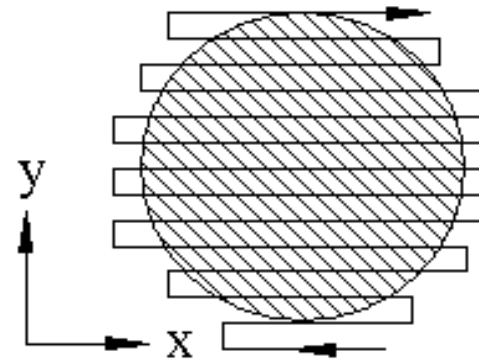
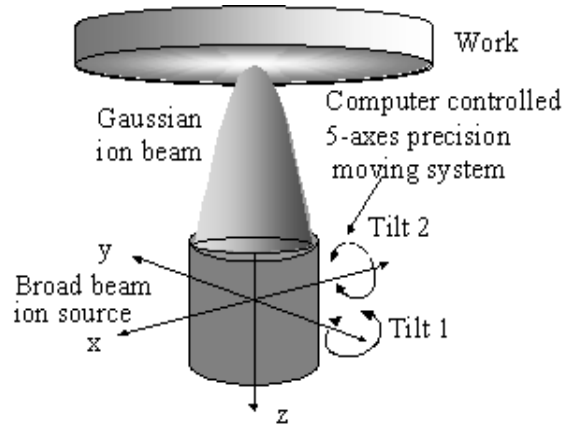


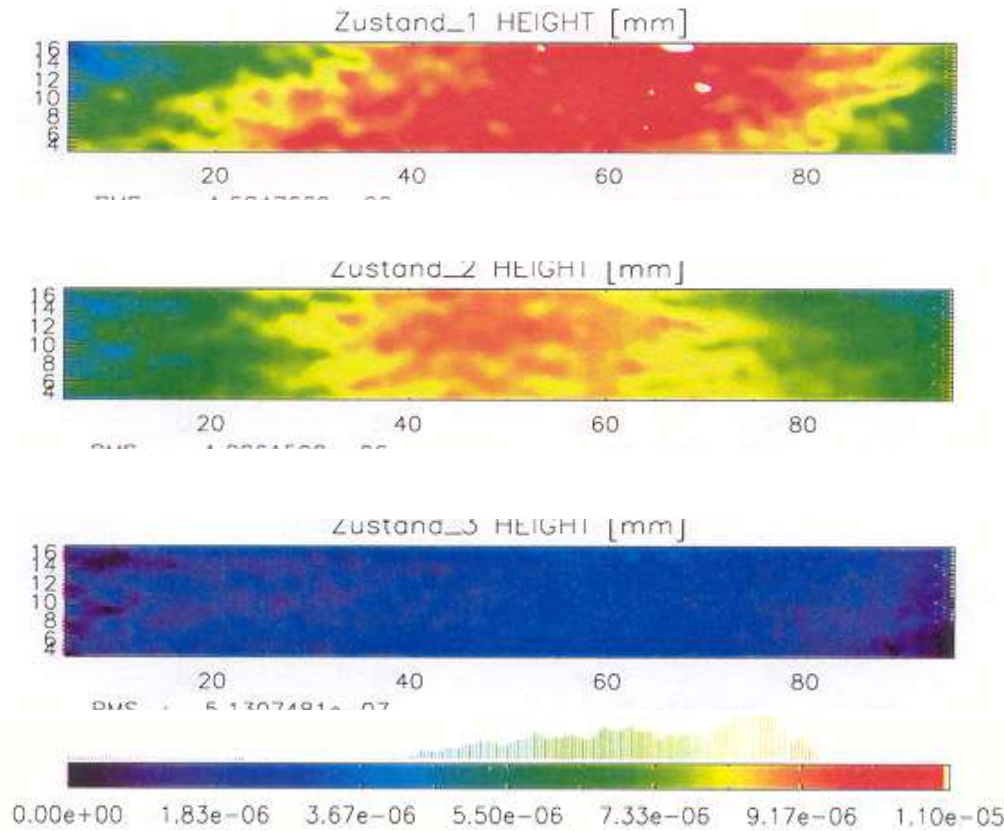
*LCLS mirrors are specified in height (nm rms).

Polishing (CCP) effect



Estimated best quality:
2-3 nm rms; 0.5 μrad rms





1. step

Height: 11.8 nm pv



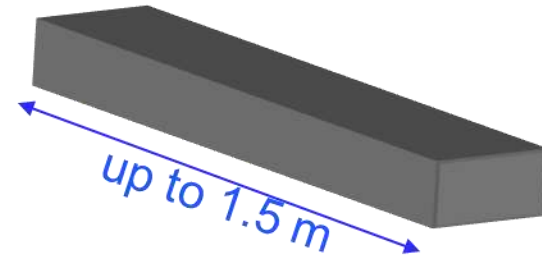
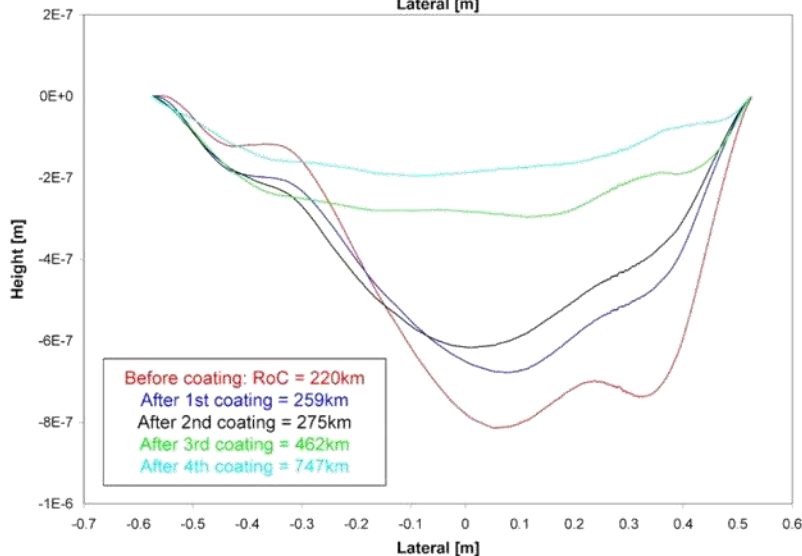
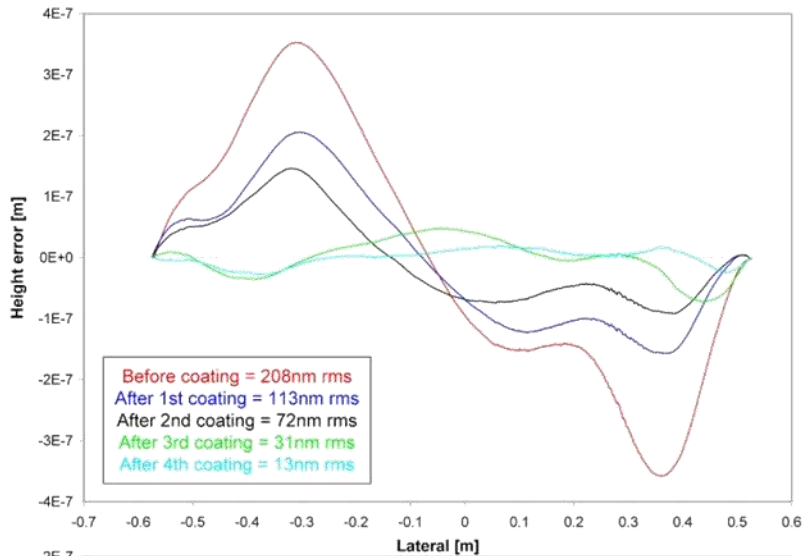
2. step

Height: 5.1 nm pv

3. step

Height: 3.3 nm pv

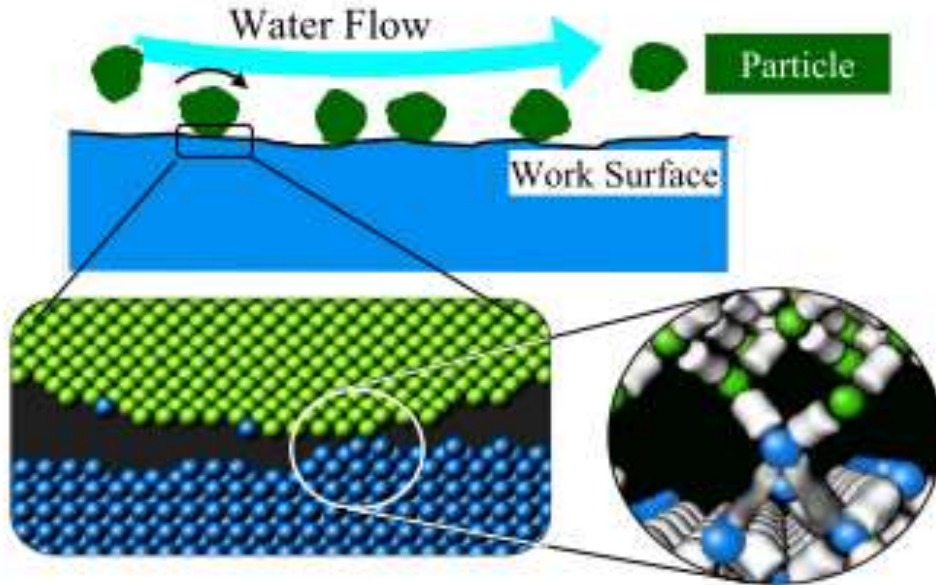
Estimated best quality:
1 nm rms; 0.1 μ rad rms



- 1) Classical polishing
 - 2) High precision metrology
 - 3) Error correction by Rh controlled deposition
 - 4) Second iteration with metrology
 - 5) Second differential coating deposition
 - 6) Third.....
 - 7)
 - 8)
 - 9)
- nn) Final required slope/shape error reached (hopefully)

Estimated best quality:
2-3 nm rms; 0.1 μ rad rms

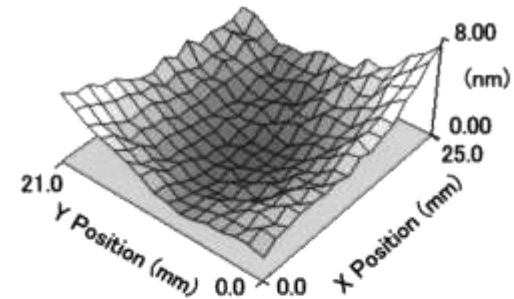
Processing technique to flat a surface in an atomic level



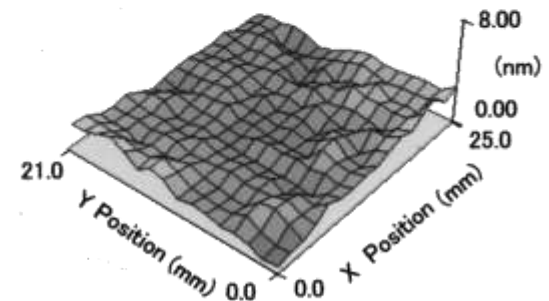
Strong Points :

1. Owing to processing at an atom level, it is **possible to be flatted at an atom level.**
2. For chemical processing, **no distortion on surface.**
3. For regional processing by numerical control , it is **possible to make various shape of mirrors.**

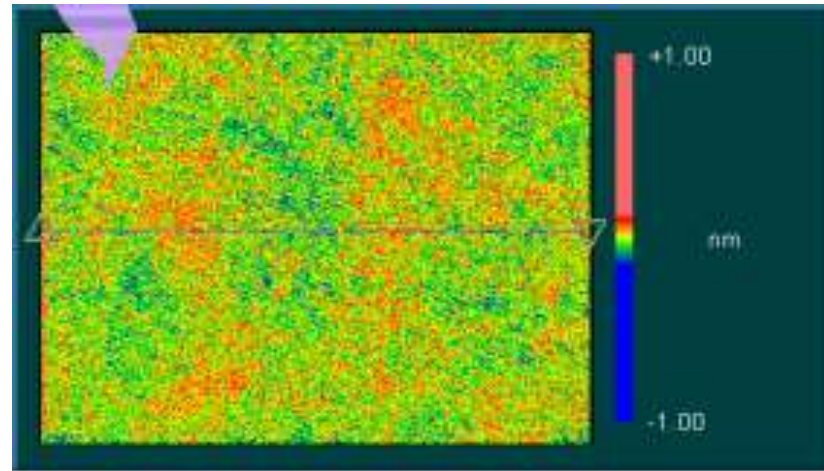
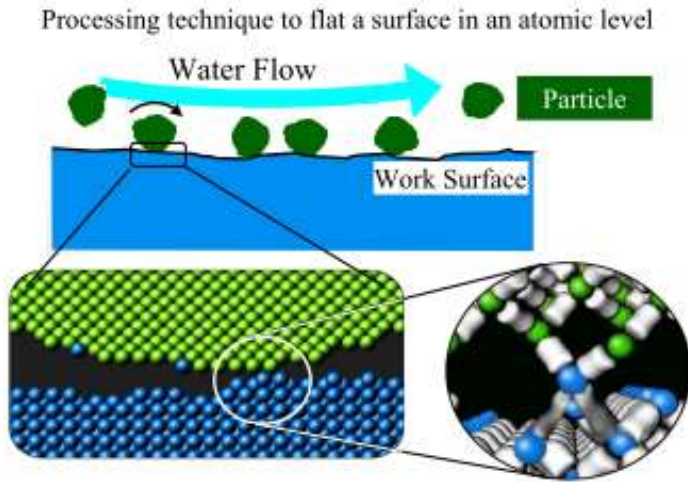
Pre-polishing (1.3 nm rms)



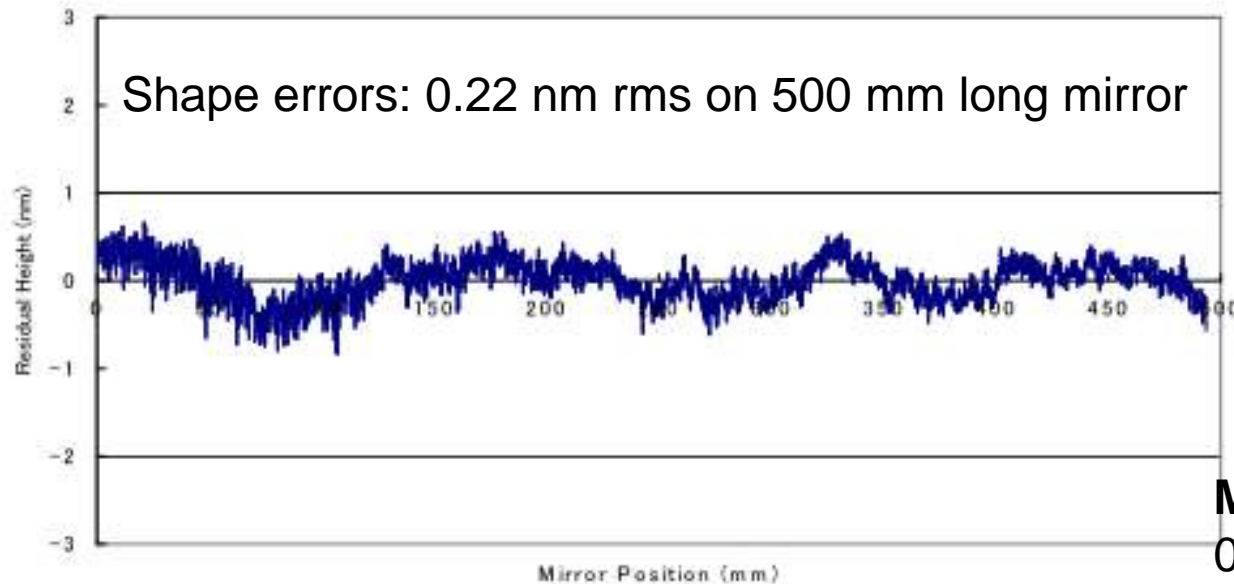
Measuring



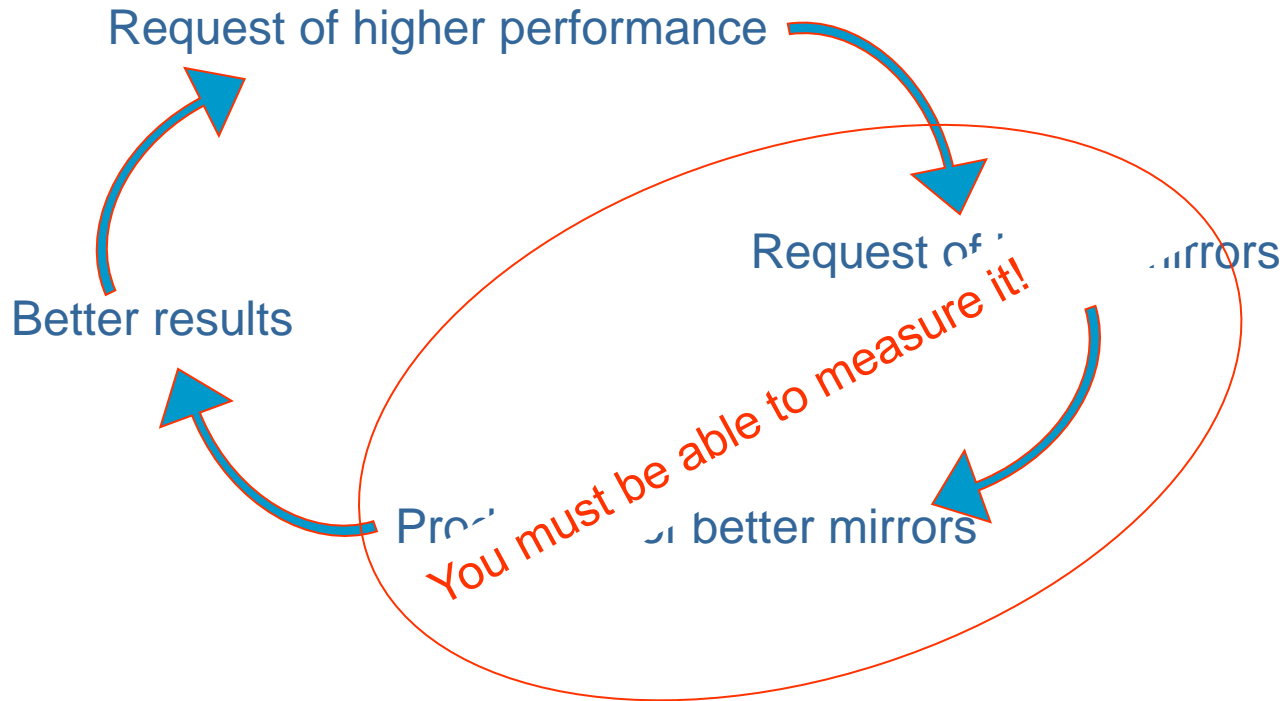
Apply atomic level correction
(0.14 nm rms)



Roughness : 0.056 nm (0.6Å) rms



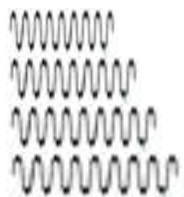
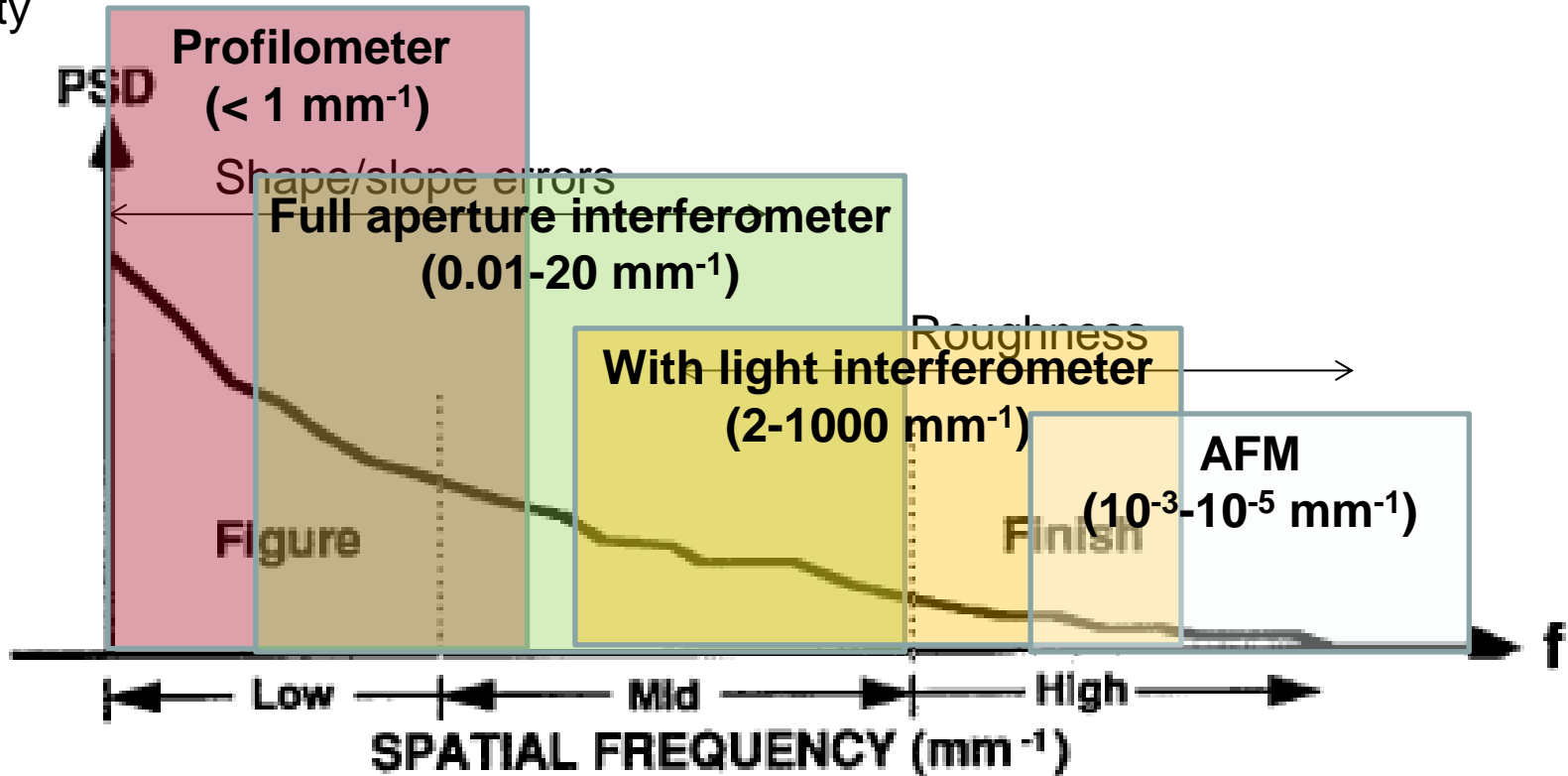
Measured best quality:
0.2 nm rms; 0.05 μ rad rms



Metrology improvement drove the mirror manufacturing improvement and, ultimately, push the science forefront limits*

**ok... it's a bit of a stretch...*

The rms deviation from the ideal surface at different periods is called the Power Spectral Density



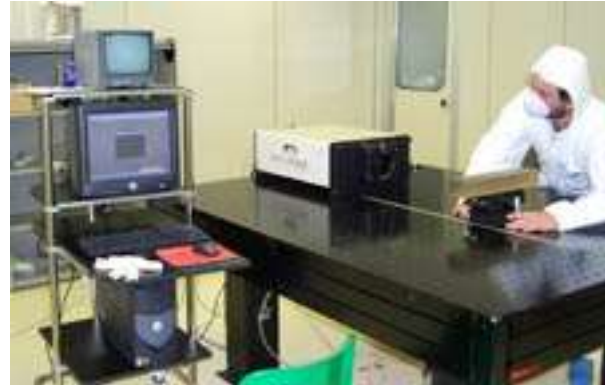
$$PSD(f) \propto \sum_{n=1}^N A_n e^{2\pi i f(nD)}$$

$$\sigma = \left(\int_{f_{\min}}^{f_{\max}} PSD(f) df \right)^{1/2}$$

Clean Room class 10,000 minimum, 1,000 ideally.
Thermo stabilized within $\pm 1^\circ$ minimum (0.1° or better ideal)



LTP / NOM
Direct slope measurement
50 nrad slope error accuracy
(0.1 nm rms accuracy) after
proper calibration and
environmental control
Single trace measurement up
to 1.2-1.5 m in length.
Minimum spatial period
covered ~ 1 mm

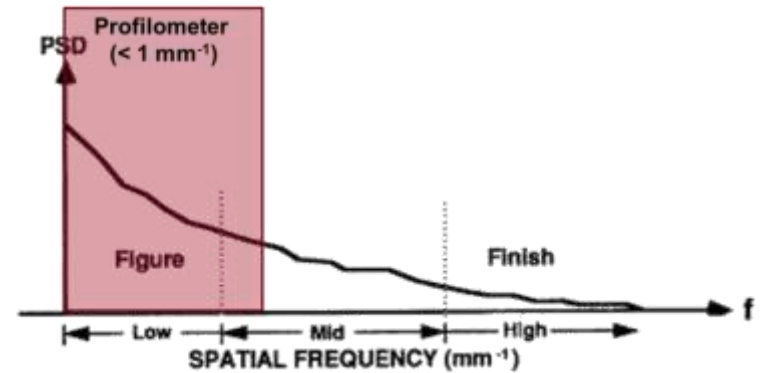
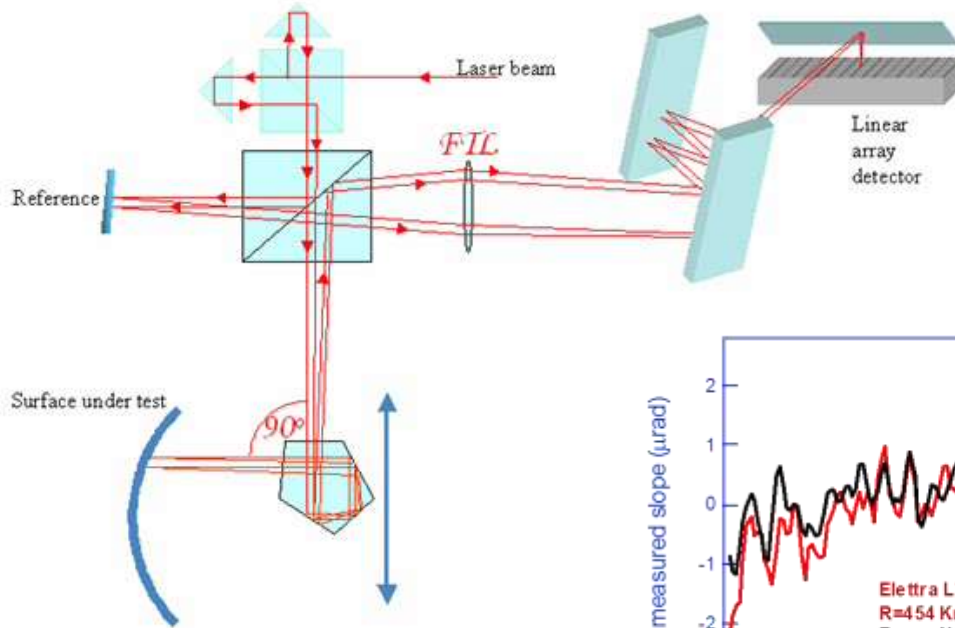


Interferometer
Direct height measurement
 ~ 0.5 nm rms after proper
calibration and environmental
control.
2D images up to 6' diameter
Possibility of stitching
reducing the accuracy.
Minimum spatial period
covered ~ 0.05 mm

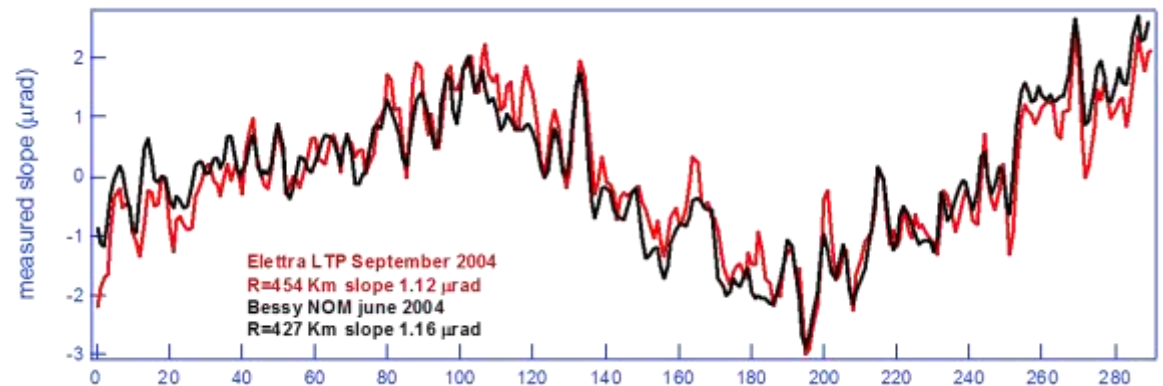


**White light micro
interferometer**
Direct height measurement
0.1 nm rms in proper
environmental condition.
2D images up to ~ 0.5 mm²
Minimum spatial period
covered ~ 0.5 μ m

We need something to measure accurately (0.1 nm rms) mirror with length up to 1 m minimum (1.5 m future prevision) and with arbitrary surface profile

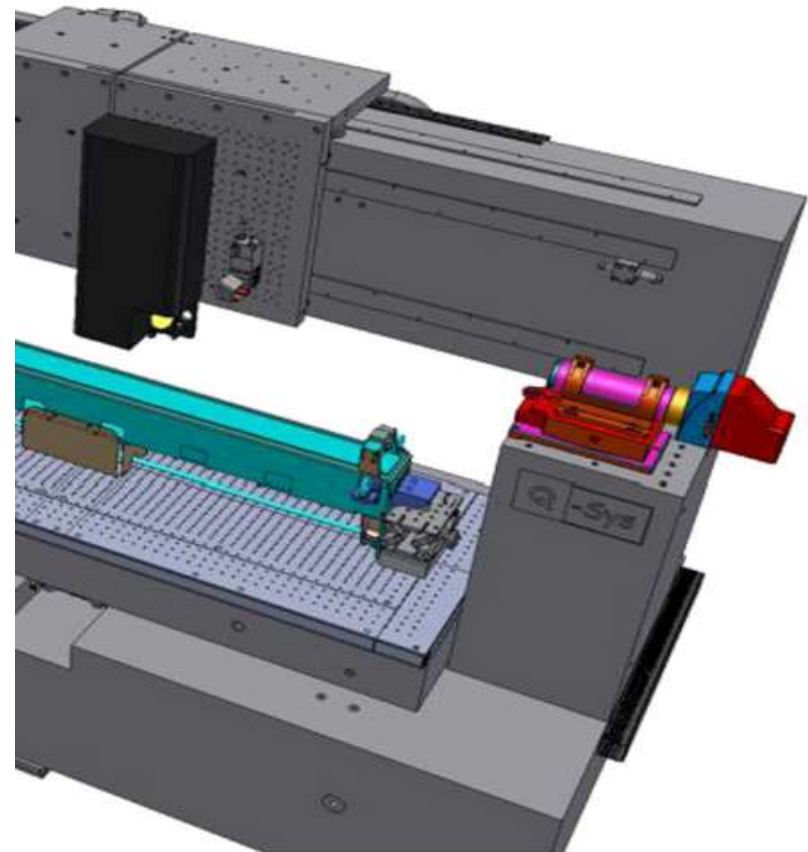
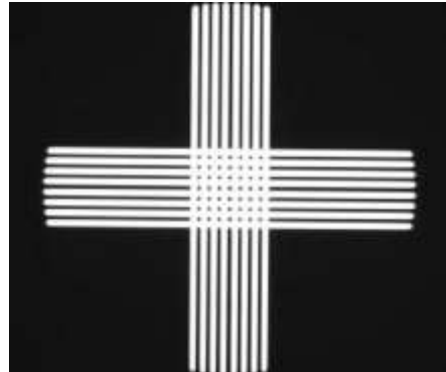


LTP
P. Takacs, S.N. Qian, S. Irick

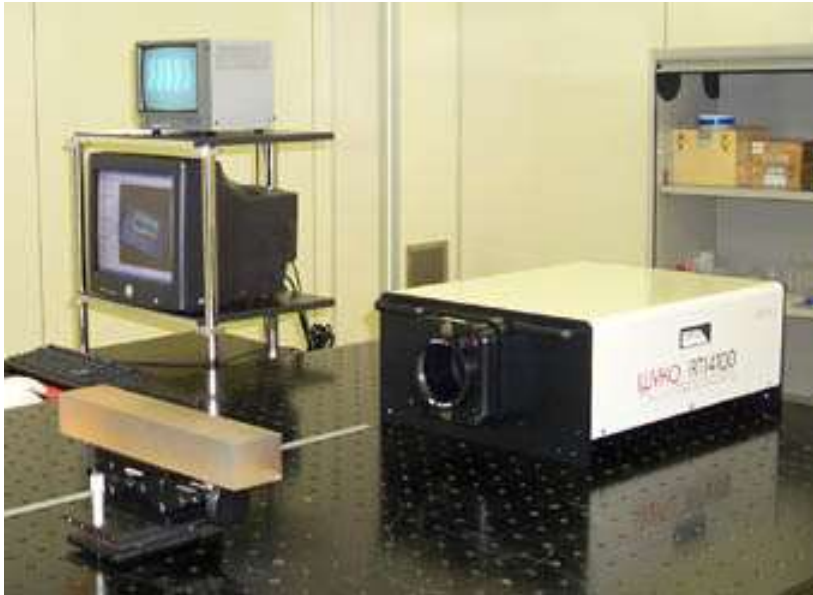


THE autocollimator to use is the Elcomat 3000/10 (by Möller-Wedel)

- Works in presence of multiple reflections
- Specifically developed for metrology application
- Simple repeatability 100 nrad (10 nrad averaging)
- Un-calibrated accuracy: 200 nrad over 100 μ rad (fix distance).
- Accuracy worst than 1 μ rad in the entire field of view.
- 10 mrad field of view



Precise but needs a lot of calibration



3D measurement of optical surfaces
Zygo specs: $\lambda/500$ precision
Typical: $\lambda/2-3000$ repeatability

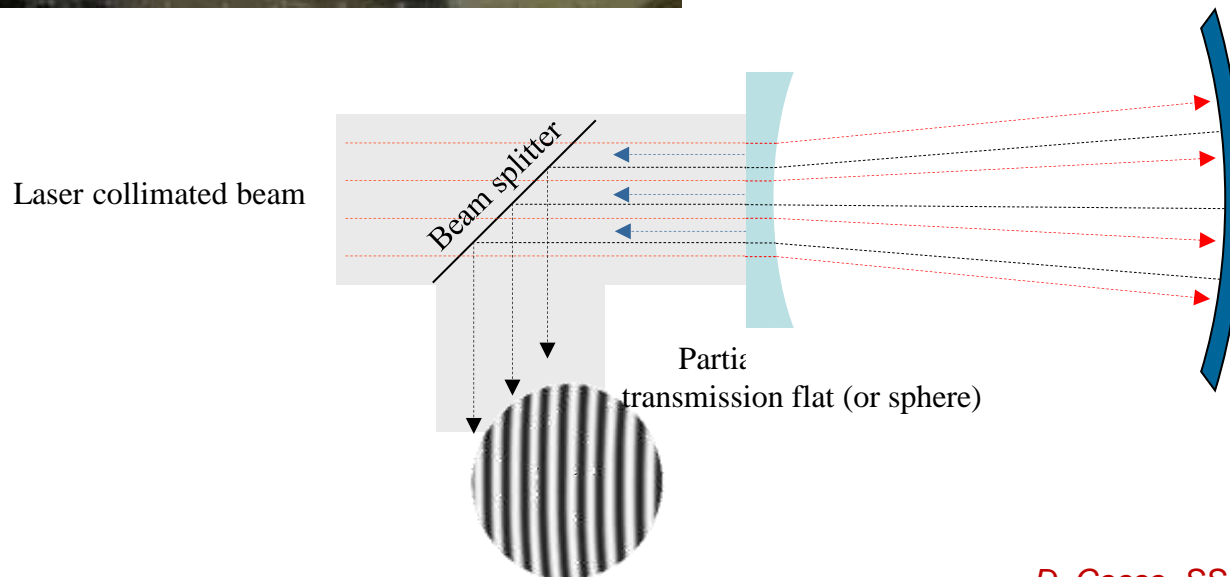
Direct measurement of radii down to 20-30 m

Optional Accessories

Transmission spheres

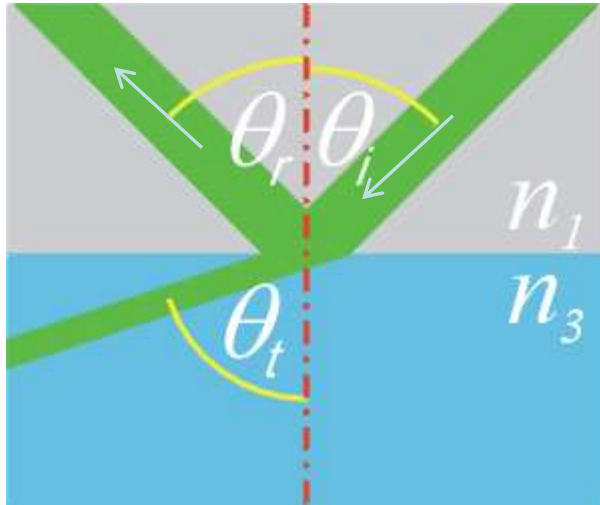
f /1.5-2 for sagittal radii and NI mirrors with $R < 1$ m

f /15-30 diverger for NI mirrors with $R > 2$ m



Optical surface damage

Above the grazing critical angle



The non reflected energy is absorbed (1/e) in $d \nabla$

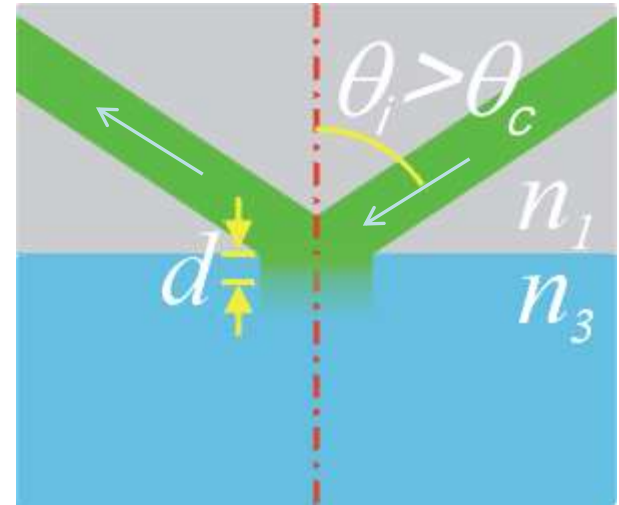
$$d = \frac{\lambda \zeta}{4\pi\beta}$$

$$\zeta = \sqrt{\frac{\sin^2 \theta - 2\delta + \sqrt{(\sin^2 \theta - 2\delta)^2 + 4\beta^2}}{2}}$$

$$n = 1 - \delta - i\beta$$

$$\delta = \frac{Ne^2 \lambda^2}{2\pi mc^2}$$

Below the grazing critical angle



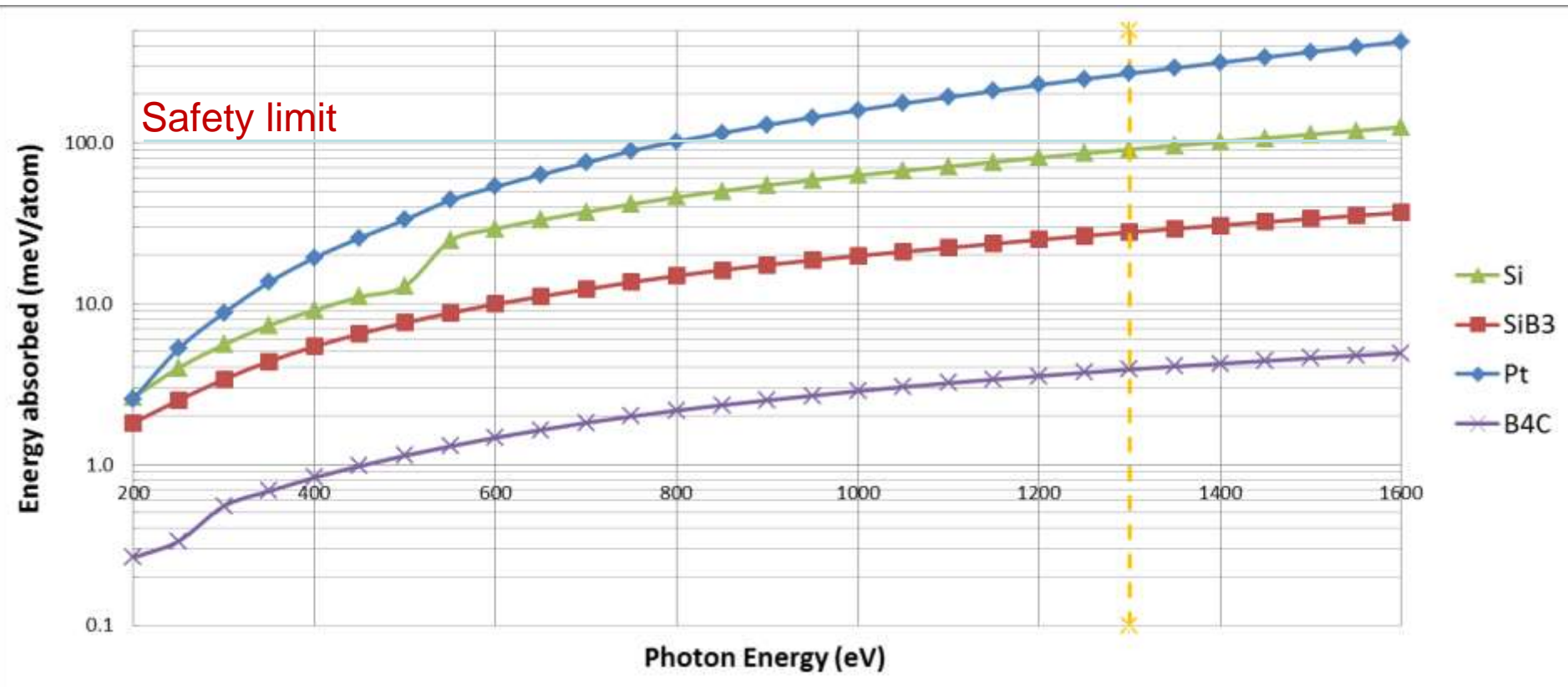
- R=reflectivity
- P=pulse power
- θ =angle of incidence
- r=source distance
- σ =source divergence
- ρ =atomic density

$$Absorbed \ Energy_{ATOM} = \frac{(1-R)P \sin \vartheta}{r \sigma_x \sigma_y d \rho}$$

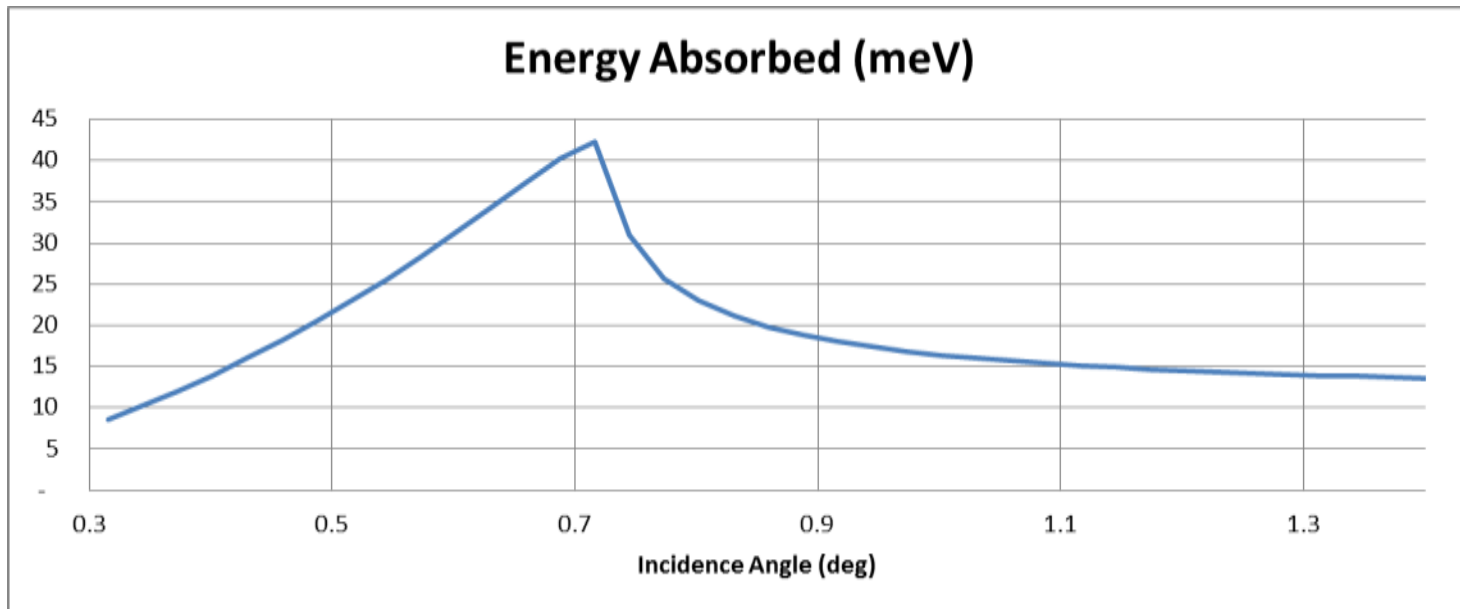
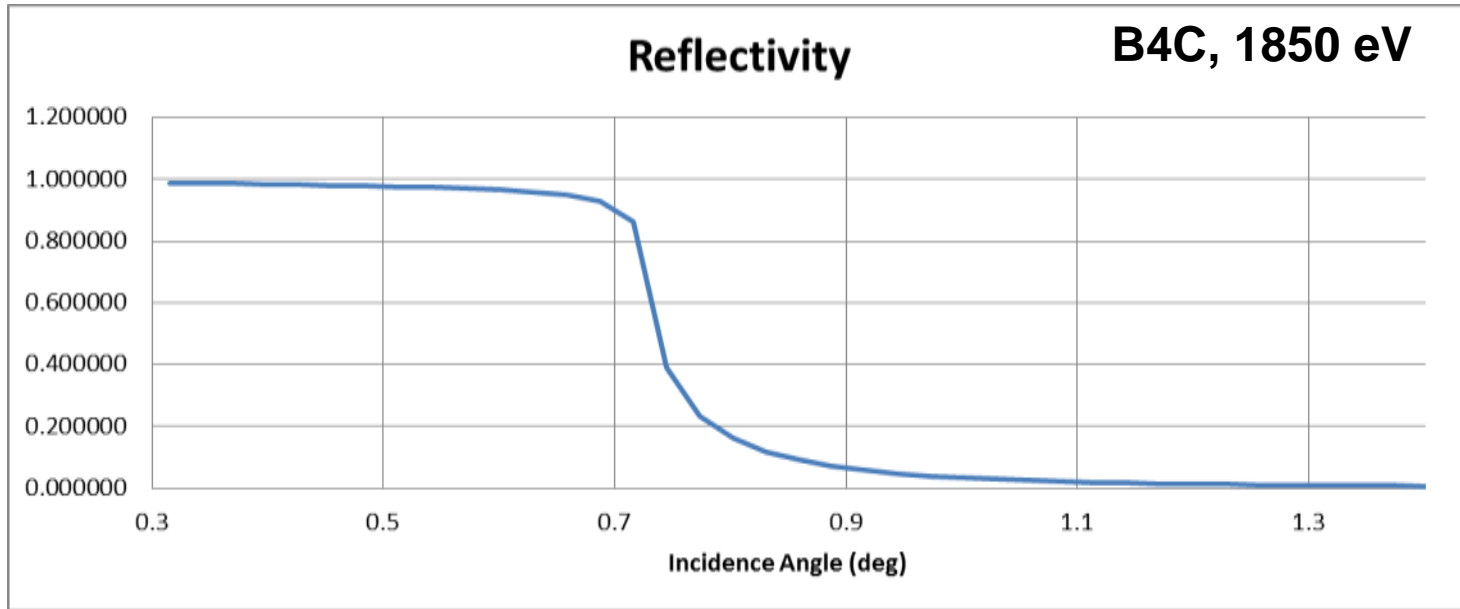
Ideal coating should have a large penetration depth (light materials) and good reflectivity (usually associated with heavy materials)

LCLS II case: 200 to 1300 eV with 2 mJ incident pulse energy

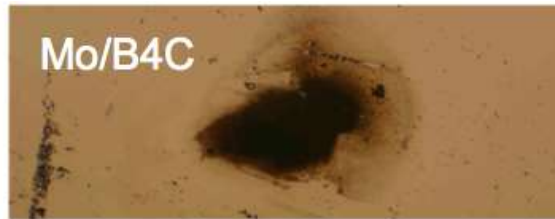
Try to work at the lowest possible angle of incidence spread the power over a large surface



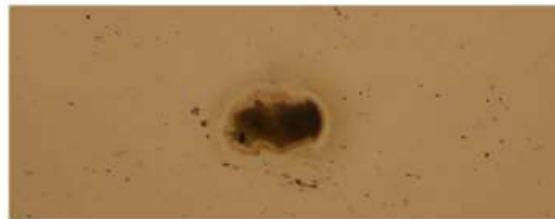
Energy absorbed vs critical angle



Example of damage for UV sources (Fermi@Elettra)



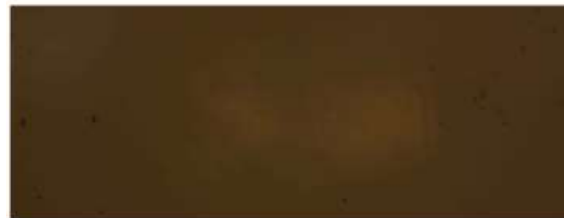
In focus
Fluence: 180 mJ/cm²



1 mm out of focus
Fluence: 60 mJ/cm²



2 mm out of focus
Fluence: 25 mJ/cm²



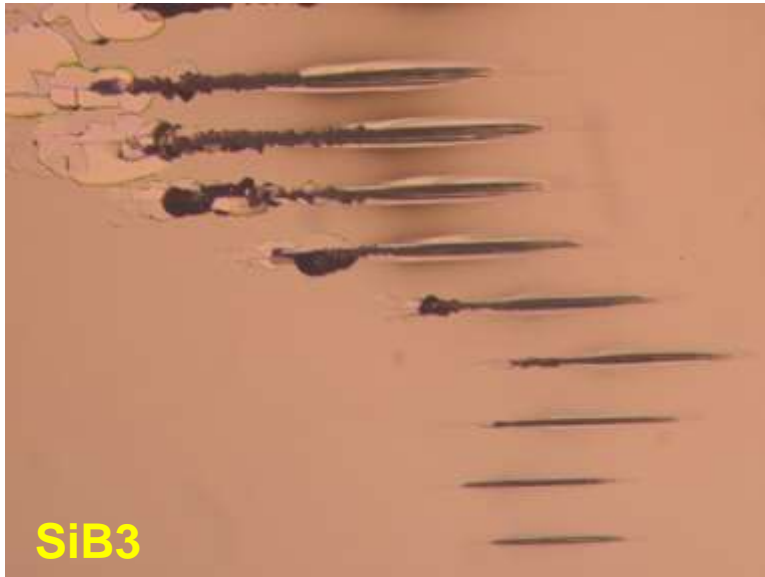
3 mm out of focus
Fluence: 12 mJ/cm²

730 μm

730 μm

α-C	60 mJ/cm ²
B4C	200 mJ/cm ²

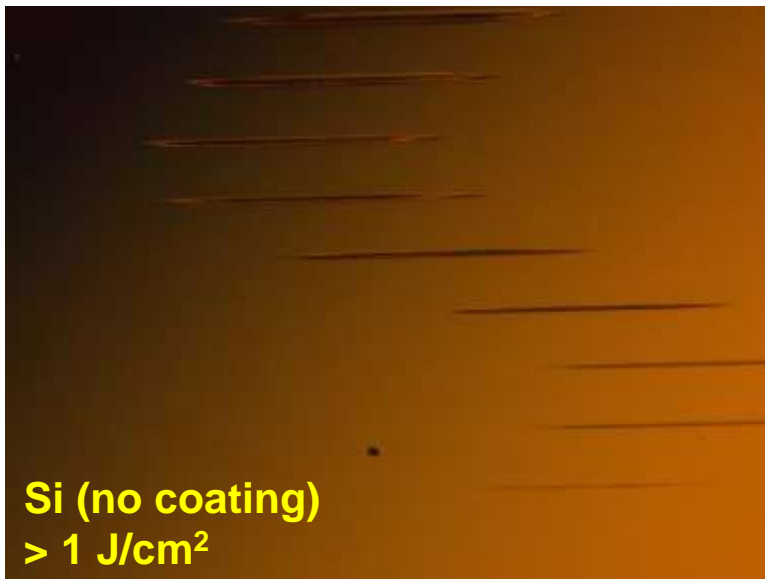
Measured at 400 nm at the EIS laser lab



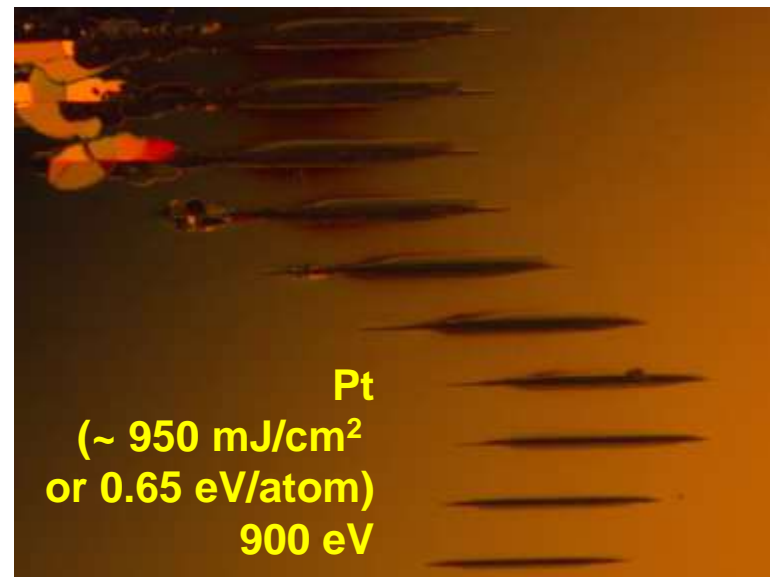
SiB3

Calculation and prediction helps... measuring the actual damage is better

By varying the fluence (power) arriving on the sample and measuring the area of the damaged surface, it is possible to estimate the damage threshold for different material and different energies.

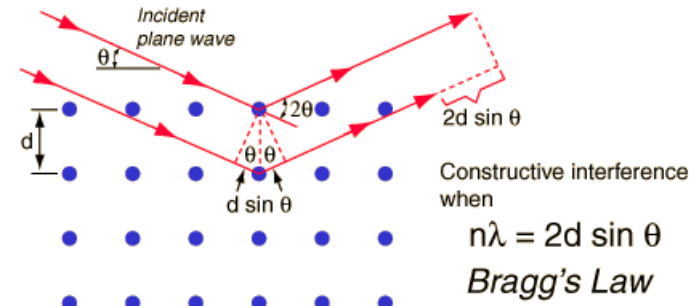
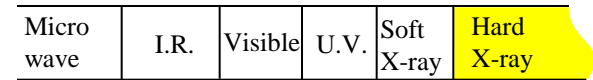
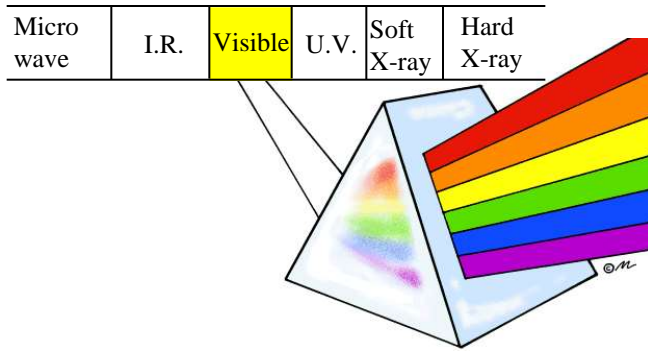


Si (no coating)
> 1 J/cm²

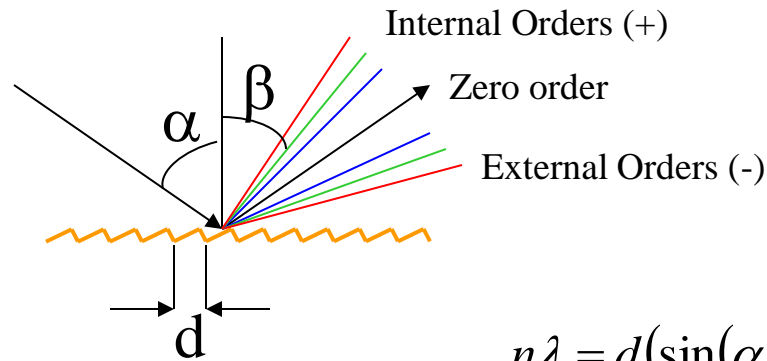
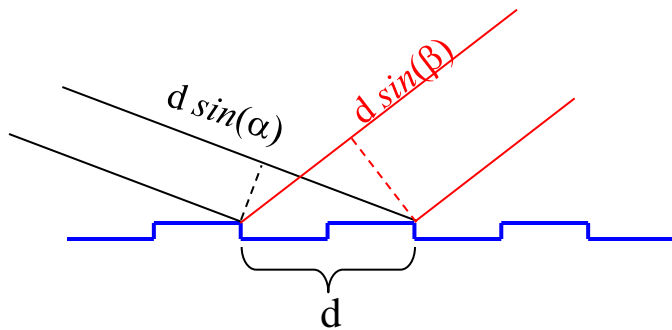
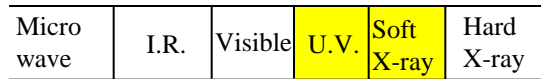


Pt
(~ 950 mJ/cm²
or 0.65 eV/atom)
900 eV

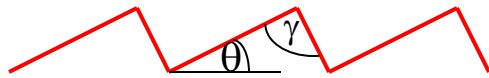
Dispersive elements



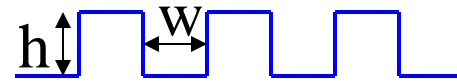
limit ~ 1-2 keV (1 nm)



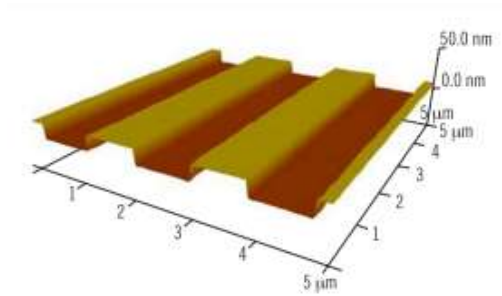
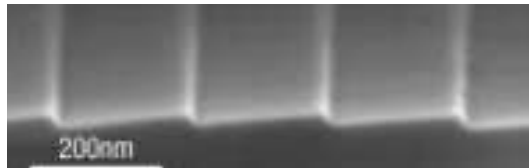
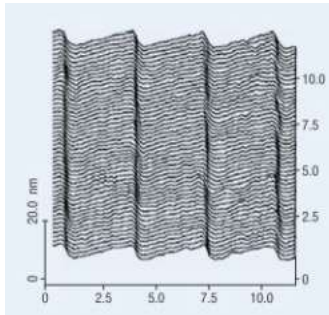
$$n\lambda = d(\sin(\alpha) - \sin(\beta))$$



Blaze profile



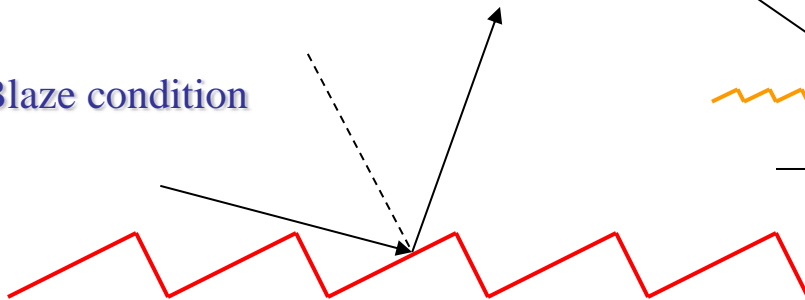
Laminar profile



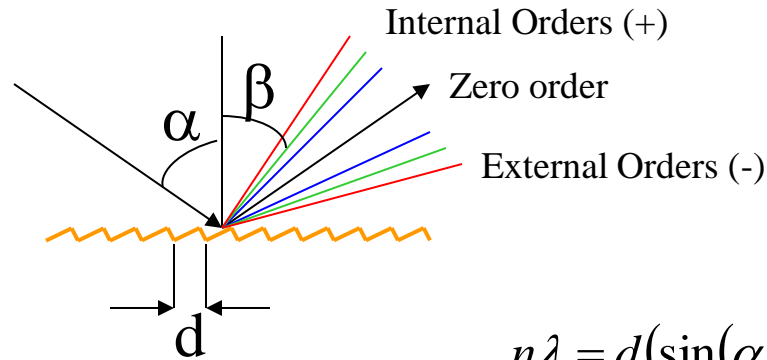
Higher efficiency

Higher spectral purity
Higher resolving power

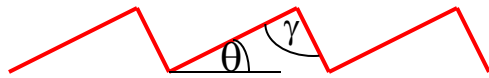
Blaze condition



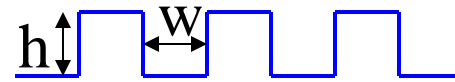
Blaze angle = $(\alpha + \beta) / 2$



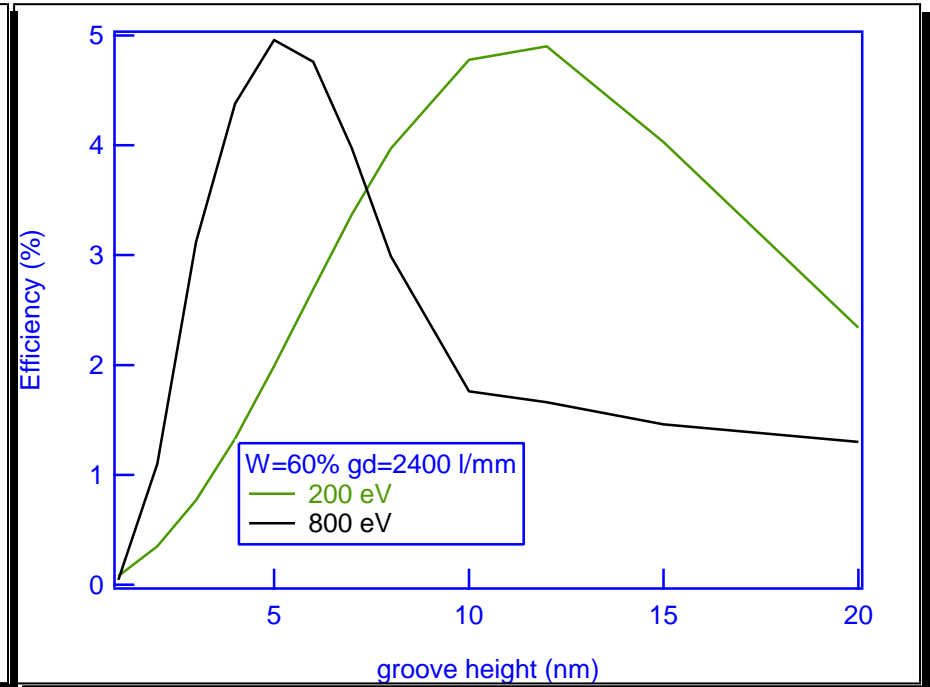
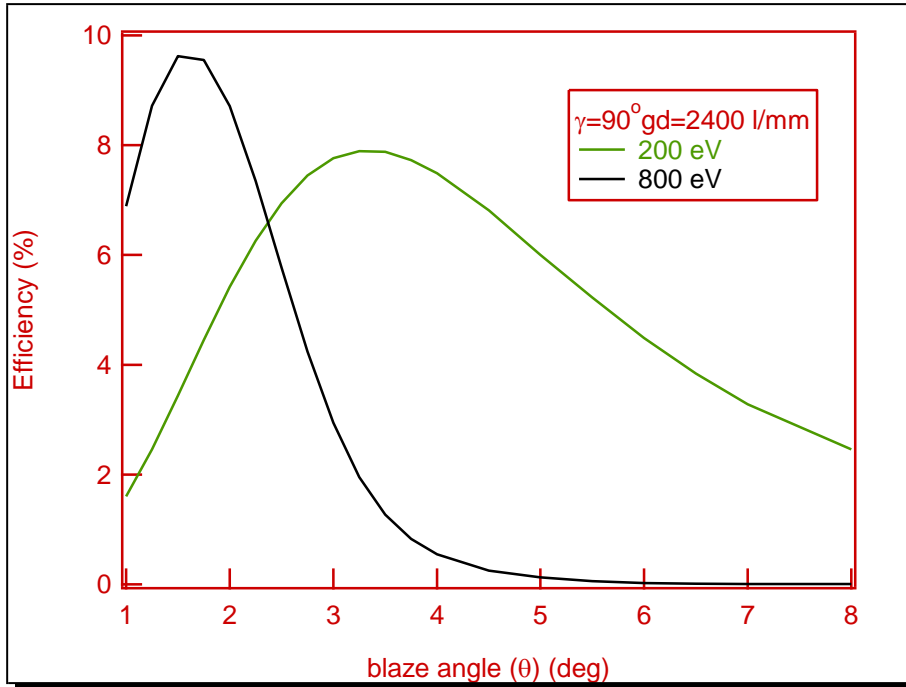
$$n\lambda = d(\sin(\alpha) - \sin(\beta))$$



Blaze profile

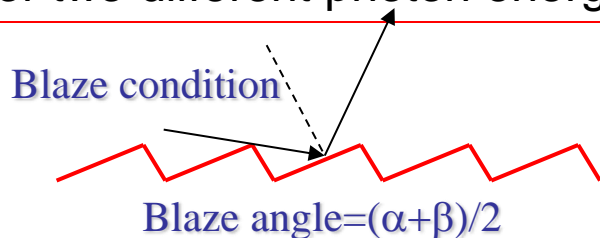


Lamellar profile

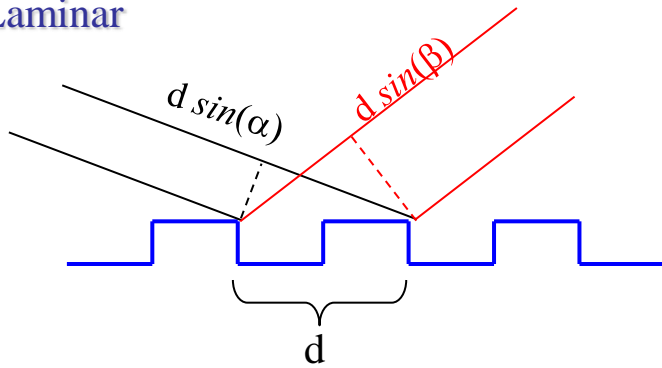


Efficiency as a function of the blaze angle for two different photon energies

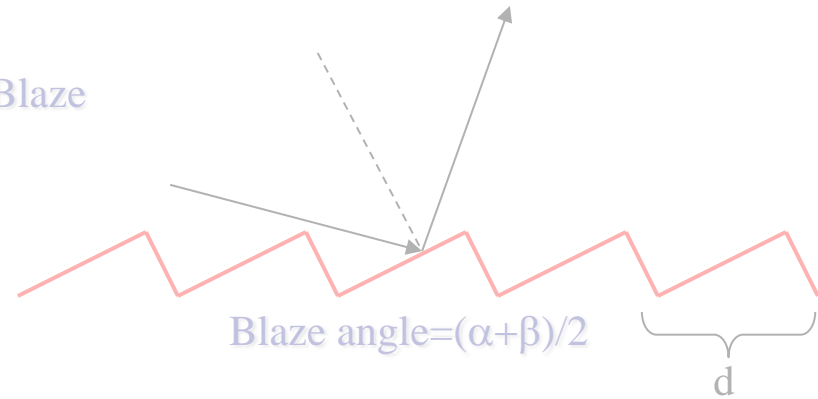
Efficiency as a function of the groove depth for two different photon energies



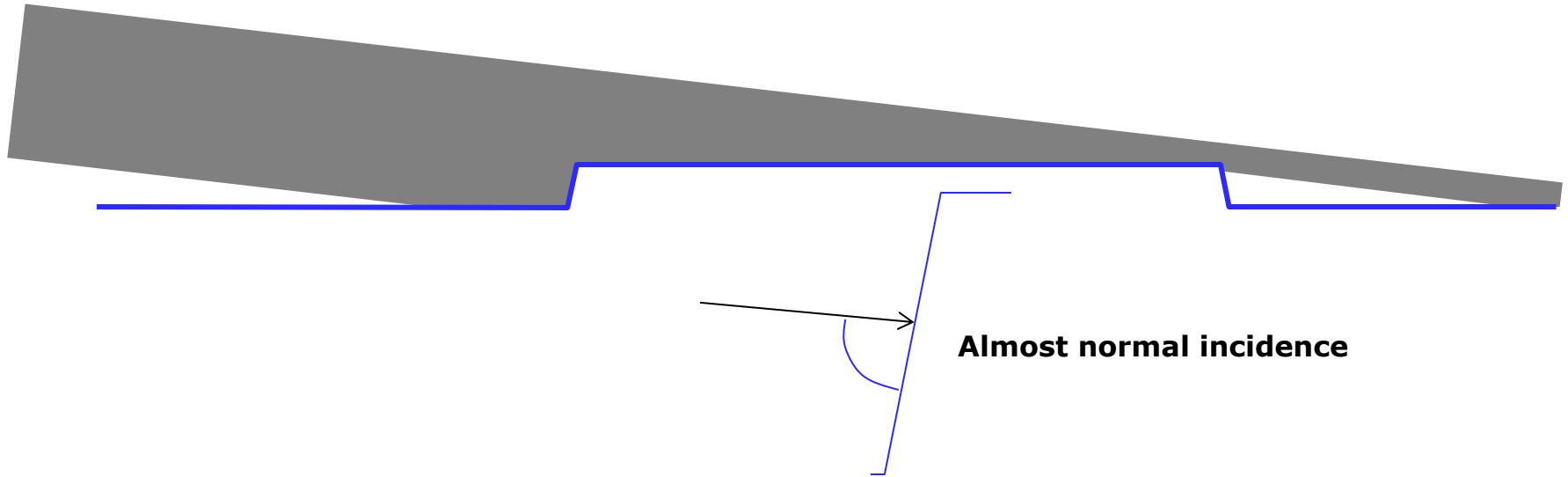
Laminar



Blaze

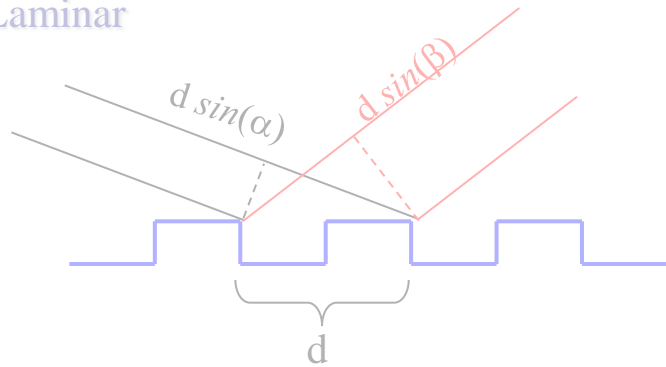


A lot of energy deposited on the grating facet



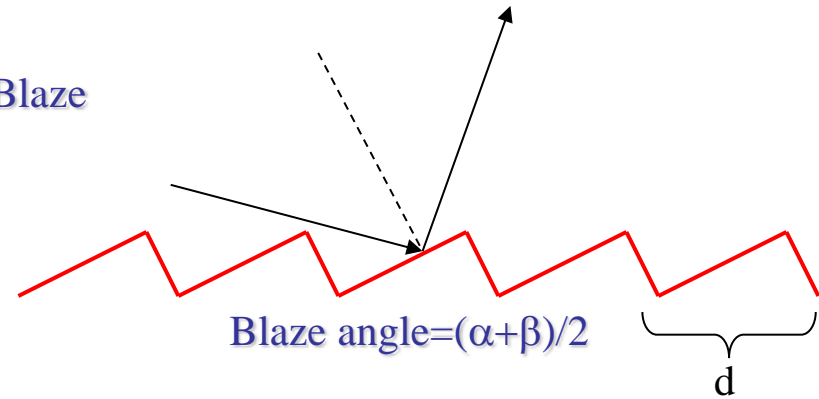
Grating Damage (blaze)

Lamellar

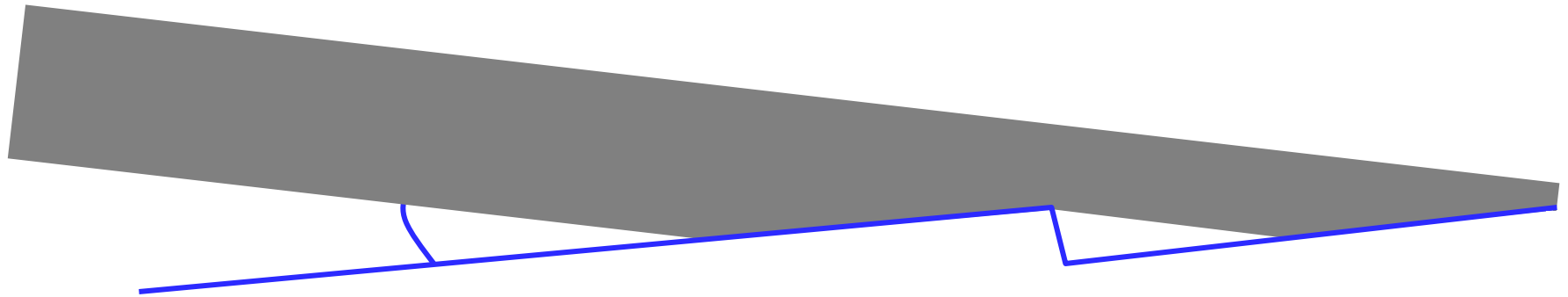


A lot of energy deposited on the grating facet

Blaze



Energy distributed on the grating facet



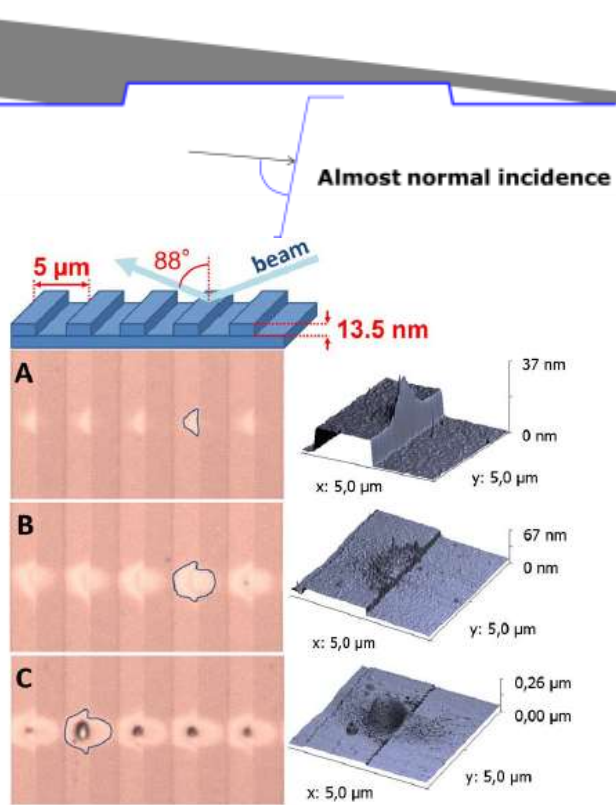
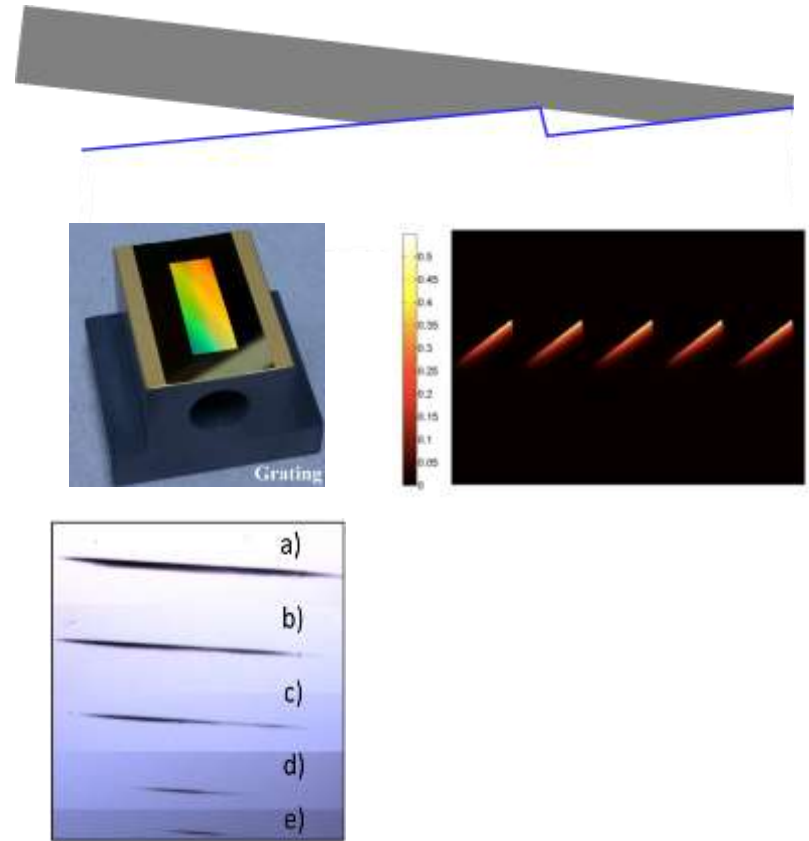


Fig. 1. (Color online) Top: schematic of the interaction of the experiment. Below: DIC microscopy (left) and AFM (right) measurements for three different fluences 356 (A), 806 (B), and 1115 mJ/cm^2 (C).

The reported damage threshold (0.5 eV/atm) is **3** times lower the observed on a flat mirror. 1.5eV/atom)

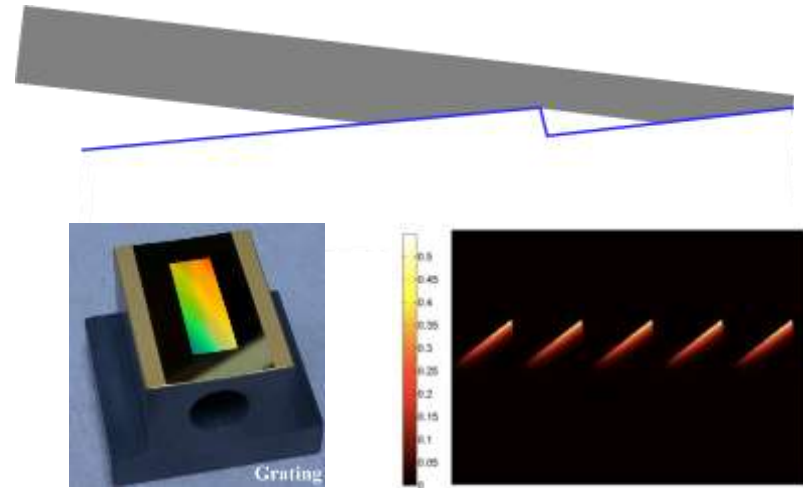
Optics Letter Vol. 37 (15) 2012, 3033



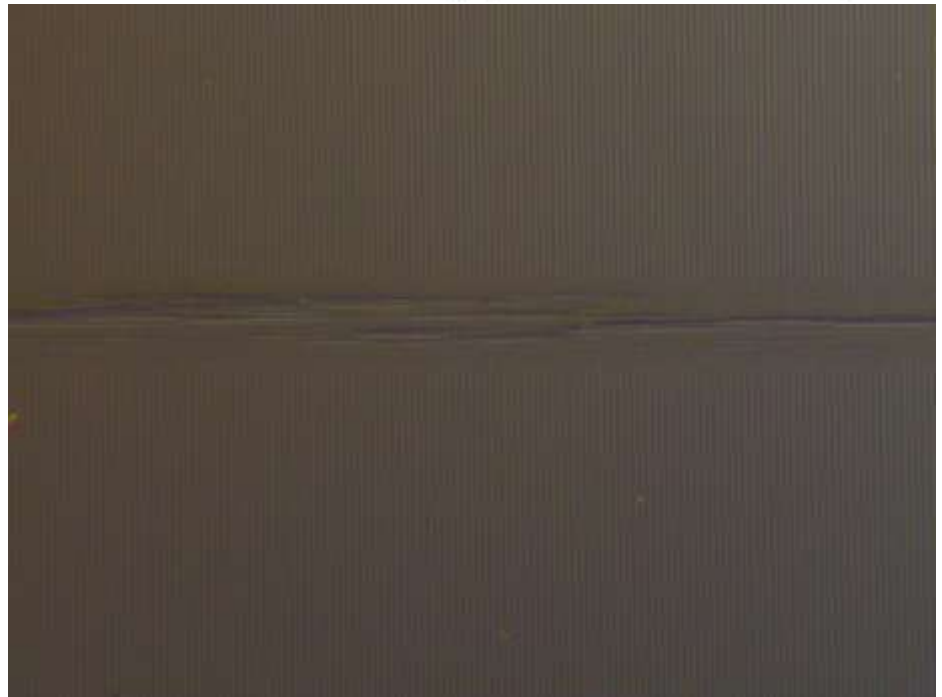
Single Shot damage $\sim 8\text{-}10$ eV/atom

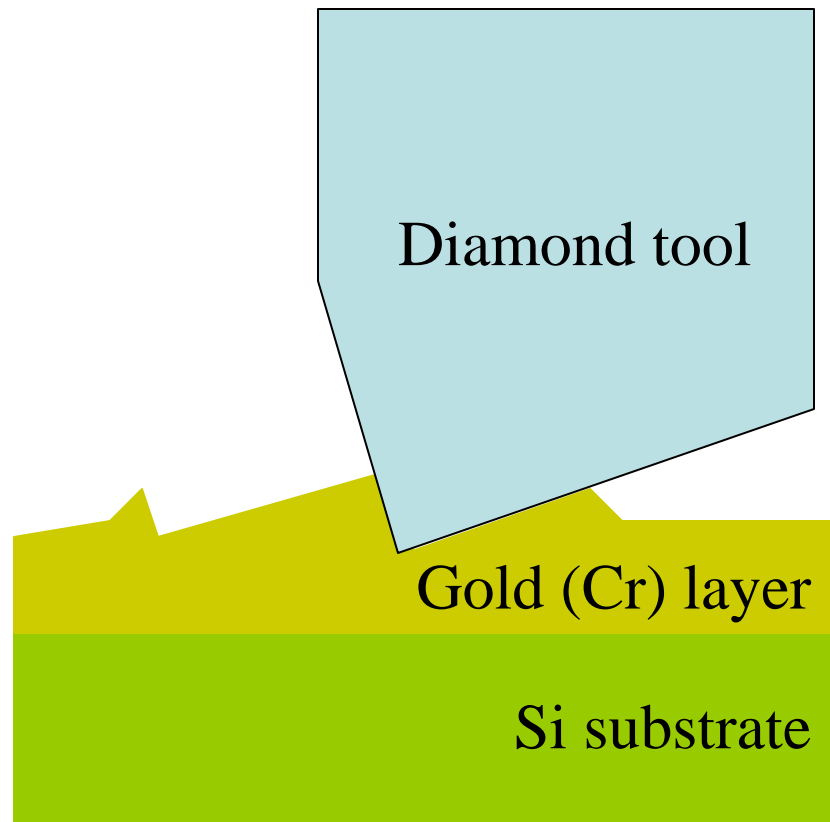
Multi shot damage ~ 720 meV/atom

Defined the maximum working energy for the Pt grating according to these tests

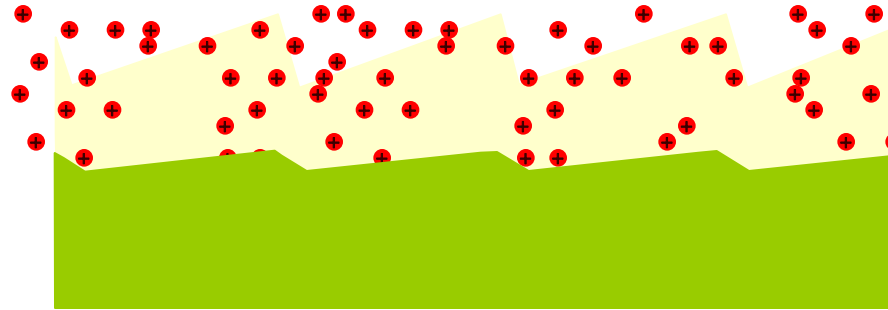


Result still under investigation but, it looks like that the grating has the same damage threshold of a mirror with an angle of incidence identical to the angle of the grating facet with respect the radiation. It means, the blaze angle shall be really small!





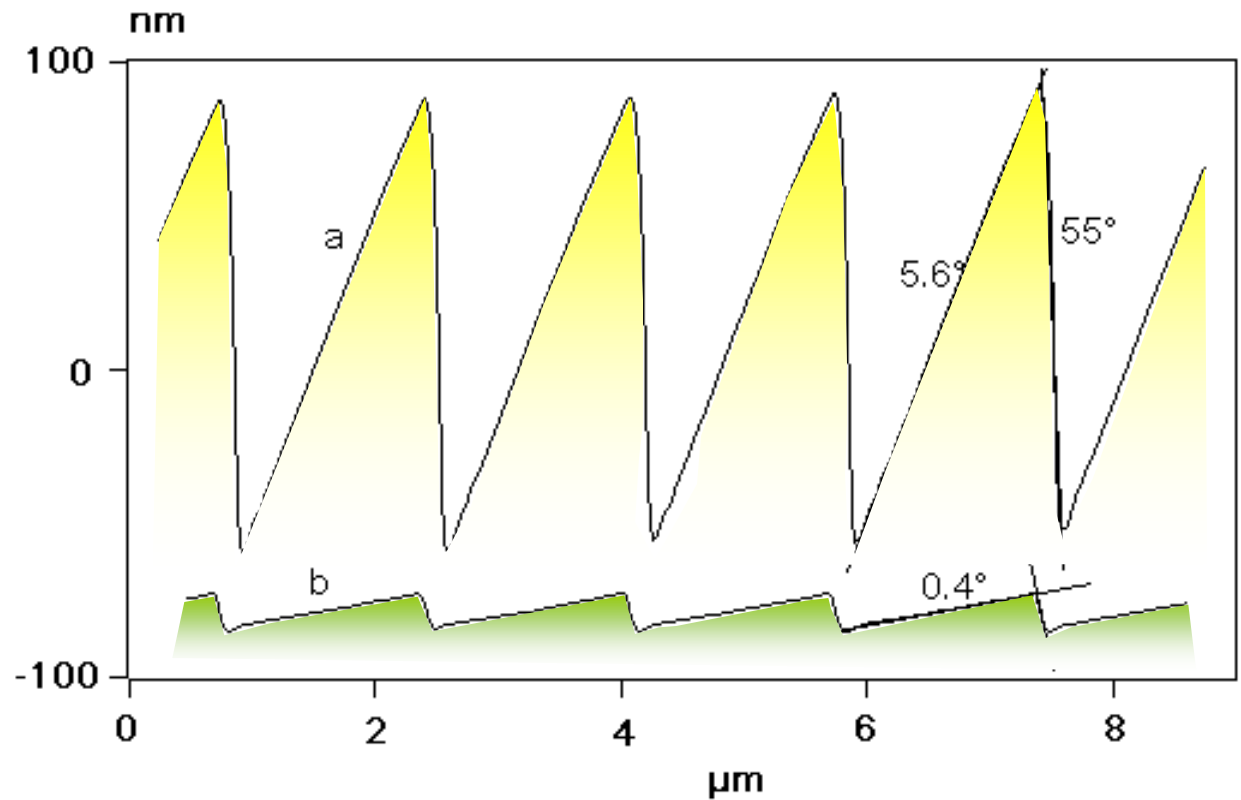
- Thermal evaporation of Gold on the Si substrate (plus Cr binding layer)
- Grooves formed by plastic deformation of the ruling layer



- Thermal evaporation of Gold on the Si substrate (plus Cr binding layer)
- Grooves formed by plastic deformation of the ruling layer
- Realization of low micro-roughness blaze grating with $20 < g < 5000$ l/mm and down to 1.5° of blaze angle
- Ar^+ ion etching (200 mm diameter collimated beam)
- Ar^+ ion etching rate on gold much larger than on Silicon
- An angle reduction of a factor 3 (even higher if $\text{Ar}^+ + \text{O}^+$ is used) can be achieved by this technique
- Roughness and anti blaze angle are also reduced.

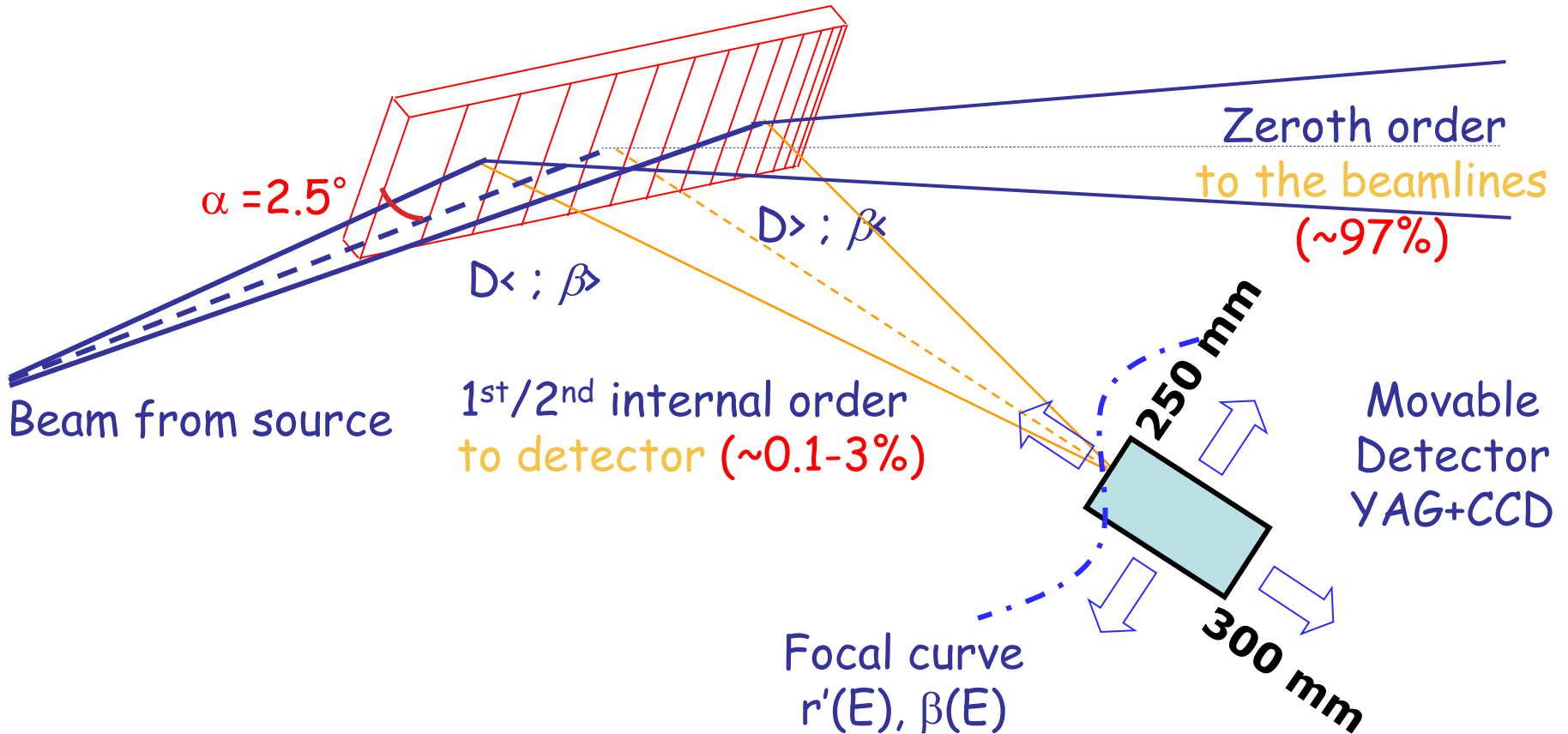
Shallow Blaze Angle grating

*Plane substrate 600 l/mm gold coated
80X5 mm useful area, blaze angle 0.4°*

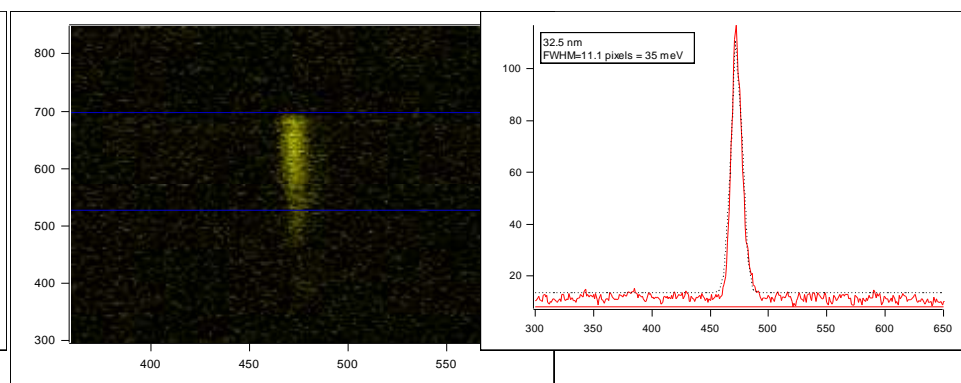
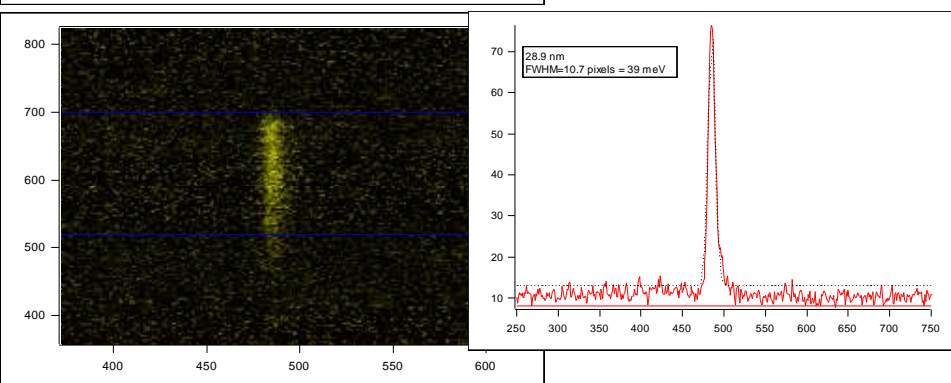
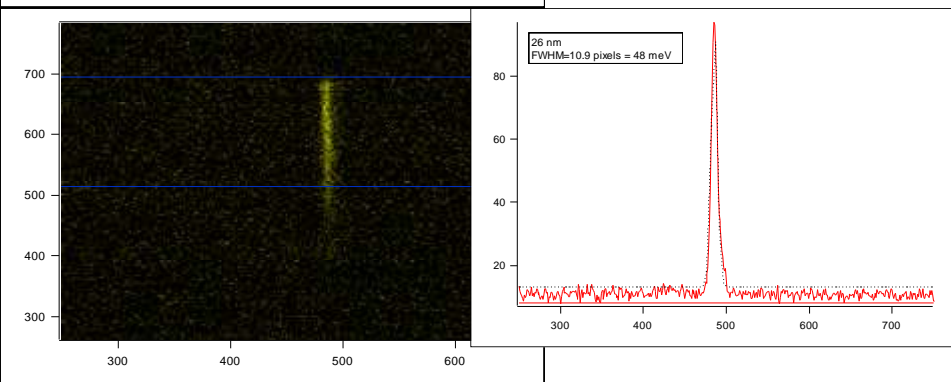
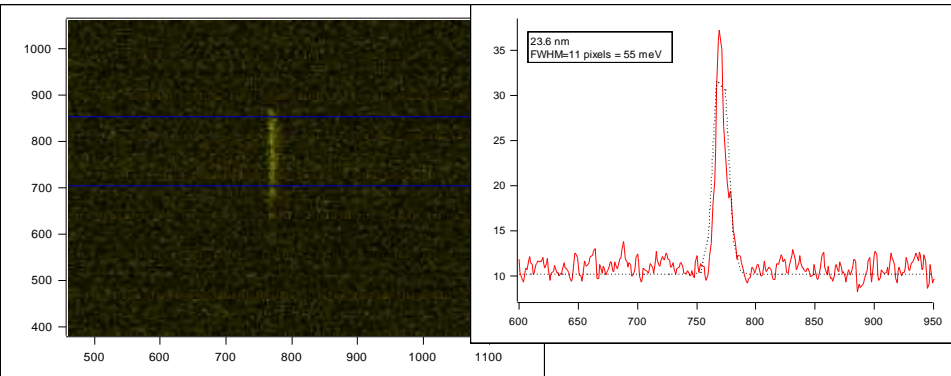


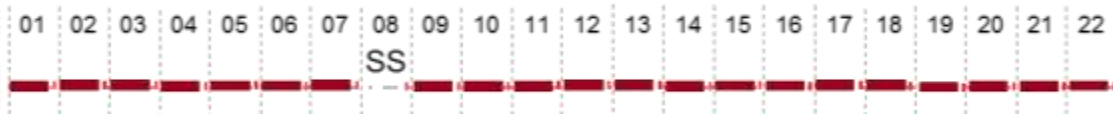
Groove density expanded in Taylor series

$$D(y) = D_0 + D_1 y + D_2 y^2 + \dots$$

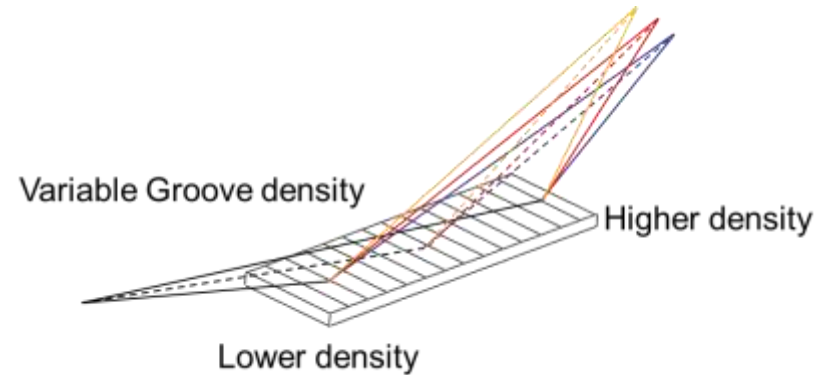
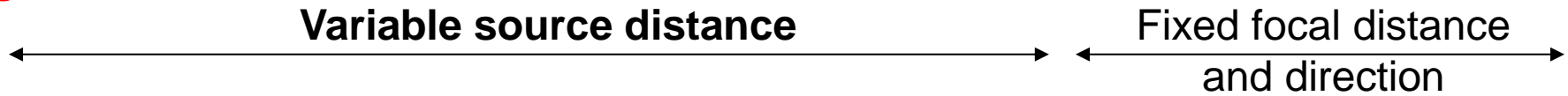
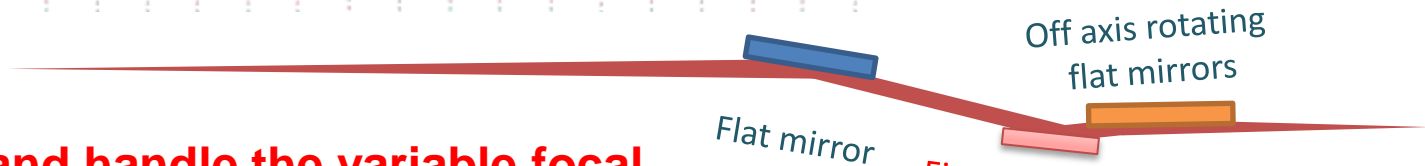


Measured HGHG Seeded FEL beam

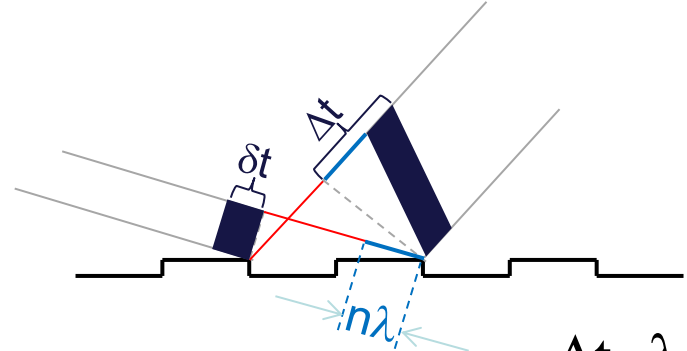
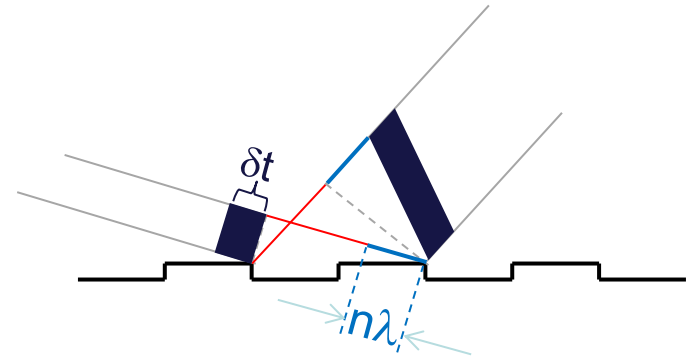
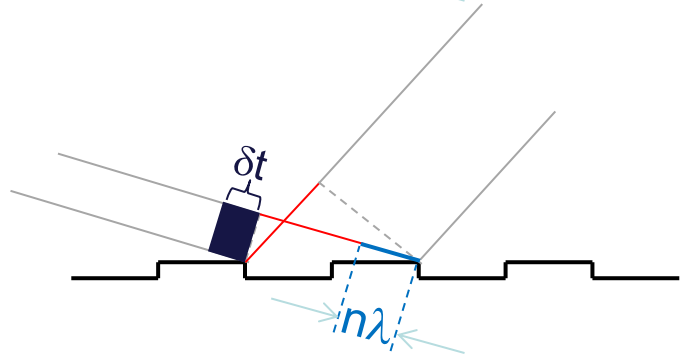
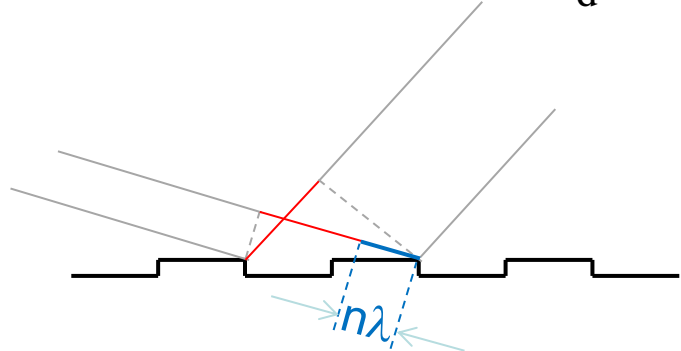
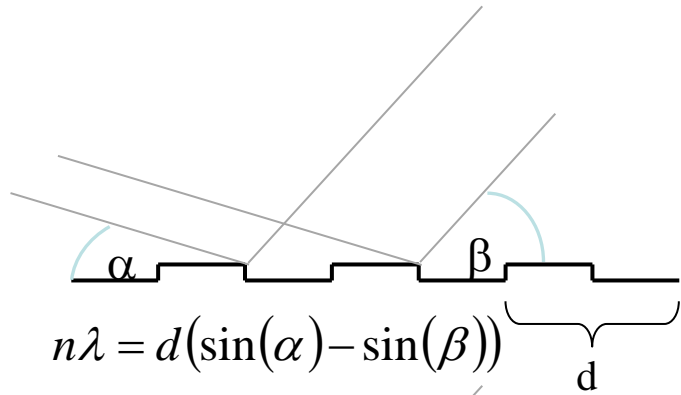




To survive and handle the variable focal distance (without adaptive optics involved) the grating must be a VLS of more than 500 mm in length



Source position calculated by J. Krzywinski



$$\Delta t = \lambda/c$$

$$\Delta t = \sqrt{\left(\frac{N\lambda}{c}\right)^2 + \delta t^2}$$

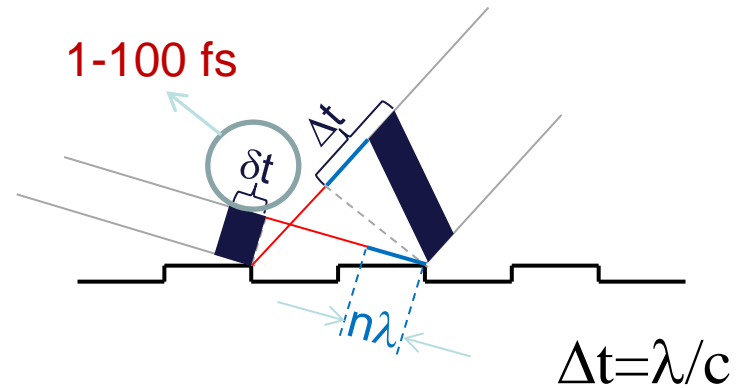
Need of long substrates to distribute the power:

1200 l/mm grating, 500 mm, 500 eV

~5,000 fsec

10 l/mm grating, 500 mm, 500 eV

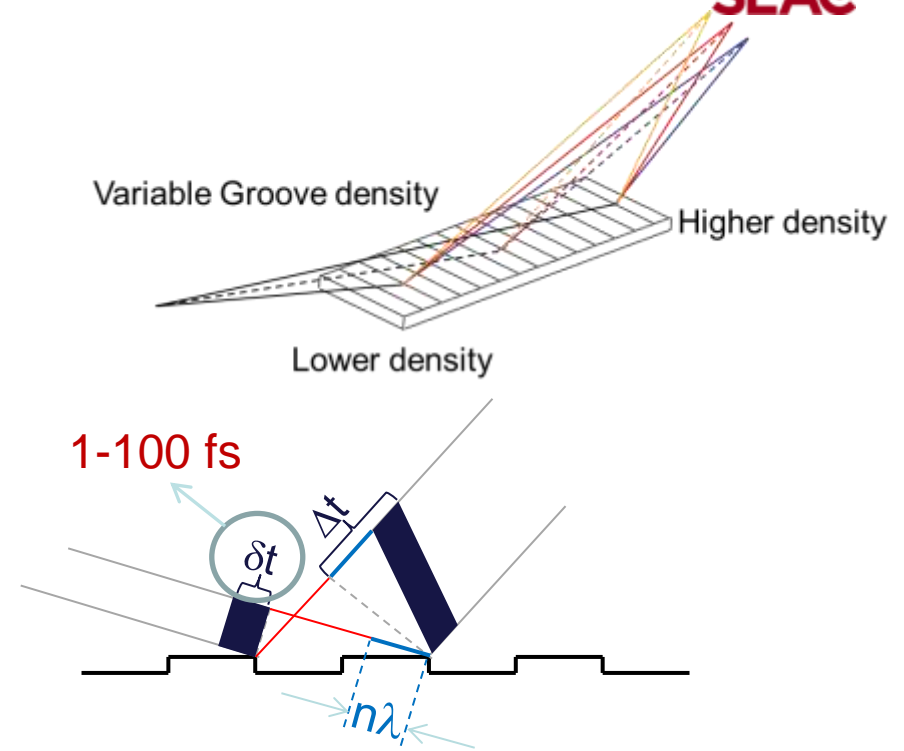
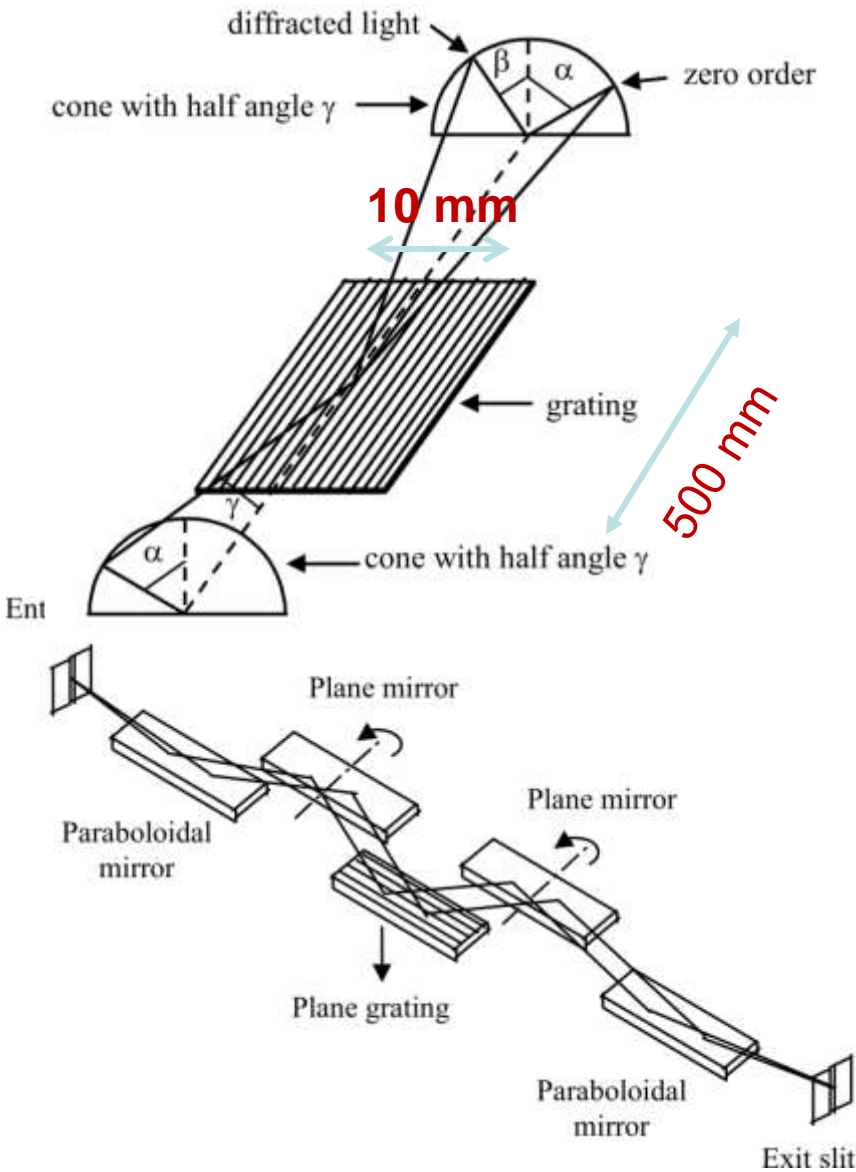
~40 fsec



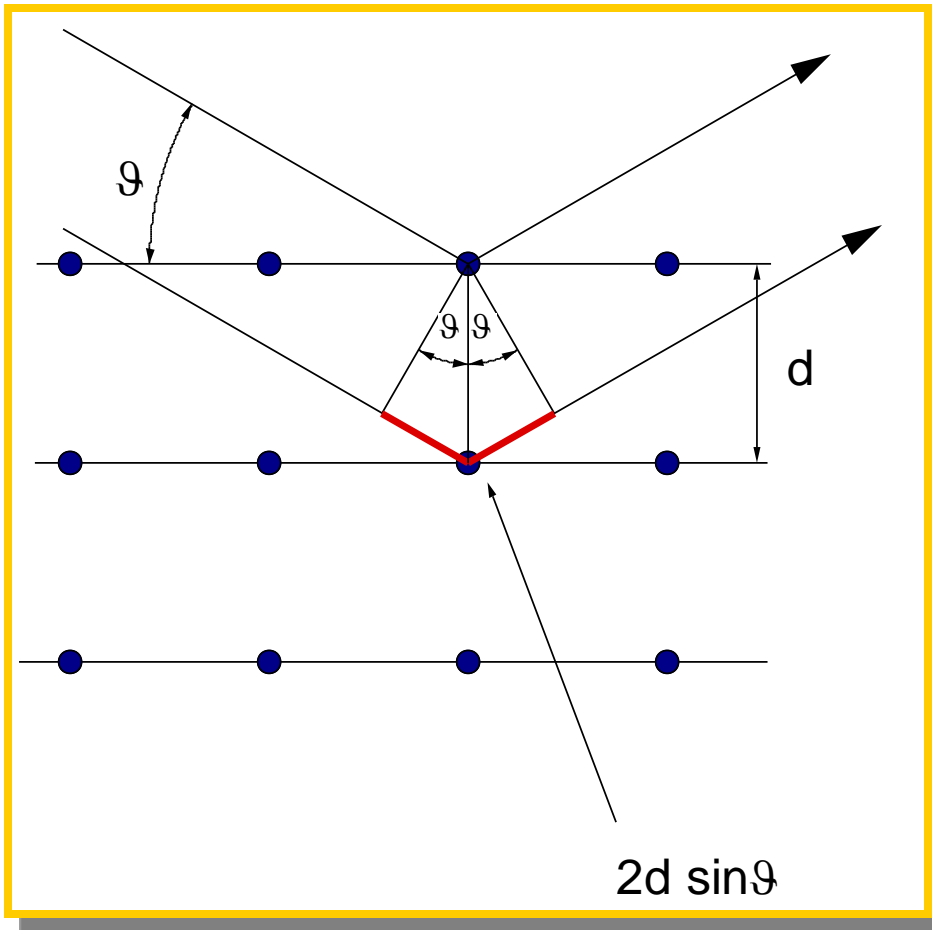
$$\Delta t = \sqrt{\left(\frac{N\lambda}{c}\right)^2 + \delta t^2}$$

Conical Diffraction

SLAC



$$\Delta t = \sqrt{\left(\frac{N\lambda}{c}\right)^2 + \delta t^2}$$



Radiation of wavelength λ is reflected by the lattice plane. The outgoing waves interfere. The interference is constructive only if the difference of optical path is a multiple of λ :

$$2d \sin \theta = n \lambda$$

Limits:

$$\sin \theta = 1 \Rightarrow \lambda_{\max}$$

$$\lambda_{\max} = 2d \quad @ \theta = 90^\circ$$

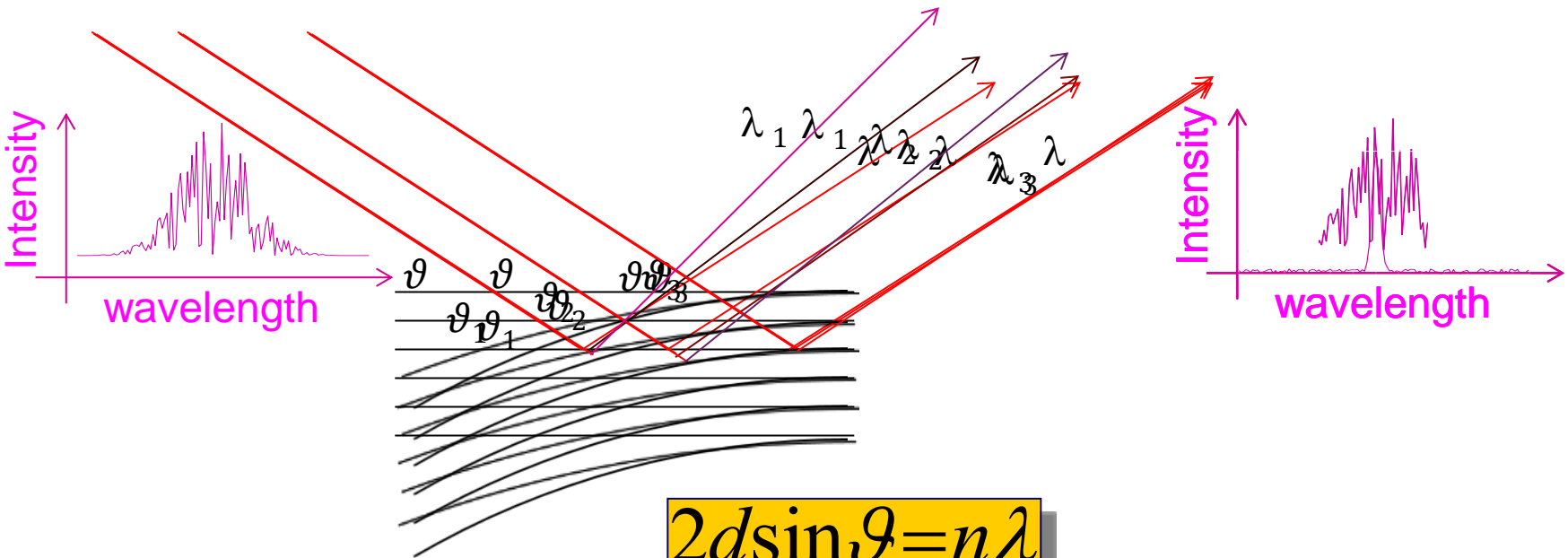
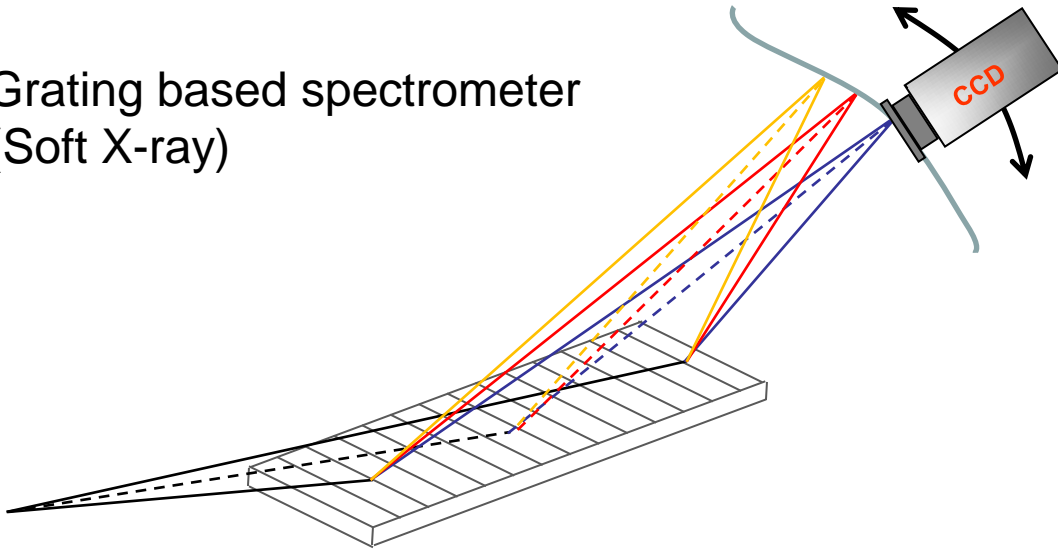
EXAMPLES: Si (111) $d = 3.13 \text{ \AA} \rightarrow E_{\min} \approx 2 \text{ keV}$

InSb (111) $d = 3.74 \text{ \AA} \rightarrow E_{\min} \approx 1.7 \text{ keV}$

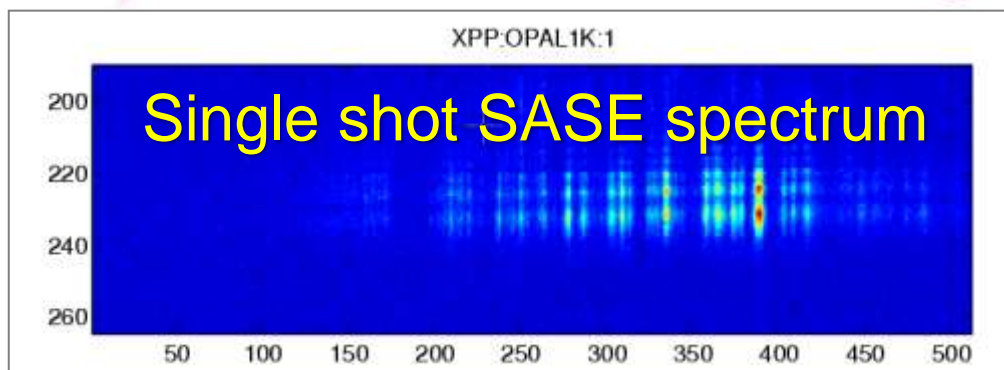
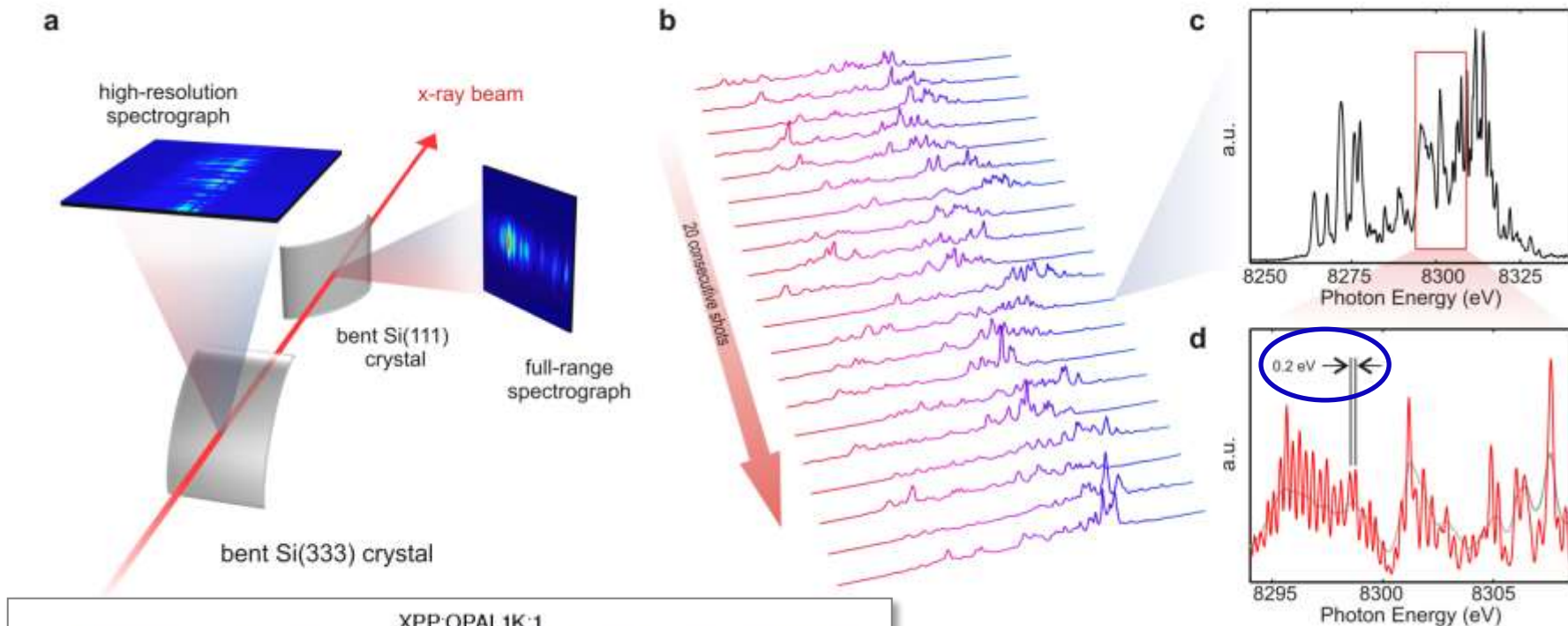
Si (311) $d = 1.64 \text{ \AA} \rightarrow E_{\min} \approx 3.8 \text{ keV}$

Beryl (10 $\bar{1}$ 0) $d = 7.98 \text{ \AA} \rightarrow E_{\min} \approx 0.8 \text{ keV}$

Grating based spectrometer
(Soft X-ray)

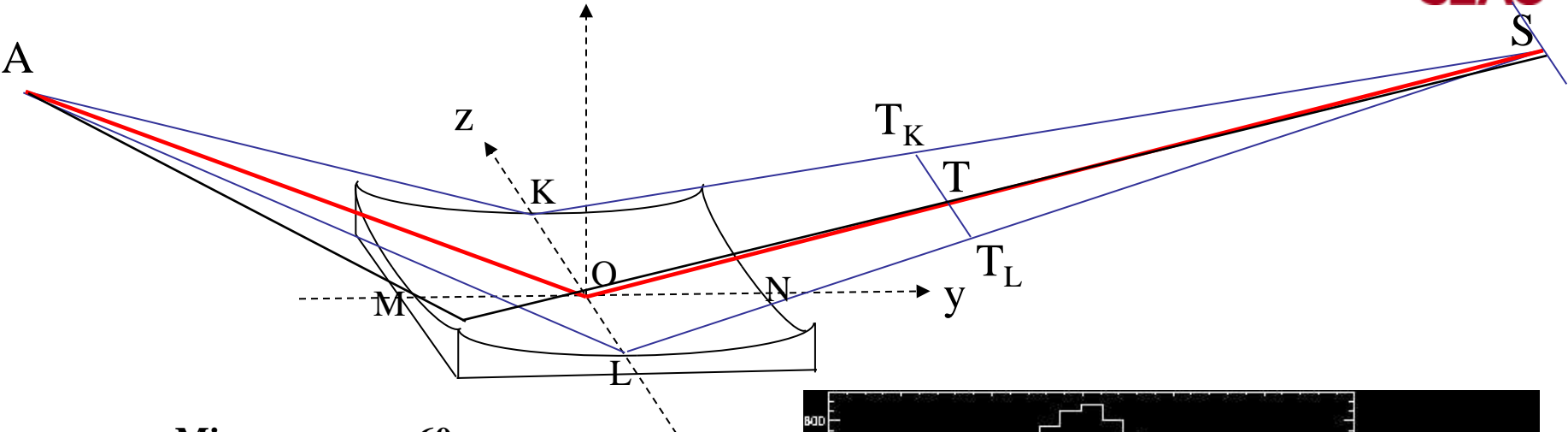


Measurement of the LCLS HXR SASE spectrum

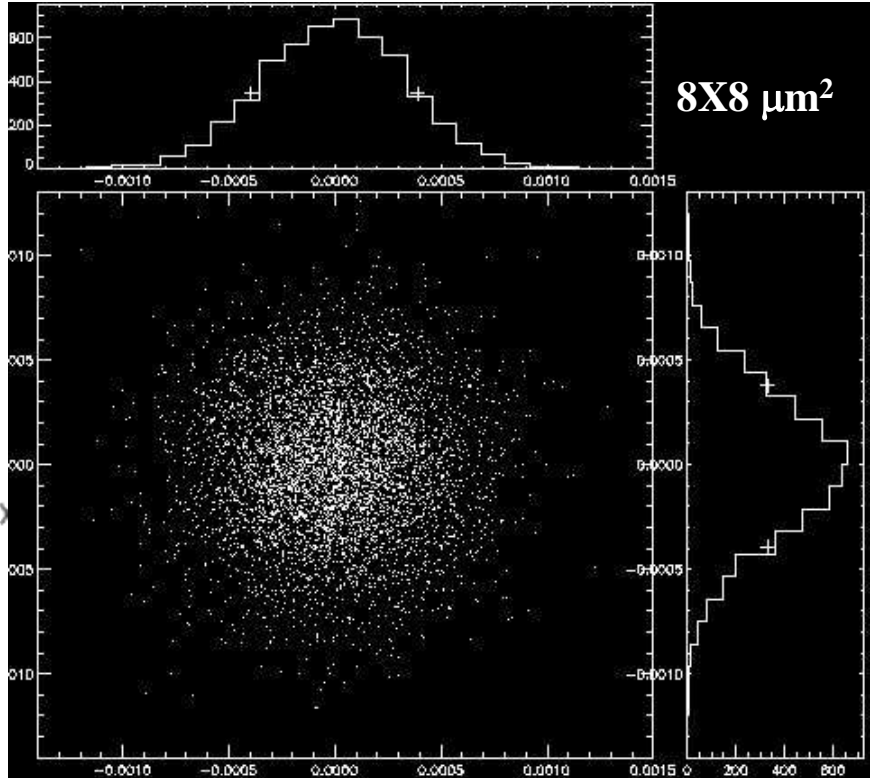
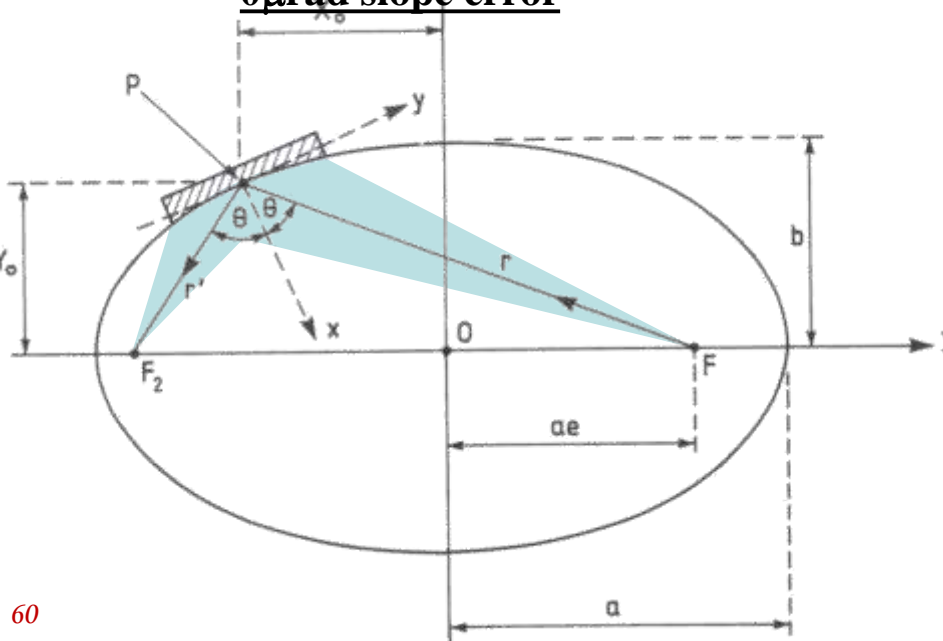


SASE Spike width
 ≈ 0.2 eV at 8.3 keV
(0.002%)

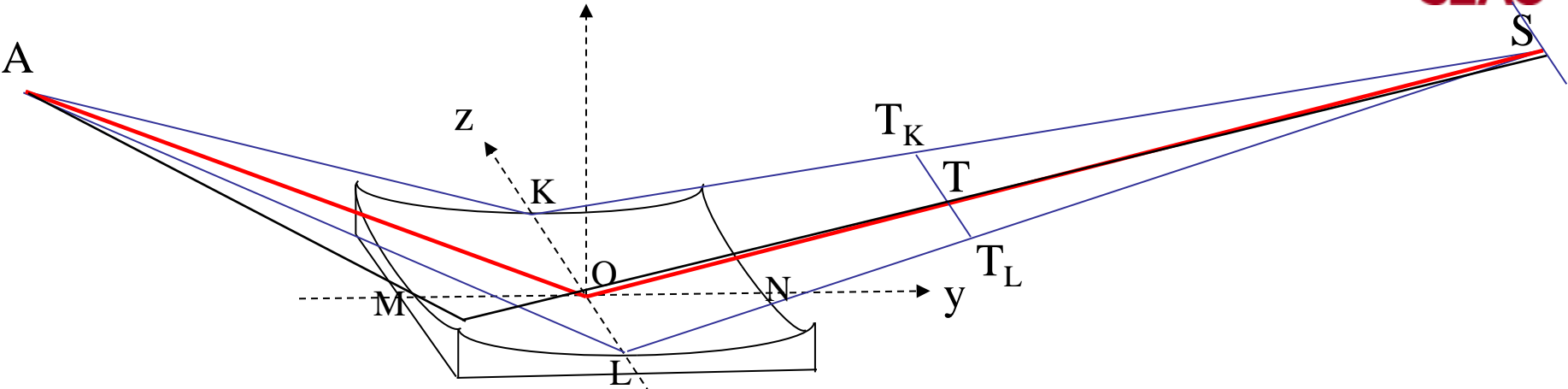
2D focusing – 1 mirror option - Ellipsoid



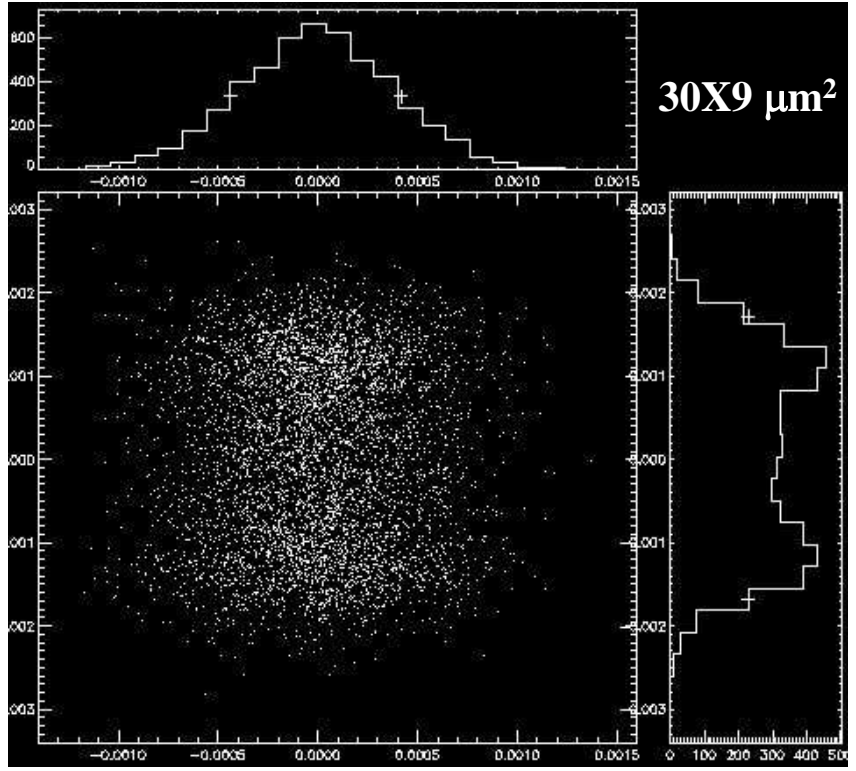
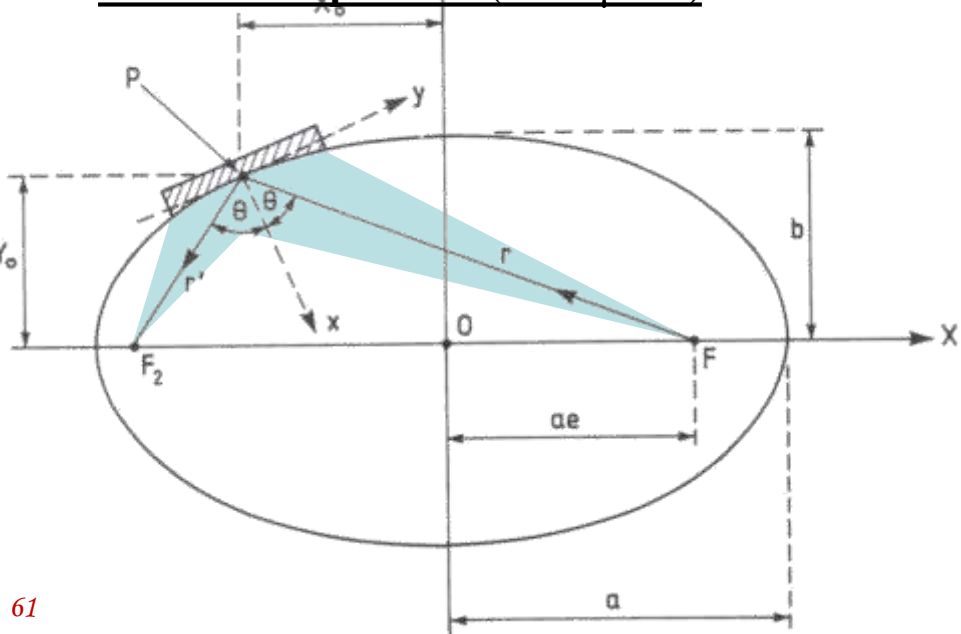
Mirror-source 60 m
 Mirror-image 1 m
0 μrad slope error



2D focusing – 1 mirror option - Ellipsoid



Mirror-source 60 m
 Mirror-image 1 m
Standard slope error (15x5 μ rad)



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Formation of Optical Images by X-Rays

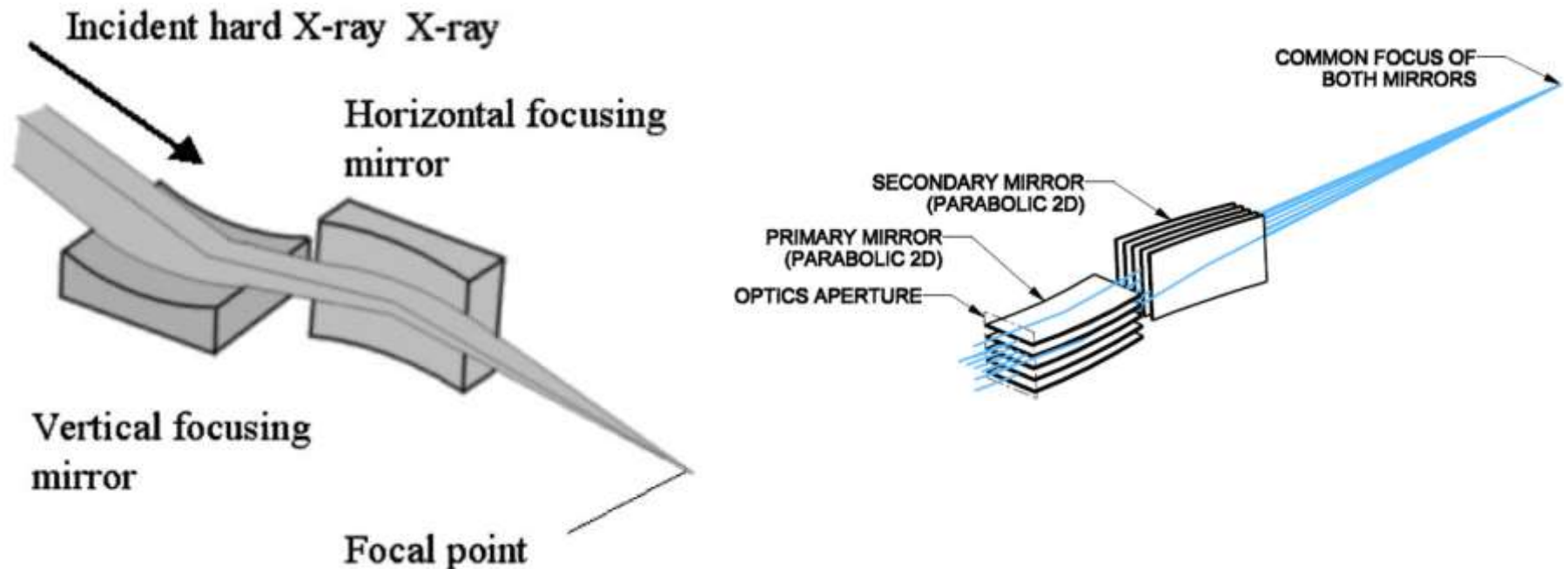
PAUL KIRKPATRICK AND A. V. BAEZ
Stanford University, Stanford, California
(Received March 12, 1948)

Several conceivable methods for the formation of optical images by x-rays are considered, and a method employing concave mirrors is adopted as the most promising. A concave spherical mirror receiving radiation at grazing incidence (a necessary arrangement with x-rays) images a point into a line in accordance with a focal length $f = R/i/2$ where R is the radius of curvature and i the grazing angle. The image is subject to an aberration such that a ray

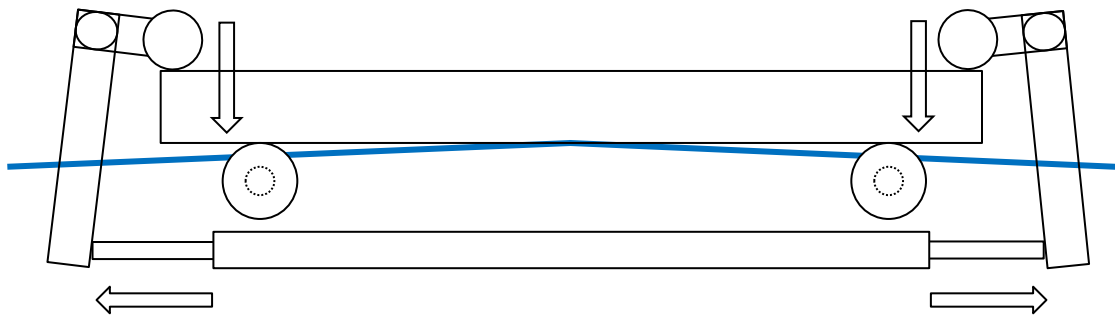
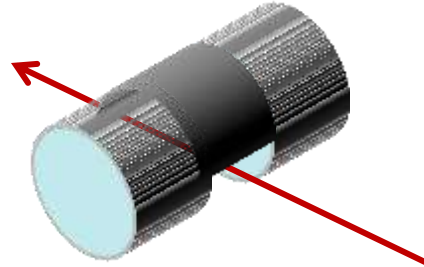
point of central rays by a distance given approximately by $S = 1.5Mr^2/R$, where M is the magnification of the image and r is the radius of the mirror face. The theoretically possible resolving power is such as to resolve point objects separated by about 70λ , a limit which is independent of the wave-length used. Point images of points and therefore extended images of extended objects may be produced by causing the radiation to reflect from two

This optical configuration is generally known as KB optics.

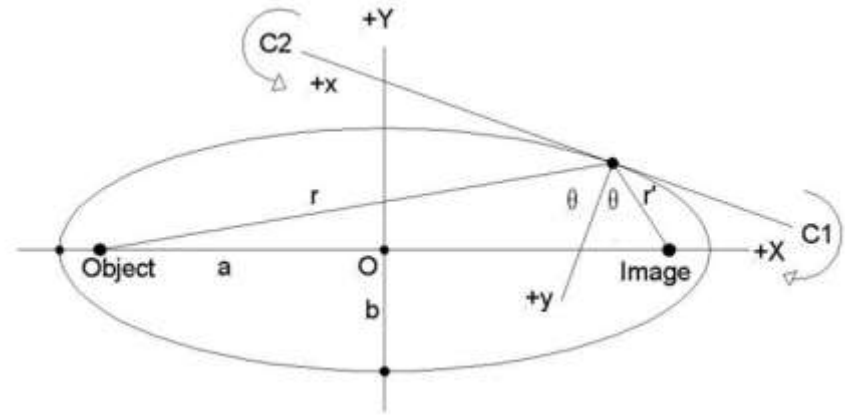
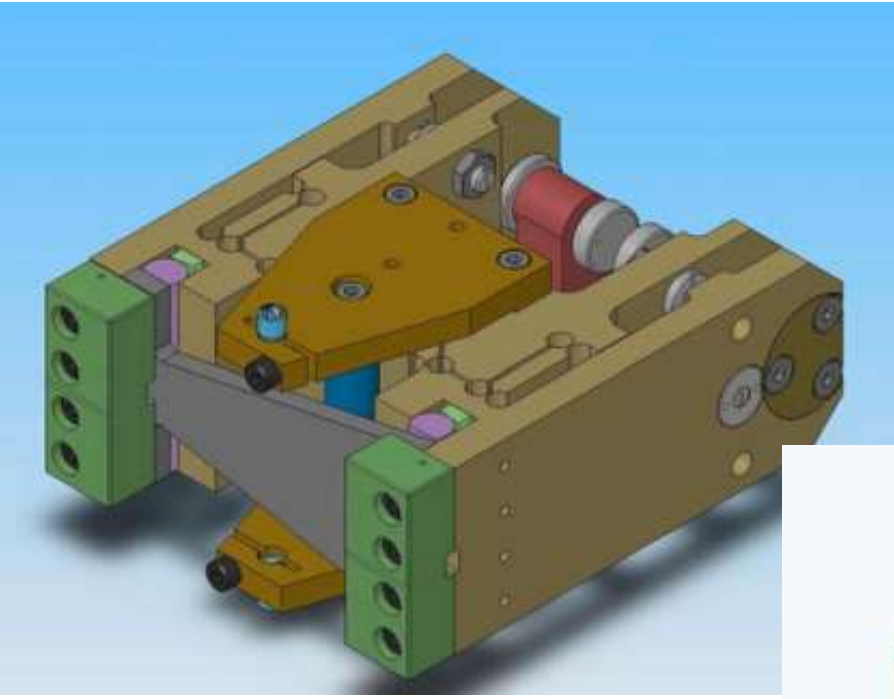
Could be made by 2 spherical mirrors, two elliptical mirror or other shapes, static or adaptive.



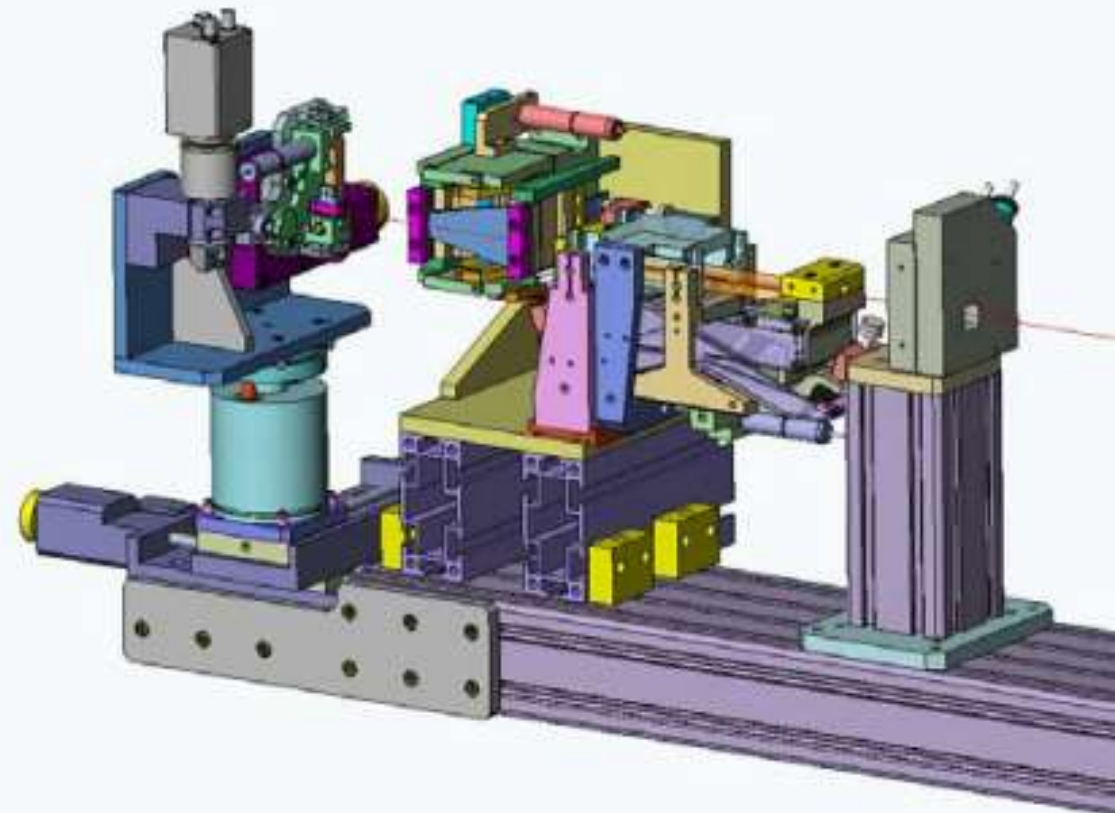
4 cylinders bender (SESO)

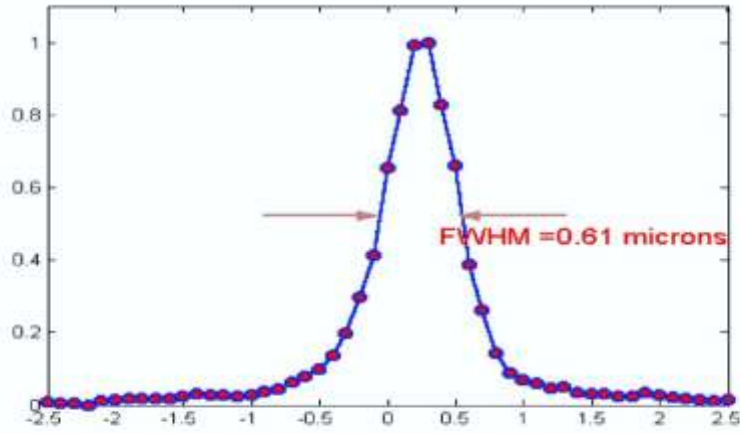


ESRF Trapezoidal Bender

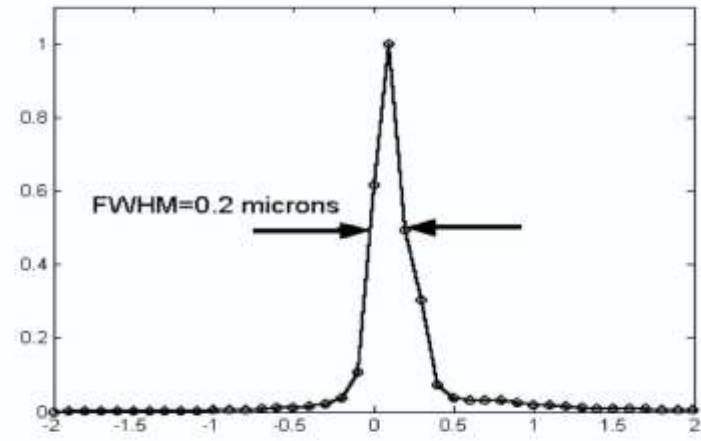


Need to control at least 3 parameter to approximate an ellipse starting from a flat

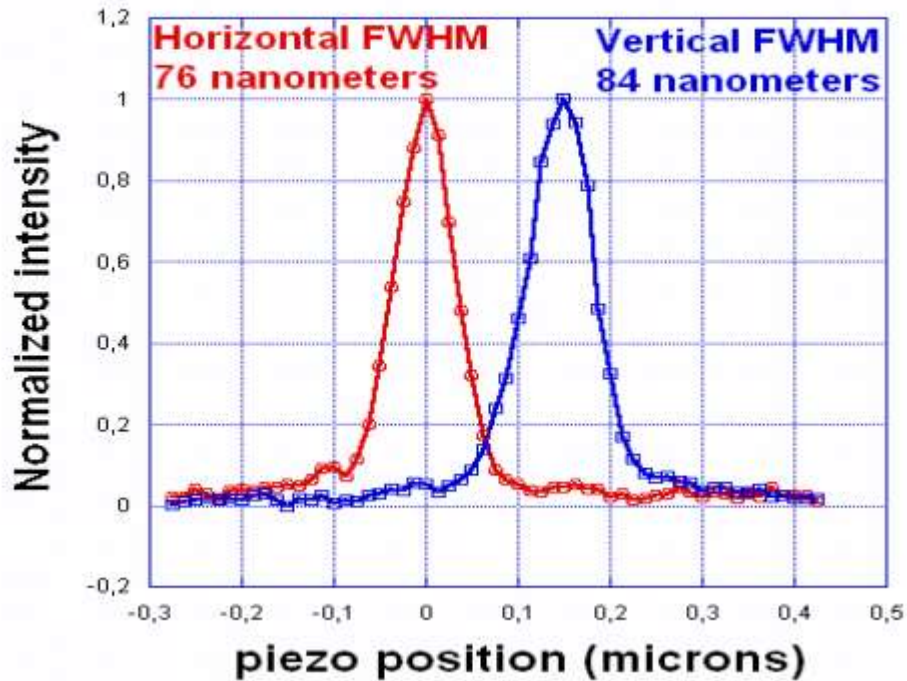




ID 22 Spot size measurement

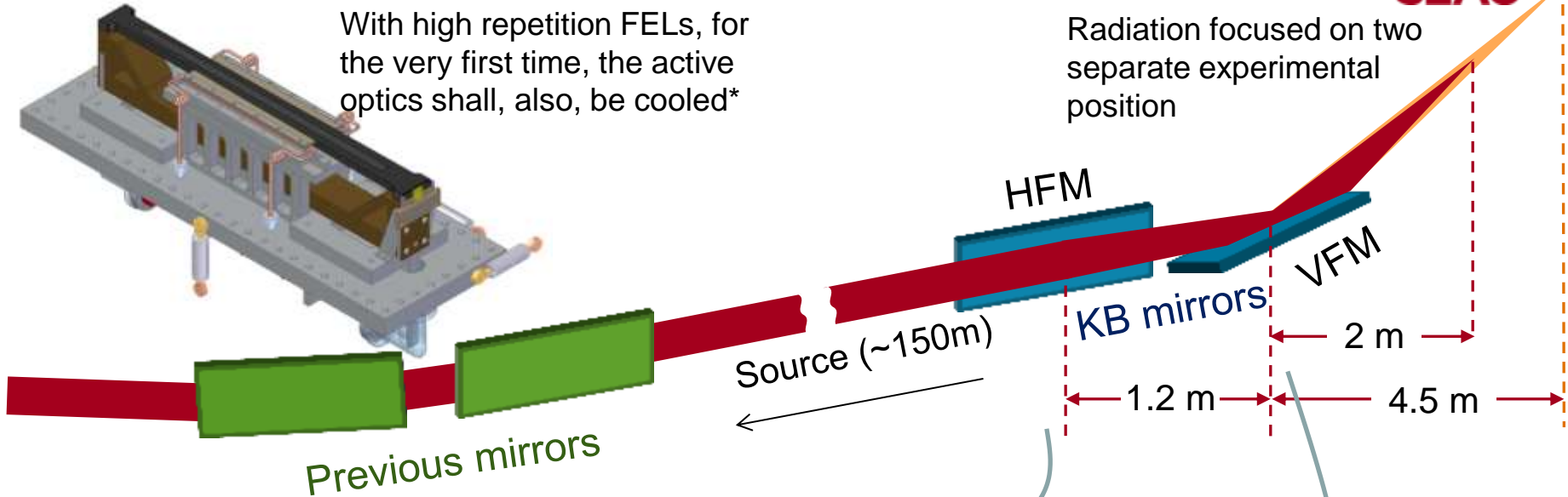


Horizontal scan



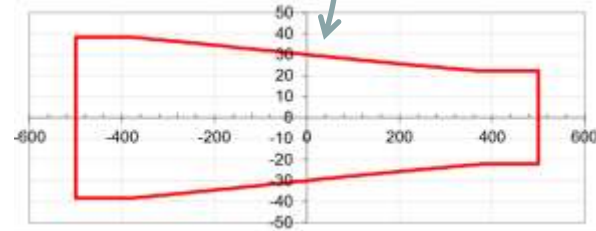
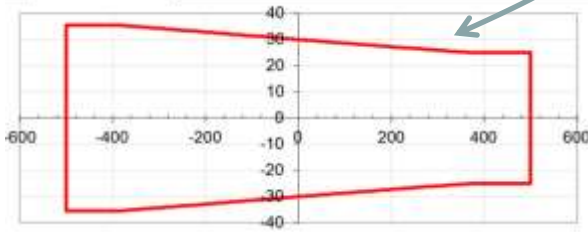
KB system for high power FELs

SLAC



With high repetition FELs, for the very first time, the active optics shall, also, be cooled*

Radiation focused on two separate experimental position



Virtually no residual rms slope errors when focusing in the 1st chamber

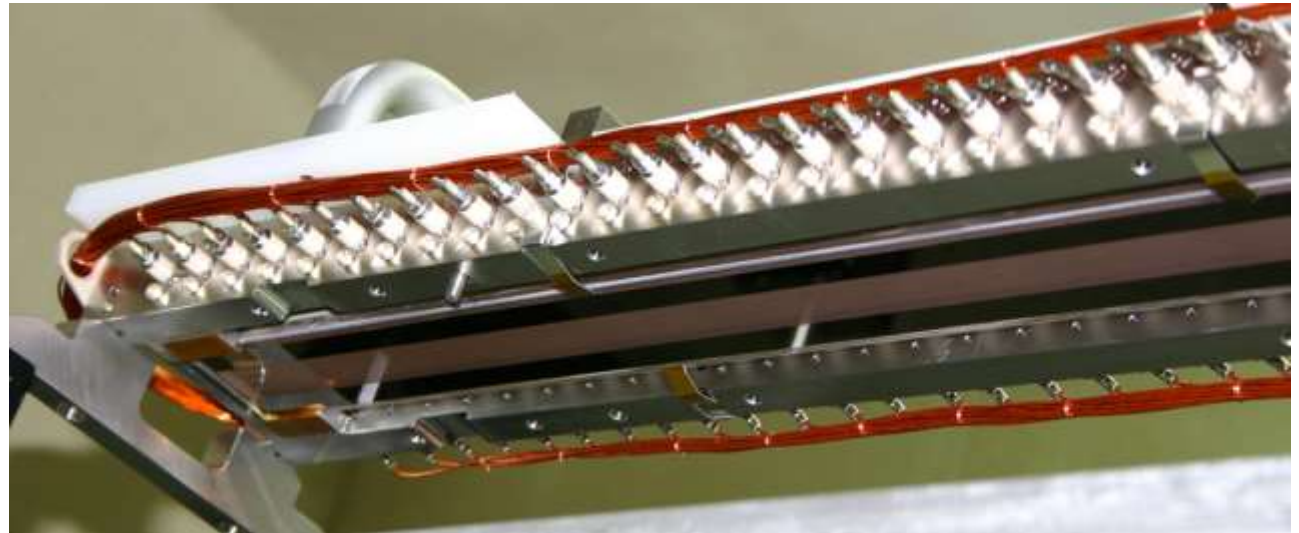
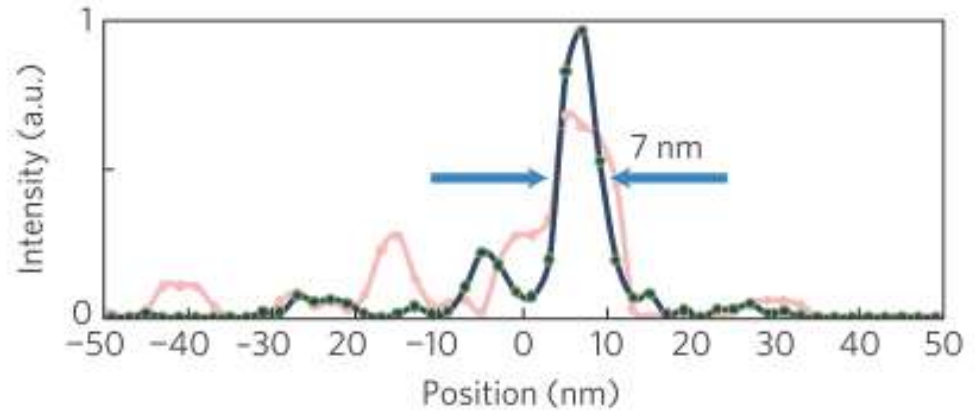
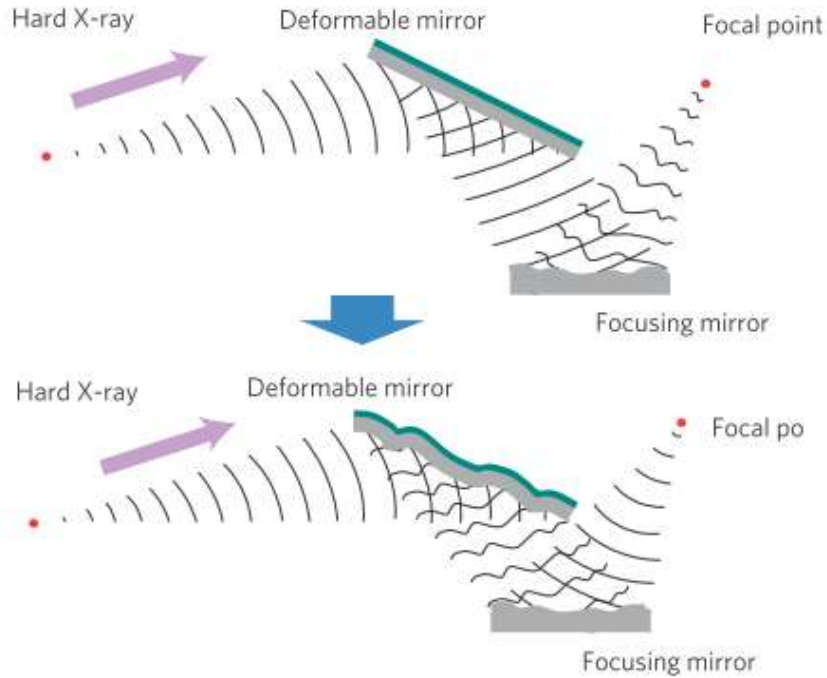
→ **~0.9X1.2 μm² spot 1st chamber**

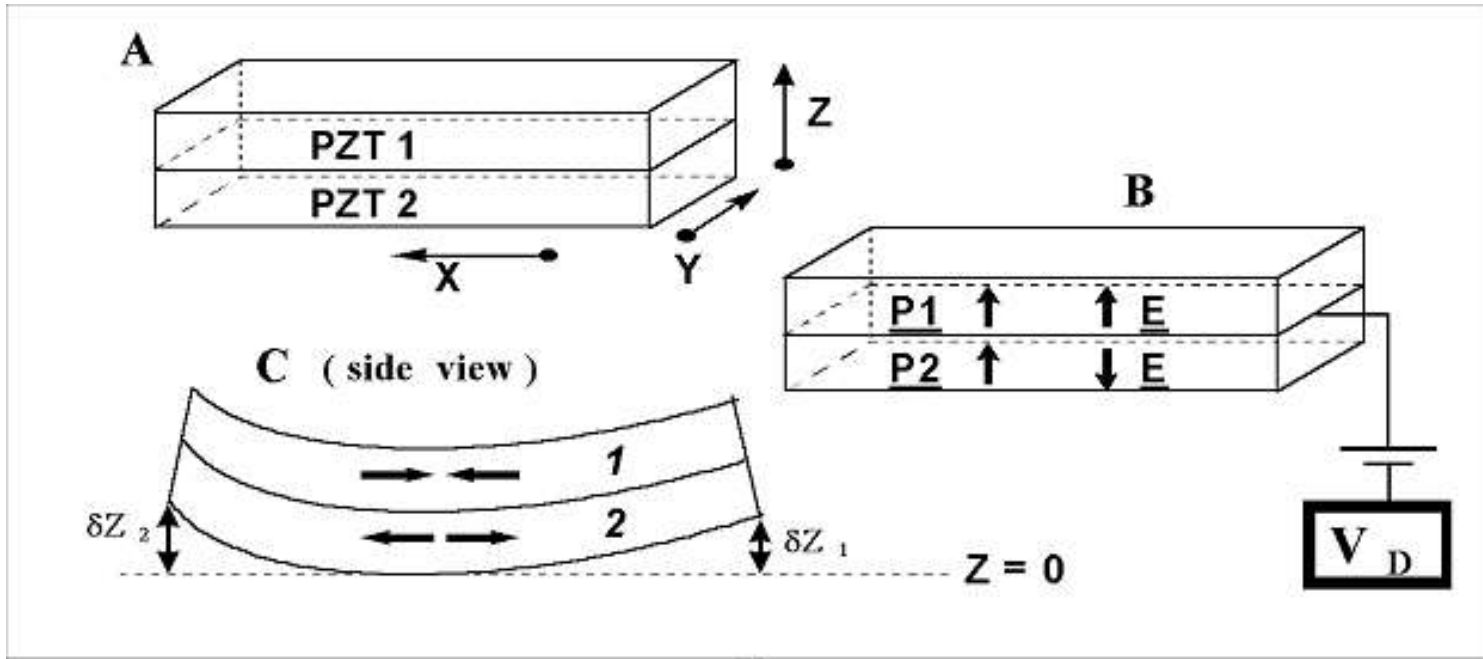
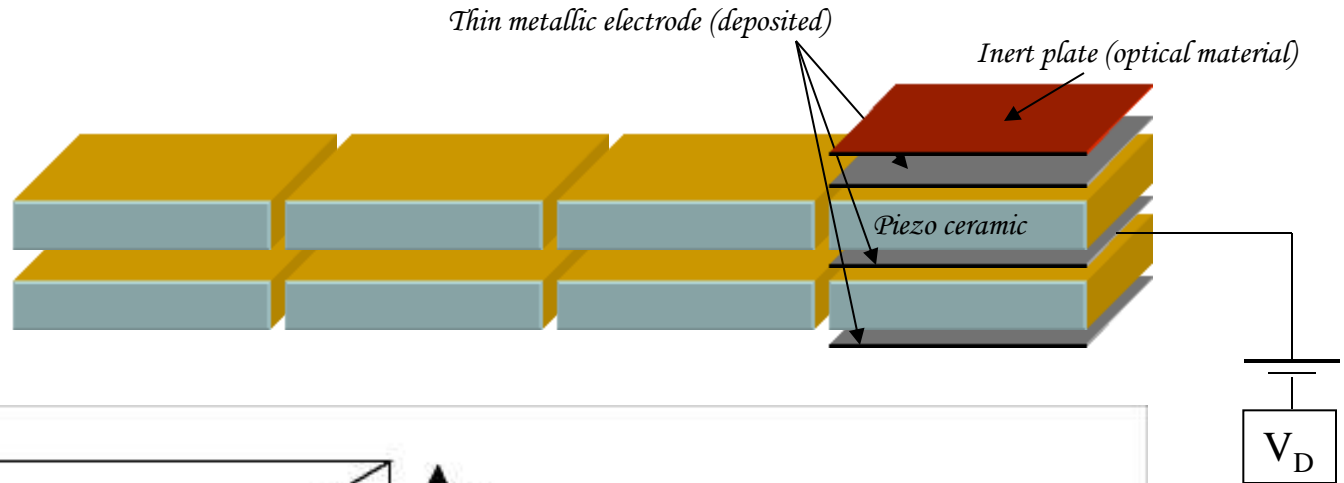
Residual rms slope errors when focusing in the second chamber

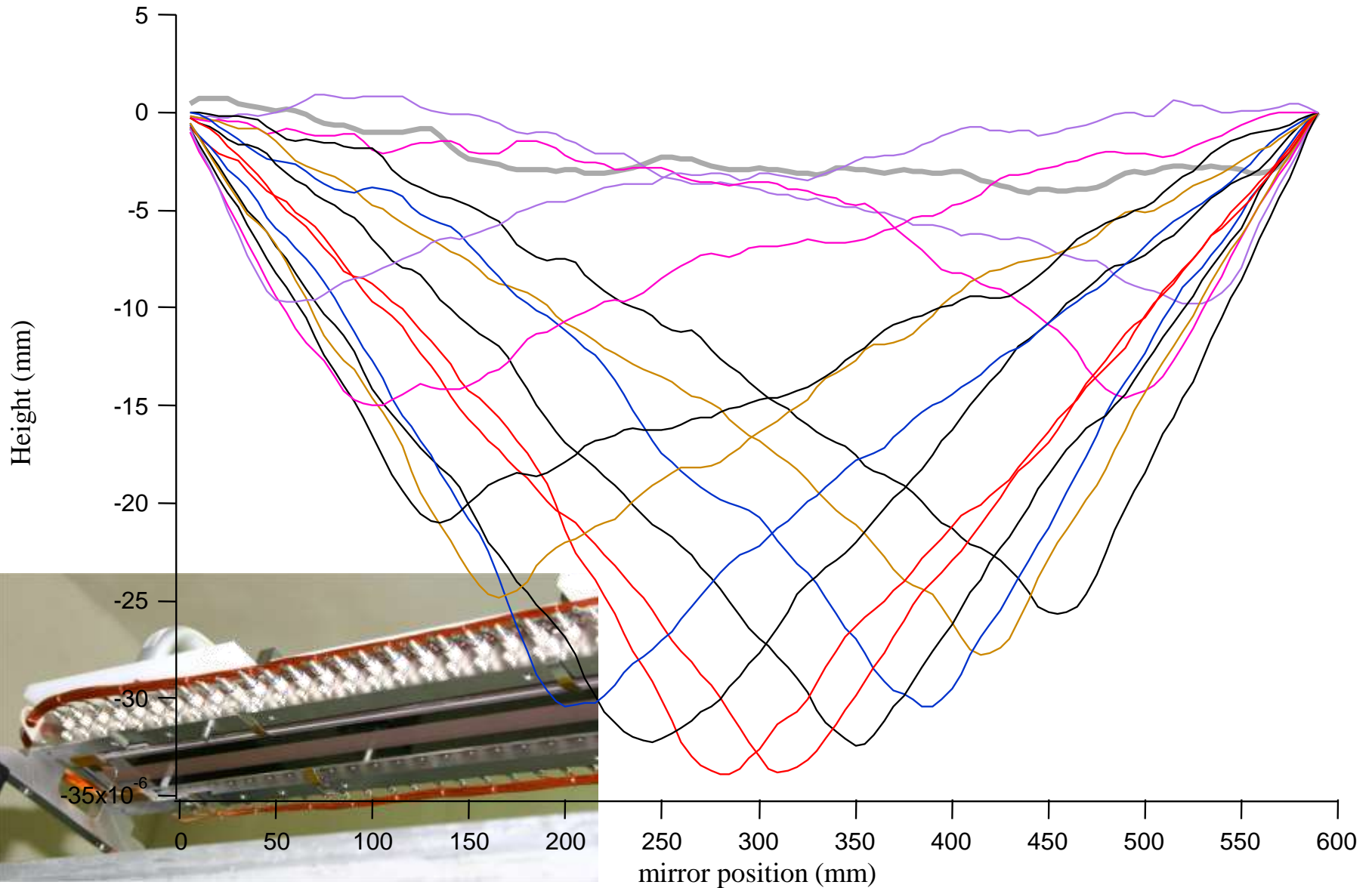
HFM: 0.13 μrad
VFM: 0.42 μrad

→ **~3X5 μm² spot 2nd chamber**

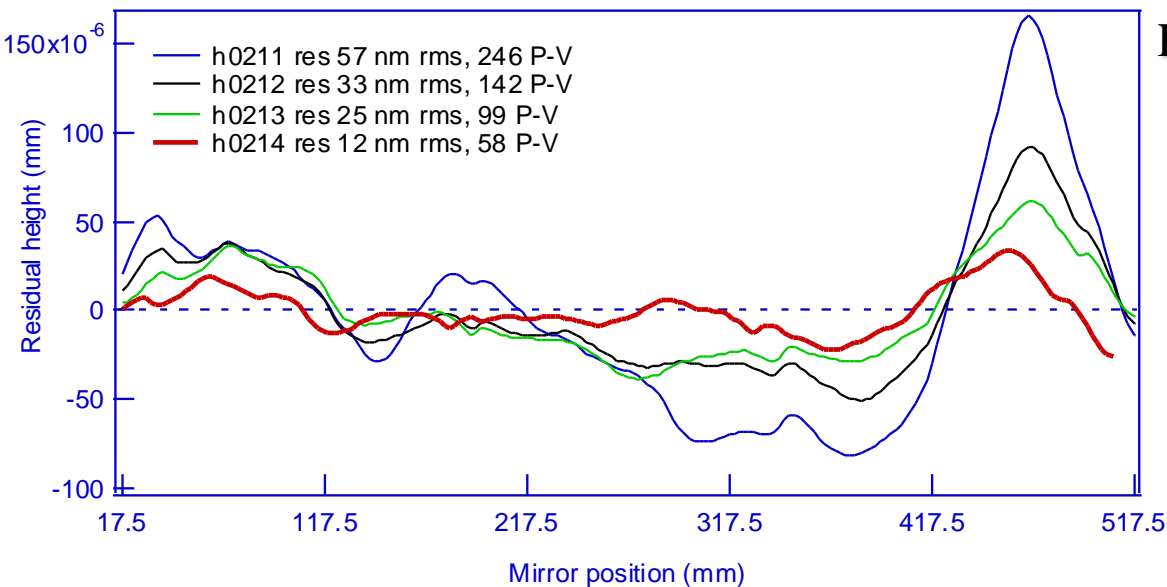
Wavefront distortion compensation



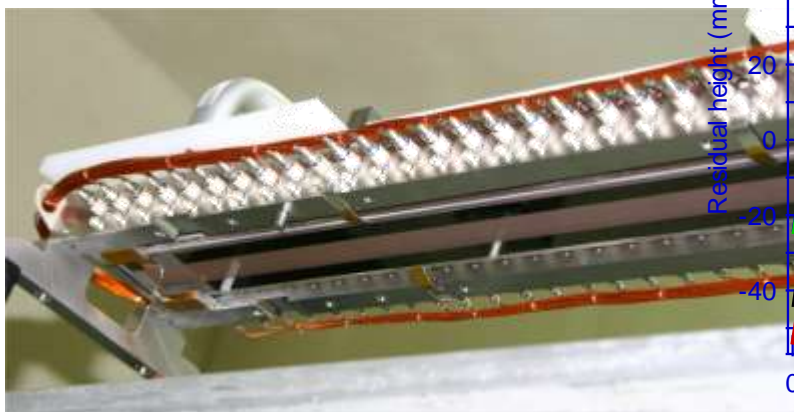
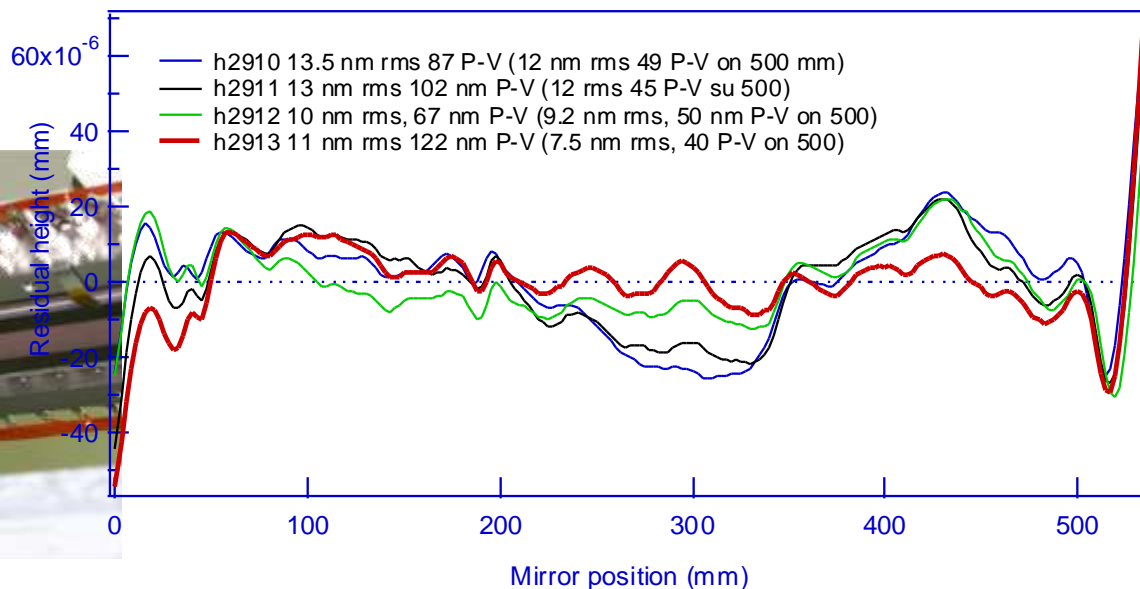




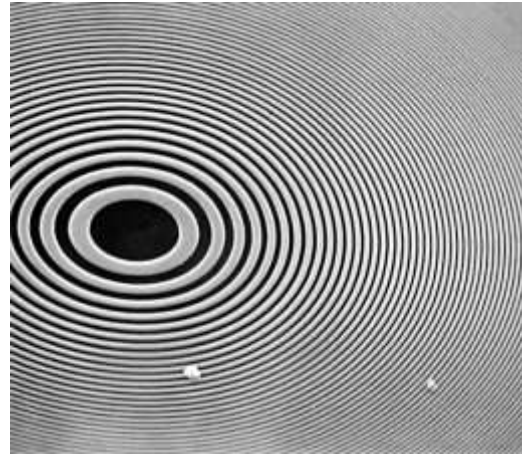
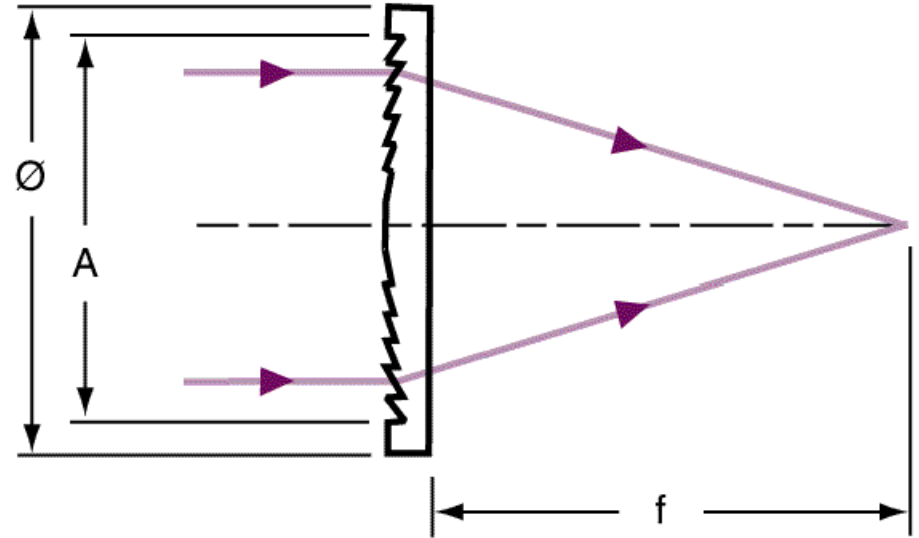
R=2 Km



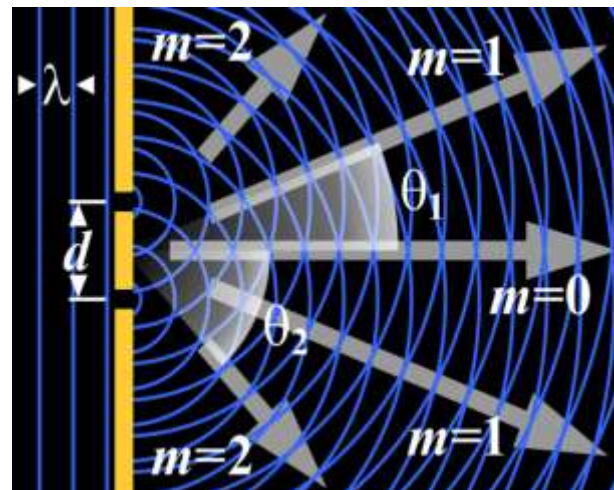
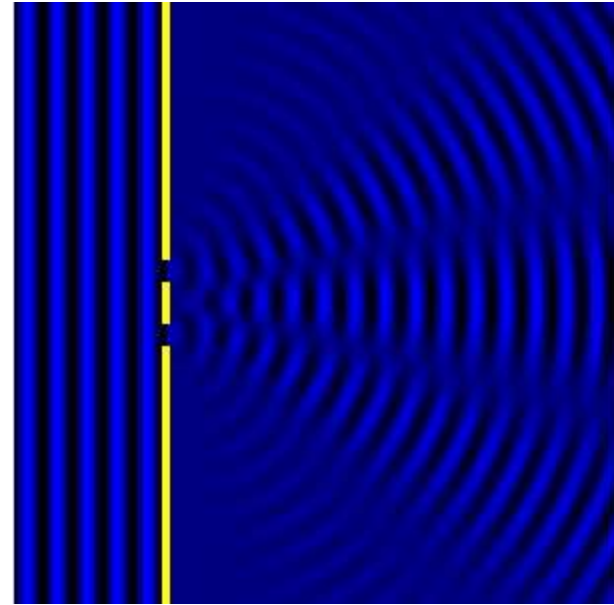
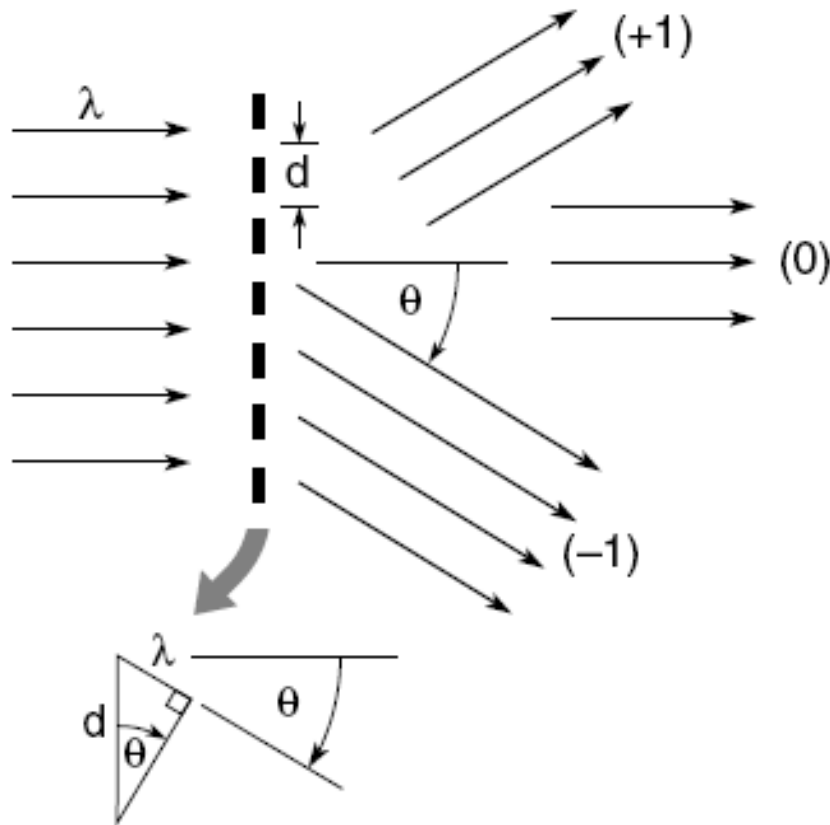
R=4.5 Km



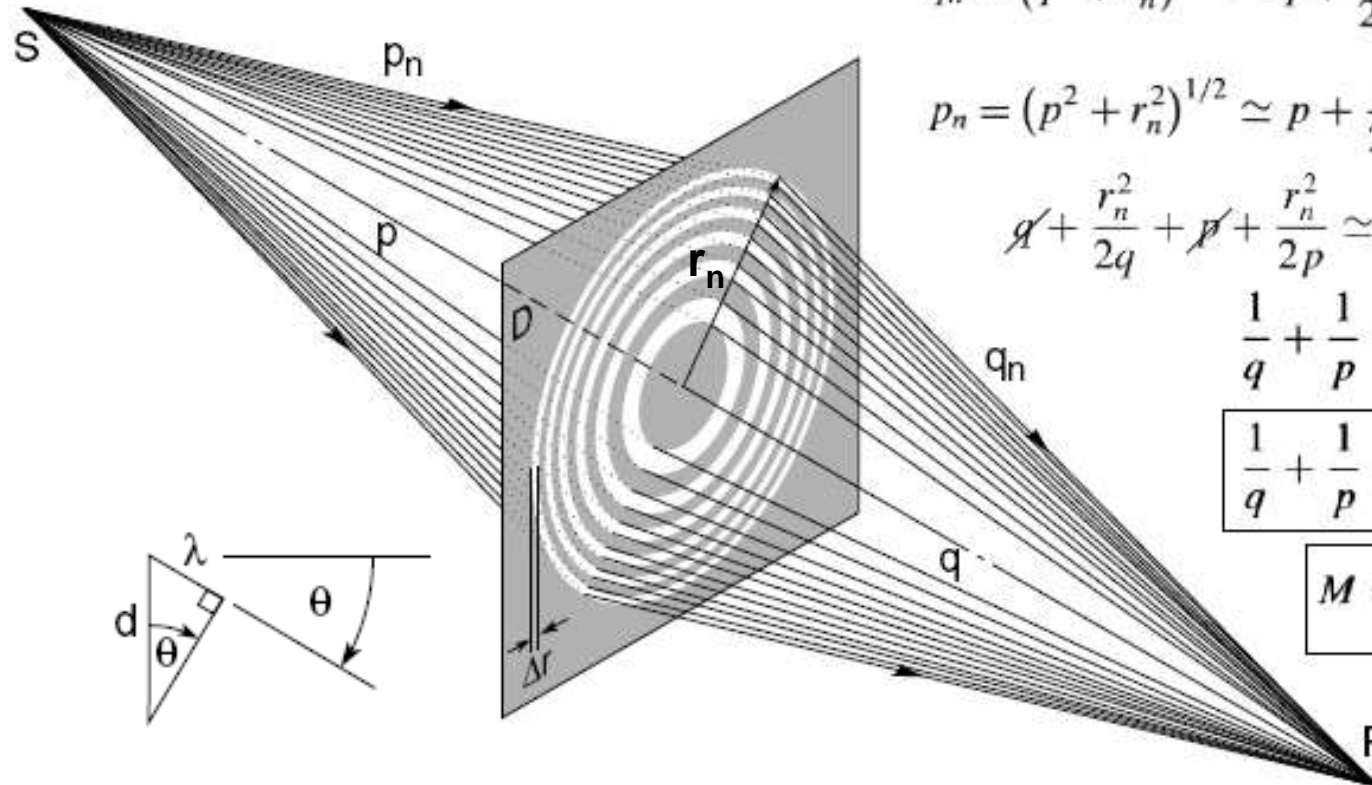
Fresnel lens



$$\sin \theta_m = \frac{m\lambda}{d}; \quad m = 0, \pm 1, \pm 2, \pm 3,$$



$$r_n^2 = fn\lambda$$



$$q_n + p_n = q + p + \frac{n\lambda}{2}$$

$$q_n = (q^2 + r_n^2)^{1/2} \simeq q + \frac{r_n^2}{2q}$$

$$p_n = (p^2 + r_n^2)^{1/2} \simeq p + \frac{r_n^2}{2p}$$

$$q + \frac{r_n^2}{2q} + p + \frac{r_n^2}{2p} \simeq q + p + \frac{n\lambda}{2}$$

$$\frac{1}{q} + \frac{1}{p} \simeq \frac{n\lambda}{r_n^2}$$

$$\frac{1}{q} + \frac{1}{p} \simeq \frac{1}{f}$$

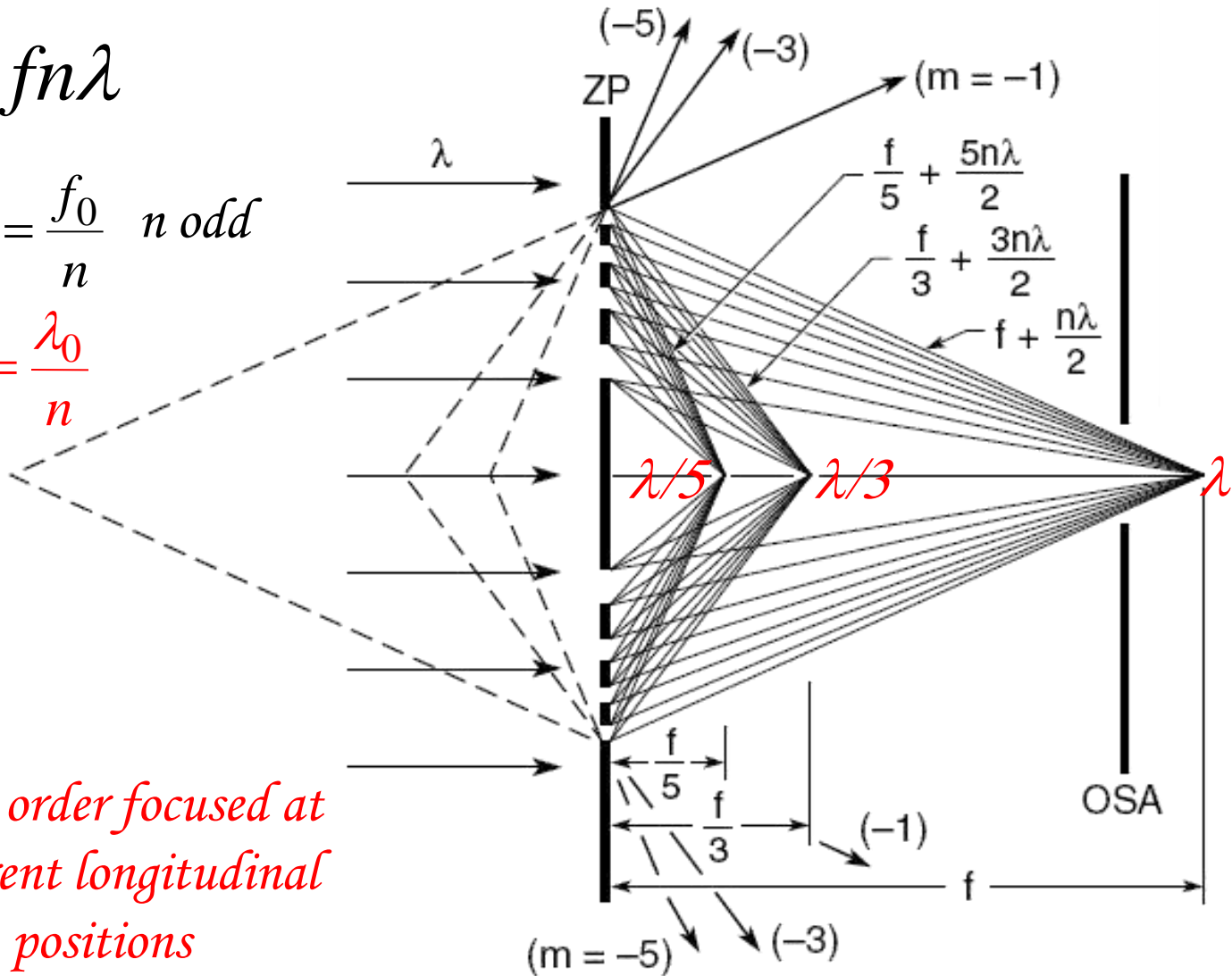
$$M = \frac{p}{q}$$

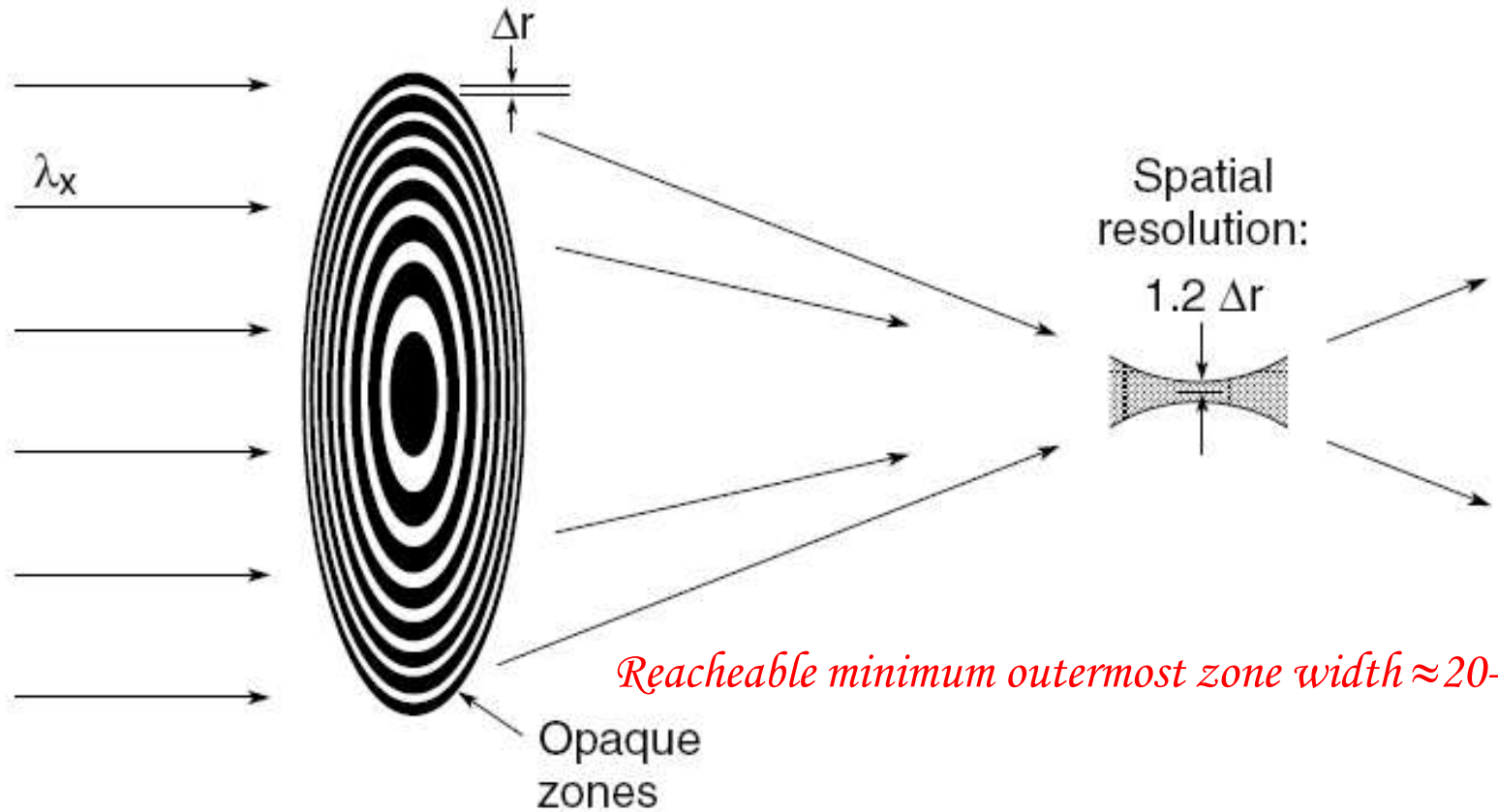
$$r_n^2 = fn\lambda$$

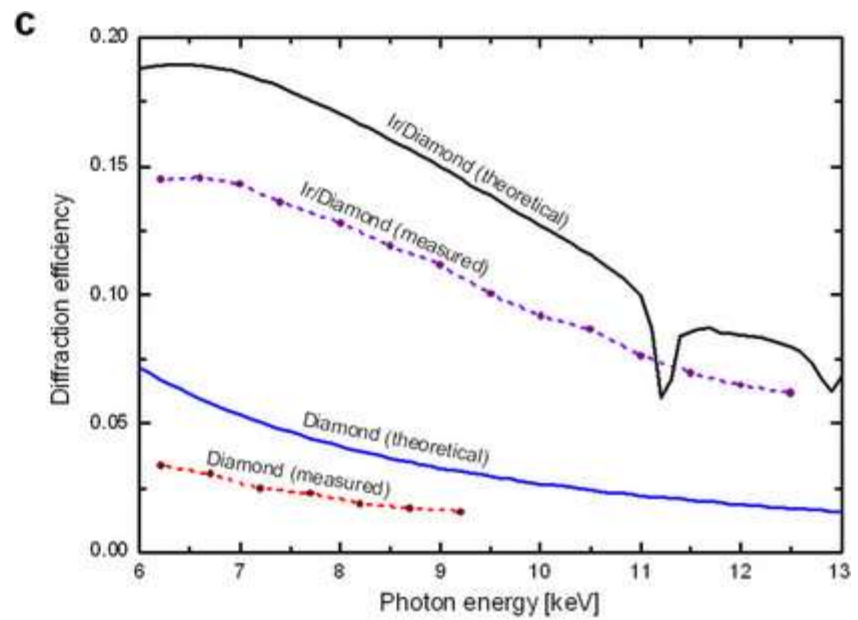
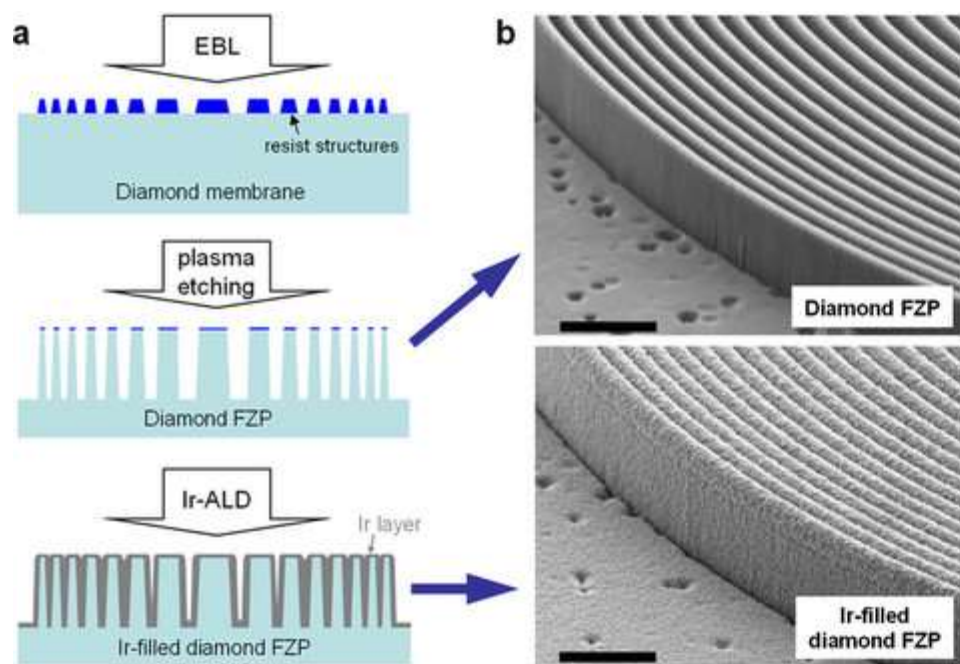
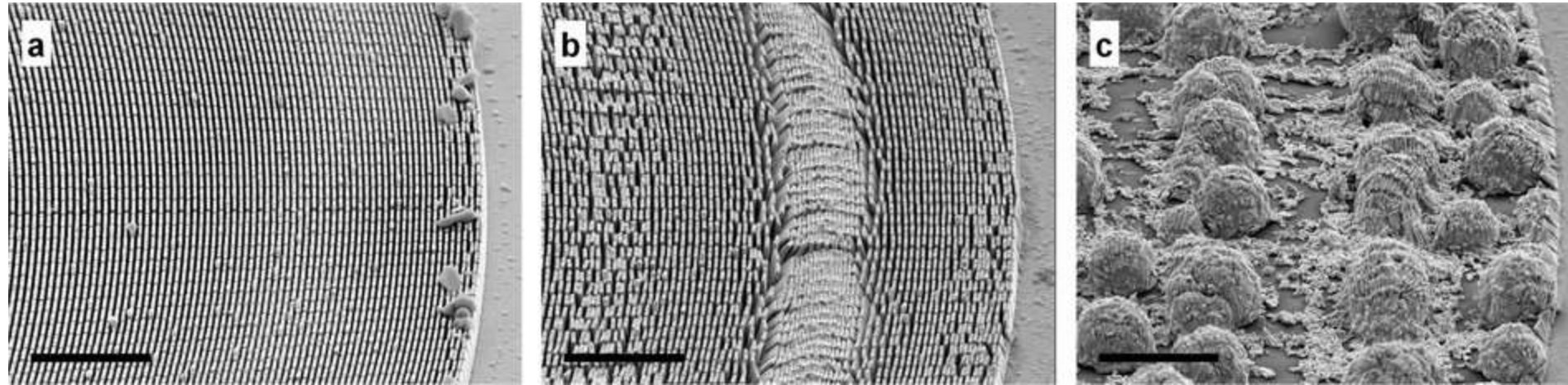
$$f = \frac{r_n^2}{n\lambda} = \frac{f_0}{n} \quad n \text{ odd}$$

$$\lambda = \frac{r_n^2}{nf} = \frac{\lambda_0}{n}$$

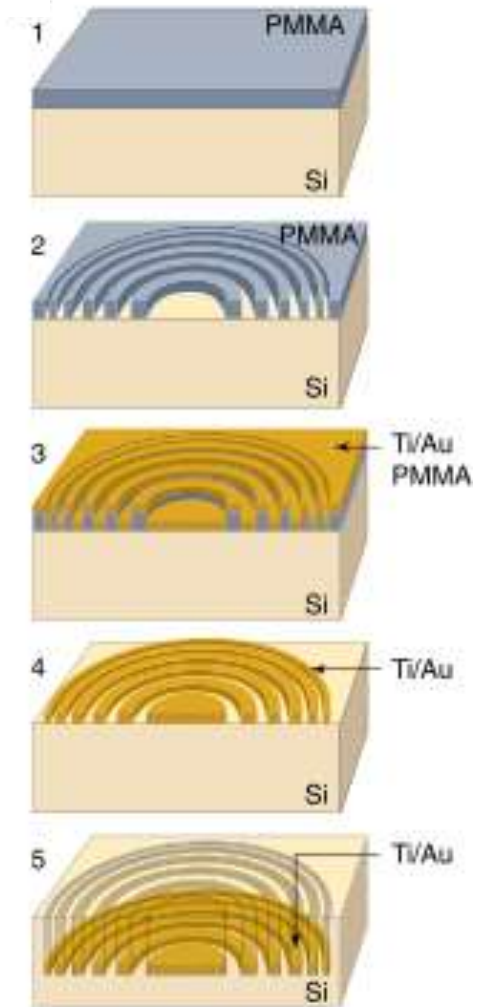
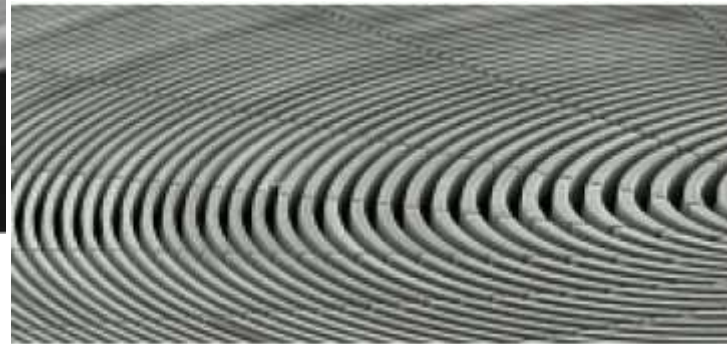
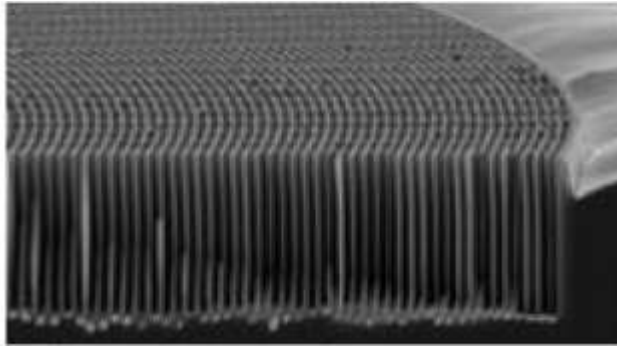
Higher order focused at different longitudinal positions







High Aspect Ratio Zone Plate



Scanning electron microscope (SEM) images of **zone plates** pattern produced with the V-MACE technique.
(Ref. Chieh Chang, Anne Sakdinawat)

→ ←
1 μm

Very good efficiency on the HXR but... does it survive the FEL radiation?

Books/tutorials

- W. B. Peatman: *Gratings Mirrors and Slit* Gordon Sci. Publ. Amsterdam (1997)
- D. Attwood, *Soft X-Rays and Extreme Ultraviolet Radiation*, Cambridge University Press
- A.A. *Modern Developments in X-ray and Neutron Optics* Springer Series in Optical Science 137
- CXRO X-ray data booklet Lawrence Berkeley Nat. lab.
- EuroFEL compendium on Photon Transport and diagnostics (http on request)
- Synchrotron Radiation Sources and Optical devices, Chapter 4 of "Magnetism and Synchrotron Radiation: New Trends" Springer Proc. in Physic 133
- Special issues of photonics on EUV Lasers:
http://www.mqpi.com/journal/photonics/special_issues/EUVL

